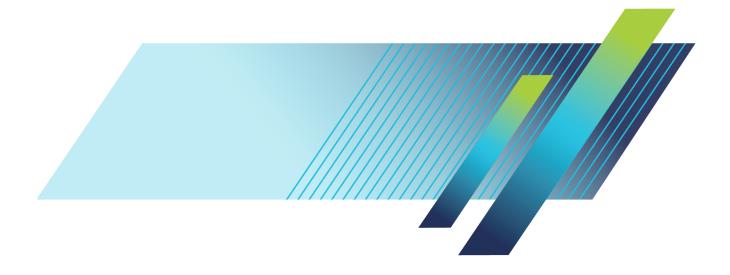
Tektronix[®]

MDO3000 Series Mixed Domain Oscilloscopes Specifications and Performance Verification

Technical Reference



Tektronix[®]

MDO3000 Series Mixed Domain Oscilloscopes Specifications and Performance Verification

Technical Reference

Revision H June 2020 www.tek.com 077-0979-00 Copyright © Tektronix. All rights reserved. Licensed software products are owned by Tektronix or its subsidiaries or suppliers, and are protected by national copyright laws and international treaty provisions.

Tektronix products are covered by U.S. and foreign patents, issued and pending. Information in this publication supersedes that in all previously published material. Specifications and price change privileges reserved.

TEKTRONIX and TEK are registered trademarks of Tektronix, Inc.

Contacting Tektronix

Tektronix, Inc. 14150 SW Karl Braun Drive P.O. Box 500 Beaverton, OR 97077 USA

For product information, sales, service, and technical support:

- In North America, call 1-800-833-9200.
- Worldwide, visit www.tek.com to find contacts in your area.

Table of Contents

Specifications 1 Analog Channel Input And Vertical Specifications 10 Digital Channel Acquisition System Specifications 10 Horizontal And Acquisition System Specifications 11 Sample Rate Range 13 Trigger Specifications 11 Display Specifications 17 Display Specifications 24 Power Source Specifications 25 Data Storage Specifications 25 Data Storage Specifications 25 Mechanical Specifications 25 Mechanical Specifications 26 P6316 Digital Probe Input Characteristics 26 P6316 Digital Probe Input Characteristics 26 P6316 Digital Probe Input Characteristics 26 Proformance Verifications 27 Arbitrary Function Generator Characteristics 30 Digital Voltmeter/Counter 33 Uggrade the Firmware 34 Test Record 35 Input Termination Tests. 36 DC Gain Accuracy Tests 45 DC Offset Accuracy Tests (MDO303X and MDO302X models) 56 Detta Time Measurement	General safety summary	iii
Digital Channel Acquisition System Specifications 10 Horizontal And Acquisition System Specifications 11 Sample Rate Range 13 Trigger Specifications 17 Display Specifications 24 Input/Output Port Specifications 24 Power Source Specifications 25 Data Storage Specifications 25 Environmental Specifications 25 Mechanical Specifications 25 RF Input Specifications 26 P6316 Digital Probe Input Characteristics 26 P6316 Digital Probe Input Characteristics 26 Pritrary Function Generator Features 30 Arbitrary Function Generator Characteristics 31 Digital Voltmeter/Counter 32 Performance Verification 33 Upgrade the Firmware 34 Test Record 35 Input Termination Tests. 36 DC Gian Accuracy Tests 47 Data Storary Tests 45 DC Offset Accuracy Tests (MDO301X and MD0302X models) 56 Delta Time Measurement Accuracy Tests (MDO303X and MD0302X models) 56 <	Specifications	1
Horizontal And Acquisition System Specifications 11 Sample Rate Range 13 Trigger Specifications 17 Display Specifications 24 Input/Output Port Specifications 24 Power Source Specifications 25 Data Storage Specifications 25 Data Storage Specifications 25 Environmental Specifications 26 P6316 Digital Probe Input Characteristics 26 P6316 Digital Probe Input Characteristics 26 RF Input Specifications 27 Arbitrary Function Generator Features 30 Arbitrary Function Generator Characteristics 31 Digital Voltmeter/Counter 32 Performance Verification 33 Upgrade the Firmware 34 Test Record 35 Input Termination Tests 36 DC Glai Accuracy Tests 45 DC Offset Accuracy Tests 45 DC Offset Accuracy Tests 45 DC Offset Accuracy Tests (MDO301X and MD0302X models) 52 Delta Time Measurement Accuracy Tests (MDO301X and MD0302X models) 52 Delta Time Mea	Analog Channel Input And Vertical Specifications	1
Horizontal And Acquisition System Specifications 11 Sample Rate Range 13 Trigger Specifications 17 Display Specifications 24 Input/Output Port Specifications 24 Power Source Specifications 25 Data Storage Specifications 25 Data Storage Specifications 25 Environmental Specifications 26 P6316 Digital Probe Input Characteristics 26 RF Input Specifications 27 Arbitrary Function Generator Features 30 Arbitrary Function Generator Characteristics 31 Digital Voltmeter/Counter 32 Performance Verification 33 Upgrade the Firmware 34 Test Record 33 Input Termination Tests 36 DC Glan Accuracy Tests 45 DC Offset Accuracy Tests 45 DC Offset Accuracy Tests (MDO301X and MD0302X models) 52 Delta Time Measurement Accuracy Tests (MDO301X and MD0302X models) 52 Delta Time Measurement Accuracy Tests (MDO301X and MD0302X models) 52 Delta Time Measurement Accuracy Tests (MDO301X and MD0302X models)	Digital Channel Acquisition System Specifications	10
Sample Rate Range 13 Trigger Specifications 17 Display Specifications 24 Input/Outpl Port Specifications 24 Power Source Specifications 25 Data Storage Specifications 25 Data Storage Specifications 25 Environmental Specifications 25 Mechanical Specifications 26 P6316 Digital Probe Input Characteristics 26 RF Input Specifications 27 Arbitrary Function Generator Characteristics 31 Digital Voltmeter/Counter 32 Performance Verification 33 Upgrade the Firmware 34 Test Record 35 Input Termination Tests. 36 DC Balance Tests 38 Analog Bandwidth Tests, 50 0. 44 DC Gain Accuracy Tests 45 DC Offset Accuracy Tests 45 DC Offset Accuracy Tests (MDO301X and MDO302X models) 52 Delta Time Measurement Accuracy Tests (MDO301X and MDO302X models) 52 Delta Time Measurement Accuracy Tests (MDO301X and MDO302X models) 52 Delta Time Measurement Accura		11
Trigger Specifications 17 Display Specifications. 24 Input/Output Port Specifications 25 Data Storage Specifications 25 Data Storage Specifications 25 Environmental Specifications 25 Mechanical Specifications 25 P6316 Digital Probe Input Characteristics 26 P6317 Specifications 26 R F Input Specifications 27 Arbitrary Function Generator Features. 30 Arbitrary Function Generator Characteristics 31 Digital Voltmeter/Counter 32 Performance Verification 33 Upgrade the Firmware 34 Test Record 35 Input Termination Tests. 36 DC Balance Tests. 36 DC Gain Accuracy Tests 45 DC Offset Accuracy Tests 45 DC Offset Accuracy Tests 50 Delta Time Measurement Accuracy Tests (MDO301X and MD0302X models) 52 Delta Time Measurement Accuracy Tests (MDO301X and MD0305X models) 56 Delta Time Measurement Accuracy Tests (MDO301X and MD0305X models) 56 De	Sample Rate Range	13
Display Specifications 24 Input/Output Port Specifications 24 Power Source Specifications 25 Data Storage Specifications 25 Data Storage Specifications 25 Mechanical Specifications 26 P0316 Digital Probe Input Characteristics 26 RF Input Specifications 27 Arbitrary Function Generator Features 30 Arbitrary Function Generator Characteristics 31 Digital Voltmeter/Counter 32 Performance Verification 33 Upgrade the Firmware 34 Test Record 35 Input Termination Tests 36 DC Balance Tests 36 DC Gain Accuracy Tests 45 DC Offset Accuracy Tests 45 DC Offset Accuracy Tests 50 Delta Time Measurement Accuracy Tests (MDO301X and MDO302X models) 52 Delta Time Measurement Accuracy Tests (MDO301X and MDO305X models) 52 Delta Time Measurement Accuracy Tests (MDO301X and MDO305X models) 52 Delta Time Measurement Accuracy Tests (MDO301X and MDO305X models) 52 Delta Time Measurement Accuracy Tests		17
Input/Output Port Specifications 24 Power Source Specifications 25 Data Storage Specifications 25 Environmental Specifications 26 P6316 Digital Probe Input Characteristics 26 P6316 Digital Probe Input Characteristics 26 RF Input Specifications 26 Arbitrary Function Generator Features 30 Arbitrary Function Generator Characteristics 31 Digital Votmeter/Counter 32 Performance Verification 33 Upgrade the Firmware 34 Test Record 35 Input Termination Tests 36 DC Balance Tests 38 Analog Bandwidth Tests, 50 Ω 44 DC Gain Accuracy Tests 45 DC Offset Accuracy Tests 45 DC Offset Accuracy Tests 47 Sample Rate and Delay Time Accuracy Tests (MDO301X and MDO302X models) 52 Delta Time Measurement Accuracy Tests (MDO31X and MDO305X models) 56 Delta Time Measurement Accuracy Tests (MDO30X and MDO305X models) 56 Delta Time Measurement Accuracy Tests (MDO31X and MDO305X models) 56 Delta Time Mea		24
Data Storage Specifications 25 Environmental Specifications 26 Mechanical Specifications 26 P6316 Digital Probe Input Characteristics 26 RF Input Specifications 27 Arbitrary Function Generator Features. 30 Arbitrary Function Generator Characteristics 31 Digital Voltmeter/Counter 32 Performance Verification 33 Upgrade the Firmware 34 Test Record 35 Input Termination Tests. 36 DC Balance Tests. 38 Analog Bandwidth Tests, 50 Ω 44 DC Gifset Accuracy Tests 45 DC Offset Accuracy Tests 47 Sample Rate and Delay Time Accuracy. 49 Random Noise, Sample Acquisition Mode Tests. 50 Delta Time Measurement Accuracy Tests (MDO301X and MDO302X models) 52 Delta Time Measurement Accuracy Tests (MDO310X models) 60 Displayed Average Noise Level Tests (DANL) 67 Residual Spurious Response Tests. 67 Level Measurement Uncertainty Tests. 68 Functional check with a TPA-N-PRE Preamp Attached		24
Data Storage Specifications 25 Environmental Specifications 25 Mechanical Specifications 26 P6316 Digital Probe Input Characteristics 26 R F Input Specifications 27 Arbitrary Function Generator Features 30 Arbitrary Function Generator Characteristics 31 Digital Voltmeter/Counter 32 Performance Verification 33 Upgrade the Firmware 34 Test Record 35 Input Termination Tests 36 DC Balance Tests 38 Analog Bandwidth Tests, 50 Ω 44 DC Offset Accuracy Tests 45 DC Offset Accuracy Tests 47 Sample Rate and Delay Time Accuracy 49 Random Noise, Sample Acquisition Mode Tests 50 Delta Time Measurement Accuracy Tests (MDO301X and MDO302X models) 52 Delta Time Measurement Accuracy Tests (MDO310X models) 60 Digital Threshold Accuracy Tests (MDO310X models) 60 Digital Threshold Accuracy Tests (MDO310X models) 60 Digital Threshold Accuracy Tests (MDNL) 67 Residual Spurious Response Tests.	Power Source Specifications	25
Environmental Specifications 25 Mechanical Specifications 26 P6316 Digital Probe Input Characteristics 26 RF Input Specifications 27 Arbitrary Function Generator Features 30 Arbitrary Function Generator Characteristics 31 Digital Voltmeter/Counter 32 Performance Verification 33 Upgrade the Firmware 34 Test Record 35 Input Termination Tests 36 DC Balance Tests 38 Analog Bandwidth Tests, 50 Ω 44 DC Gain Accuracy Tests 45 DC Offset Accuracy Tests 47 Sample Rate and Delay Time Accuracy. 49 Random Noise, Sample Acquisition Mode Tests 50 Delta Time Measurement Accuracy Tests (MDO301X and MDO302X models) 52 Delta Time Measurement Accuracy Tests (MDO301X models) 60 Digital Threshold Accuracy Tests (MDO310X models) 60 Digital Threshold Accuracy Tests (MDO310X models) 61 Displayed Average Noise Level Tests (DANL) 67 Residual Spurious Response Tests. 67 Level Measurement Uncertainty Te		25
P6316 Digital Probe Input Characteristics 26 RF Input Specifications 27 Arbitrary Function Generator Features 30 Arbitrary Function Generator Characteristics 31 Digital Voltmeter/Counter 32 Performance Verification 33 Upgrade the Firmware 34 Test Record 35 Input Termination Tests 36 DC Balance Tests 38 Analog Bandwidth Tests, 50 Ω 44 DC Gain Accuracy Tests 45 DC Offset Accuracy Tests 47 Sample Rate and Delay Time Accuracy 49 Random Noise, Sample Acquisition Mode Tests. 50 Delta Time Measurement Accuracy Tests (MDO301X and MDO302X models) 52 Delta Time Measurement Accuracy Tests (MDO310X models) 60 Digital Threshold Accuracy Tests (MDO310X models) 60 Digital Threshold Accuracy Tests (With MDO3MSO option) 66 Delta Time Measurement Uncertainty Tests. 67 Level Measurement Uncertainty Tests. 68 Functional check with a TPA-N-PRE Preamp Attached 68 Displayed Average Noise Level (DANL) with a TPA-N-PRE Preamp Attached.		25
RF Input Specifications 27 Arbitrary Function Generator Features 30 Arbitrary Function Generator Characteristics 31 Digital Voltmeter/Counter 32 Performance Verification 33 Upgrade the Firmware 34 Test Record 35 Input Termination Tests 36 DC Balance Tests 36 Analog Bandwidth Tests, 50 Ω 44 DC Gain Accuracy Tests 45 DC Offset Accuracy Tests 47 Sample Rate and Delay Time Accuracy 49 Random Noise, Sample Acquisition Mode Tests 50 Delta Time Measurement Accuracy Tests (MDO301X and MDO302X models) 52 Delta Time Measurement Accuracy Tests (MDO310X models) 56 Delta Time Measurement Accuracy Tests (MDO310X models) 60 Digital Threshold Accuracy Tests (MDO310X models) 66 Displayed Average Noise Level Tests (DANL) 67 Residual Spurious Response Tests 67 Level Measurement Uncertainty Tests 68 Functional check with a TPA-N-PRE Preamp Attached 68 Displayed Average Noise Level (DANL) with a TPA-N-PRE Preamp Attached 69	Mechanical Specifications	26
RF Input Specifications 27 Arbitrary Function Generator Features 30 Arbitrary Function Generator Characteristics 31 Digital Voltmeter/Counter 32 Performance Verification 33 Upgrade the Firmware 34 Test Record 35 Input Termination Tests 36 DC Balance Tests 38 Analog Bandwidth Tests, 50 Ω 44 DC Gain Accuracy Tests 45 DC Offset Accuracy Tests 47 Sample Rate and Delay Time Accuracy 49 Random Noise, Sample Acquisition Mode Tests 50 Delta Time Measurement Accuracy Tests (MDO301X and MDO302X models) 52 Delta Time Measurement Accuracy Tests (MDO303X and MDO305X models) 56 Delta Time Measurement Accuracy Tests (MDO301X models) 60 Digital Threshold Accuracy Tests (MDO30XS option) 66 Displayed Average Noise Level Tests (DANL) 67 Residual Spurious Response Tests 68 Functional check with a TPA-N-PRE Preamp Attached 68 Displayed Average Noise Level (DANL) with a TPA-N-PRE Preamp Attached 69 Auxiliary (Trigger) Output Tests <t< td=""><td>P6316 Digital Probe Input Characteristics</td><td>26</td></t<>	P6316 Digital Probe Input Characteristics	26
Arbitrary Function Generator Features 30 Arbitrary Function Generator Characteristics 31 Digital Voltmeter/Counter 32 Performance Verification 33 Upgrade the Firmware 34 Test Record 35 Input Termination Tests 36 DC Balance Tests 38 Analog Bandwidth Tests, 50 Ω 44 DC Gain Accuracy Tests 45 DC Offset Accuracy Tests 47 Sample Rate and Delay Time Accuracy 49 Random Noise, Sample Acquisition Mode Tests 50 Delta Time Measurement Accuracy Tests (MDO301X and MDO302X models) 52 Delta Time Measurement Accuracy Tests (MDO303X and MDO305X models) 56 Delta Time Measurement Accuracy Tests (MDO301X models) 60 Digital Threshold Accuracy Tests (MDO300X coption) 66 Displayed Average Noise Level Tests (DANL) 67 Residual Spurious Response Tests 68 Functional check with a TPA-N-PRE Preamp Attached 68 Displayed Average Noise Level (DANL) with a TPA-N-PRE Preamp Attached 69 Auxiliary (Trigger) Output Tests 69 AFG Sine and Ramp Frequency Accuracy		27
Arbitrary Function Generator Characteristics 31 Digital Voltmeter/Counter 32 Performance Verification 33 Upgrade the Firmware 34 Test Record 35 Input Termination Tests 36 DC Balance Tests 38 Analog Bandwidth Tests, 50 Ω 44 DC Gain Accuracy Tests 45 DC Offset Accuracy Tests 45 DC Offset Accuracy Tests 47 Sample Rate and Delay Time Accuracy 49 Random Noise, Sample Acquisition Mode Tests 50 Delta Time Measurement Accuracy Tests (MDO301X and MDO302X models) 52 Delta Time Measurement Accuracy Tests (MDO310X models) 60 Digital Threshold Accuracy Tests (MDO310X models) 60 Displayed Average Noise Level Tests (DANL) 67 Residual Spurious Response Tests. 68 Functional check with a TPA-N-PRE Preamp Attached 68 Displayed Average Noise Level (DANL) with a TPA-N-PRE Preamp Attached 69 Auxiliary (Trigger) Output Tests 69 Auxiliary (Trigger) Output Tests 69		30
Digital Voltmeter/Counter 32 Performance Verification 33 Upgrade the Firmware 34 Test Record 35 Input Termination Tests 36 DC Balance Tests 38 Analog Bandwidth Tests, 50 Ω 44 DC Gain Accuracy Tests 45 DC Offset Accuracy Tests 47 Sample Rate and Delay Time Accuracy 49 Random Noise, Sample Acquisition Mode Tests 50 Delta Time Measurement Accuracy Tests (MDO301X and MDO302X models) 52 Delta Time Measurement Accuracy Tests (MDO310X models) 60 Digital Threshold Accuracy Tests (With MDO305X models) 60 Digital Spurious Response Tests 67 Level Measurement Uncertainty Tests. 68 Functional check with a TPA-N-PRE Preamp Attached 68 Displayed Average Noise Level (DANL) with a TPA-N-PRE Preamp Attached. 69 Auxiliary (Trigger) Output Tests 69 AFG Sine and Ramp Frequency Accuracy Tests 69		31
Performance Verification 33 Upgrade the Firmware 34 Test Record 35 Input Termination Tests 36 DC Balance Tests 38 Analog Bandwidth Tests, 50 Ω 44 DC Gain Accuracy Tests 45 DC Offset Accuracy Tests 47 Sample Rate and Delay Time Accuracy 49 Random Noise, Sample Acquisition Mode Tests 50 Delta Time Measurement Accuracy Tests (MDO301X and MDO302X models) 52 Delta Time Measurement Accuracy Tests (MDO310X models) 56 Delta Time Measurement Accuracy Tests (MDO310X models) 60 Digital Threshold Accuracy Tests (DANL) 67 Residual Spurious Response Tests 67 Level Measurement Uncertainty Tests 68 Functional check with a TPA-N-PRE Preamp Attached 68 Displayed Average Noise Level (DANL) with a TPA-N-PRE Preamp Attached 69 Auxiliary (Trigger) Output Tests 69 AFG Sine and Ramp Frequency Accuracy Tests 69		32
Upgrade the Firmware 34 Test Record 35 Input Termination Tests 36 DC Balance Tests 38 Analog Bandwidth Tests, 50 Ω 44 DC Gain Accuracy Tests 45 DC Offset Accuracy Tests 47 Sample Rate and Delay Time Accuracy 49 Random Noise, Sample Acquisition Mode Tests 50 Delta Time Measurement Accuracy Tests (MDO301X and MDO302X models) 52 Delta Time Measurement Accuracy Tests (MDO310X models) 56 Delta Time Measurement Accuracy Tests (MDO310X models) 60 Digital Threshold Accuracy Tests (DANL) 67 Residual Spurious Response Tests 67 Level Measurement Uncertainty Tests 68 Functional check with a TPA-N-PRE Preamp Attached 68 Displayed Average Noise Level (DANL) with a TPA-N-PRE Preamp Attached 69 Auxiliary (Trigger) Output Tests 69 Auxiliary (Trigger) Output Tests 69 AFG Sine and Ramp Frequency Accuracy Tests 69		
Test Record 35 Input Termination Tests. 36 DC Balance Tests. 38 Analog Bandwidth Tests, 50 Ω 44 DC Gain Accuracy Tests 45 DC Offset Accuracy Tests 47 Sample Rate and Delay Time Accuracy. 49 Random Noise, Sample Acquisition Mode Tests 50 Delta Time Measurement Accuracy Tests (MDO301X and MDO302X models) 52 Delta Time Measurement Accuracy Tests (MDO310X models) 56 Delta Time Measurement Accuracy Tests (MDO310X models) 60 Digital Threshold Accuracy Tests (DANL) 67 Residual Spurious Response Tests. 68 Functional check with a TPA-N-PRE Preamp Attached 68 Displayed Average Noise Level (DANL) with a TPA-N-PRE Preamp Attached 69 Auxiliary (Trigger) Output Tests 69 AFG Sine and Ramp Frequency Accuracy Tests 69		
Input Termination Tests 36 DC Balance Tests 38 Analog Bandwidth Tests, 50 Ω 44 DC Gain Accuracy Tests 45 DC Offset Accuracy Tests 47 Sample Rate and Delay Time Accuracy. 49 Random Noise, Sample Acquisition Mode Tests 50 Delta Time Measurement Accuracy Tests (MDO301X and MDO302X models) 52 Delta Time Measurement Accuracy Tests (MDO310X models) 56 Delta Time Measurement Accuracy Tests (MDO310X models) 60 Digital Threshold Accuracy Tests (With MDO3MSO option) 66 Displayed Average Noise Level Tests (DANL) 67 Residual Spurious Response Tests. 68 Functional check with a TPA-N-PRE Preamp Attached 68 Displayed Average Noise Level (DANL) with a TPA-N-PRE Preamp Attached. 69 Auxiliary (Trigger) Output Tests 69 AFG Sine and Ramp Frequency Accuracy Tests 69		
DC Balance Tests. 38 Analog Bandwidth Tests, 50 Ω 44 DC Gain Accuracy Tests 45 DC Offset Accuracy Tests 47 Sample Rate and Delay Time Accuracy 49 Random Noise, Sample Acquisition Mode Tests 50 Delta Time Measurement Accuracy Tests (MDO301X and MDO302X models) 52 Delta Time Measurement Accuracy Tests (MDO303X and MDO305X models) 56 Delta Time Measurement Accuracy Tests (MDO310X models) 60 Digital Threshold Accuracy Tests (MDO310X models) 60 Displayed Average Noise Level Tests (DANL) 67 Residual Spurious Response Tests 68 Functional check with a TPA-N-PRE Preamp Attached 68 Displayed Average Noise Level (DANL) with a TPA-N-PRE Preamp Attached 69 Auxiliary (Trigger) Output Tests 69 AFG Sine and Ramp Frequency Accuracy Tests 69		
Analog Bandwidth Tests, 50 Ω 44 DC Gain Accuracy Tests 45 DC Offset Accuracy Tests 47 Sample Rate and Delay Time Accuracy 49 Random Noise, Sample Acquisition Mode Tests 50 Delta Time Measurement Accuracy Tests (MDO301X and MDO302X models) 52 Delta Time Measurement Accuracy Tests (MDO301X and MDO305X models) 56 Delta Time Measurement Accuracy Tests (MDO310X models) 60 Digital Threshold Accuracy Tests (With MDO3MSO option) 66 Displayed Average Noise Level Tests (DANL) 67 Residual Spurious Response Tests. 68 Functional check with a TPA-N-PRE Preamp Attached 68 Displayed Average Noise Level (DANL) with a TPA-N-PRE Preamp Attached 69 Auxiliary (Trigger) Output Tests 69 AFG Sine and Ramp Frequency Accuracy Tests 69		
DC Gain Accuracy Tests45DC Offset Accuracy Tests47Sample Rate and Delay Time Accuracy49Random Noise, Sample Acquisition Mode Tests50Delta Time Measurement Accuracy Tests (MDO301X and MDO302X models)52Delta Time Measurement Accuracy Tests (MDO303X and MDO305X models)56Delta Time Measurement Accuracy Tests (MDO310X models)60Digital Threshold Accuracy Tests (MDO310X models)60Displayed Average Noise Level Tests (DANL)67Residual Spurious Response Tests68Functional check with a TPA-N-PRE Preamp Attached68Displayed Average Noise Level (DANL) with a TPA-N-PRE Preamp Attached69Auxiliary (Trigger) Output Tests69AFG Sine and Ramp Frequency Accuracy Tests69		
DC Offset Accuracy Tests 47 Sample Rate and Delay Time Accuracy 49 Random Noise, Sample Acquisition Mode Tests 50 Delta Time Measurement Accuracy Tests (MDO301X and MDO302X models) 52 Delta Time Measurement Accuracy Tests (MDO303X and MDO305X models) 56 Delta Time Measurement Accuracy Tests (MDO310X models) 60 Digital Threshold Accuracy Tests (MDO310X models) 60 Displayed Average Noise Level Tests (DANL) 67 Residual Spurious Response Tests 67 Level Measurement Uncertainty Tests 68 Functional check with a TPA-N-PRE Preamp Attached 68 Displayed Average Noise Level (DANL) with a TPA-N-PRE Preamp Attached 69 Auxiliary (Trigger) Output Tests 69 AFG Sine and Ramp Frequency Accuracy Tests 69	-	
Sample Rate and Delay Time Accuracy49Random Noise, Sample Acquisition Mode Tests50Delta Time Measurement Accuracy Tests (MDO301X and MDO302X models)52Delta Time Measurement Accuracy Tests (MDO303X and MDO305X models)56Delta Time Measurement Accuracy Tests (MDO310X models)60Digital Threshold Accuracy Tests (with MDO3MSO option)66Displayed Average Noise Level Tests (DANL)67Residual Spurious Response Tests68Functional check with a TPA-N-PRE Preamp Attached68Displayed Average Noise Level (DANL) with a TPA-N-PRE Preamp Attached69Auxiliary (Trigger) Output Tests69AFG Sine and Ramp Frequency Accuracy Tests69		
Random Noise, Sample Acquisition Mode Tests50Delta Time Measurement Accuracy Tests (MDO301X and MDO302X models)52Delta Time Measurement Accuracy Tests (MDO303X and MDO305X models)56Delta Time Measurement Accuracy Tests (MDO310X models)60Digital Threshold Accuracy Tests (with MDO3MSO option)66Displayed Average Noise Level Tests (DANL)67Residual Spurious Response Tests67Level Measurement Uncertainty Tests68Functional check with a TPA-N-PRE Preamp Attached68Displayed Average Noise Level (DANL) with a TPA-N-PRE Preamp Attached69Auxiliary (Trigger) Output Tests69AFG Sine and Ramp Frequency Accuracy Tests69		
Delta Time Measurement Accuracy Tests (MDO301X and MDO302X models)52Delta Time Measurement Accuracy Tests (MDO303X and MDO305X models)56Delta Time Measurement Accuracy Tests (MDO310X models)60Digital Threshold Accuracy Tests (with MDO3MSO option)66Displayed Average Noise Level Tests (DANL)67Residual Spurious Response Tests67Level Measurement Uncertainty Tests68Functional check with a TPA-N-PRE Preamp Attached68Displayed Average Noise Level (DANL) with a TPA-N-PRE Preamp Attached69Auxiliary (Trigger) Output Tests69AFG Sine and Ramp Frequency Accuracy Tests69		
Delta Time Measurement Accuracy Tests (MDO303X and MDO305X models) 56 Delta Time Measurement Accuracy Tests (MDO310X models) 60 Digital Threshold Accuracy Tests (with MDO3MSO option) 66 Displayed Average Noise Level Tests (DANL) 67 Residual Spurious Response Tests. 67 Level Measurement Uncertainty Tests. 68 Functional check with a TPA-N-PRE Preamp Attached 68 Displayed Average Noise Level (DANL) with a TPA-N-PRE Preamp Attached. 69 Auxiliary (Trigger) Output Tests 69 AFG Sine and Ramp Frequency Accuracy Tests 69		
Delta Time Measurement Accuracy Tests (MDO310X models)60Digital Threshold Accuracy Tests (with MDO3MSO option)66Displayed Average Noise Level Tests (DANL)67Residual Spurious Response Tests.67Level Measurement Uncertainty Tests.68Functional check with a TPA-N-PRE Preamp Attached68Displayed Average Noise Level (DANL) with a TPA-N-PRE Preamp Attached.69Auxiliary (Trigger) Output Tests69AFG Sine and Ramp Frequency Accuracy Tests69		
Digital Threshold Accuracy Tests (with MDO3MSO option) 66 Displayed Average Noise Level Tests (DANL) 67 Residual Spurious Response Tests 67 Level Measurement Uncertainty Tests 68 Functional check with a TPA-N-PRE Preamp Attached 68 Displayed Average Noise Level (DANL) with a TPA-N-PRE Preamp Attached 69 Auxiliary (Trigger) Output Tests 69 AFG Sine and Ramp Frequency Accuracy Tests 69		
Displayed Average Noise Level Tests (DANL) 67 Residual Spurious Response Tests 67 Level Measurement Uncertainty Tests 68 Functional check with a TPA-N-PRE Preamp Attached 68 Displayed Average Noise Level (DANL) with a TPA-N-PRE Preamp Attached 69 Auxiliary (Trigger) Output Tests 69 AFG Sine and Ramp Frequency Accuracy Tests 69		
Residual Spurious Response Tests. 67 Level Measurement Uncertainty Tests. 68 Functional check with a TPA-N-PRE Preamp Attached 68 Displayed Average Noise Level (DANL) with a TPA-N-PRE Preamp Attached. 69 Auxiliary (Trigger) Output Tests 69 AFG Sine and Ramp Frequency Accuracy Tests 69		
Level Measurement Uncertainty Tests 68 Functional check with a TPA-N-PRE Preamp Attached 68 Displayed Average Noise Level (DANL) with a TPA-N-PRE Preamp Attached 69 Auxiliary (Trigger) Output Tests 69 AFG Sine and Ramp Frequency Accuracy Tests 69		
Functional check with a TPA-N-PRE Preamp Attached 68 Displayed Average Noise Level (DANL) with a TPA-N-PRE Preamp Attached. 69 Auxiliary (Trigger) Output Tests 69 AFG Sine and Ramp Frequency Accuracy Tests 69		
Displayed Average Noise Level (DANL) with a TPA-N-PRE Preamp Attached		
Auxiliary (Trigger) Output Tests 69 AFG Sine and Ramp Frequency Accuracy Tests 69	·	
AFG Sine and Ramp Frequency Accuracy Tests		
AFG Signal Amplitude Accuracy Tests		
AFG DC Offset Accuracy Tests		

DVM Voltage Accuracy Tests (DC)	71
DVM Voltage Accuracy Tests (AC)	73
DVM Frequency Accuracy Tests and Maximum Input Frequency	74
Performance Verification Procedures	75
Self Tests — System Diagnostics and Signal Path Compensation	75
Check Input Termination, DC Coupled (Resistance)	77
Check DC Balance	78
Check Analog Bandwidth, 50 Ω	80
Check DC Gain Accuracy	83
Check Long-term Sample Rate and Delay Time Accuracy	89
Check Random Noise, Sample Acquisition Mode	90
Check Delta Time Measurement Accuracy	91
Check Digital Threshold Accuracy (with MDO3MSO option)	93
Check Displayed Average Noise Level (DANL)	96
Check Residual Spurious Response	99
Check Level Measurement Uncertainty	101
Functional Check of the MDO3000 with a TPA-N-PRE Attached to its RF Input	105
Check Displayed Average Noise Level (DANL) with a TPA-N-PRE Attached:	108
Check Auxiliary Output	113
Check AFG Sine and Ramp Frequency	114
Check AFG Square and Pulse Frequency Accuracy	115
Check AFG Signal Amplitude Accuracy	116
Check AFG DC Offset Accuracy	117
Check DVM Voltage Accuracy (DC)	118
Check DVM Voltage Accuracy (AC)	120
Check DVM Frequency Accuracy and Maximum Input Frequency	121

General safety summary

Review the following safety precautions to avoid injury and prevent damage to this product or any products connected to it.

To avoid potential hazards, use this product only as specified.

Only qualified personnel should perform service procedures.

While using this product, you may need to access other parts of a larger system. Read the safety sections of the other component manuals for warnings and cautions related to operating the system.

To avoid fire or personal injury

Use proper power cord. Use only the power cord specified for this product and certified for the country of use.

Connect and disconnect properly. Do not connect or disconnect probes or test leads while they are connected to a voltage source.

Connect and disconnect properly. De-energize the circuit under test before connecting or disconnecting the current probe.

Ground the product. This product is grounded through the grounding conductor of the power cord. To avoid electric shock, the grounding conductor must be connected to earth ground. Before making connections to the input or output terminals of the product, ensure that the product is properly grounded.

Observe all terminal ratings. To avoid fire or shock hazard, observe all ratings and markings on the product. Consult the product manual for further ratings information before making connections to the product.

Connect the probe reference lead to earth ground only.

Do not apply a potential to any terminal, including the common terminal, that exceeds the maximum rating of that terminal.

Power disconnect. The power cord disconnects the product from the power source. Do not block the power cord; it must remain accessible to the user at all times.

Do not operate without covers. Do not operate this product with covers or panels removed.

Do not operate with suspected failures. If you suspect that there is damage to this product, have it inspected by qualified service personnel.

Avoid exposed circuitry. Do not touch exposed connections and components when power is present.

Do not operate in wet/damp conditions.

Do not operate in an explosive atmosphere.

Keep product surfaces clean and dry.

Provide proper ventilation. Refer to the manual's installation instructions for details on installing the product so it has proper ventilation.

Terms in this manual

These terms may appear in this manual:



WARNING. Warning statements identify conditions or practices that could result in injury or loss of life.



CAUTION. Caution statements identify conditions or practices that could result in damage to this product or other property.

Symbols and terms on the product

These terms may appear on the product:

- DANGER indicates an injury hazard immediately accessible as you read the marking.
- WARNING indicates an injury hazard not immediately accessible as you read the marking.
- CAUTION indicates a hazard to property including the product.

The following symbol(s) may appear on the product:



Refer to Manual





(Earth) Terminal



Specifications

This chapter contains specifications for the MDO3000 Series oscilloscopes. All specifications are guaranteed unless noted as "typical." Typical specifications are provided for your convenience but are not guaranteed. Specifications that are marked with the \vee symbol have associated procedures listed in the *Performance Verification* section.

All specifications apply to all MDO3000 models unless noted otherwise. To meet specifications, two conditions must first be met:

- The oscilloscope must have been operating continuously for twenty minutes within the operating temperature range specified.
- You must perform the Signal Path Compensation (SPC) operation described in this manual prior to evaluating specifications. (See page 75.) If the operating temperature changes by more than 10 °C (18 °F), you must perform the SPC operation again.

Analog Channel Input And Vertical Specifications

Characteristic	Description	
Number of input channels	MDO3104, MDO3054, MDO3034, MDO3024, MDO3014	4 analog, digitized simultaneously
	MDO3102, MDO3052, MDO3032, MDO3022, MDO3012	2 analog, digitized simultaneously
Input coupling	DC, AC	
Input termination selection	1 MΩ, 50 Ω, or 75 Ω.	
	The 75 Ω setting is not available on MDO310X inst	truments.
 Input termination, 1 MΩ, DC coupled 	1 MΩ, ±1%	

Table 1: Analog channel input and vertical specifications

Characteristic	Description				
Input termination,	50 Ω, ±1%				
50 Ω, DC coupled (See page 77.)	For instruments with 1 GHz bandwidth (includes MDO310X models as well as MDO305X/303X/302X/301X models with 1 GHz upgrade):	VSWR ≤ 1.5:1 from DC to 1 GHz, typical			
	For instruments with 500 MHz bandwidth (includes MDO305X models as well as MDO303X/302X/301X models with 500 MHz upgrade):	VSWR ≤ 1.5:1 from DC to 500 MHz, typical			
	For instruments with 350 MHz bandwidth (includes MDO303X models as well as MDO302X/301X models with 350 MHz upgrade):	VSWR ≤ 1.5:1 from DC to 350 MHz, typical			
	For instruments with 200 MHz bandwidth (includes MDO302X models as well as MDO301X models with 200 MHz upgrade):	VSWR ≤ 1.5:1 from DC to 200 MHz, typical			
	For instruments with 100 MHz bandwidth (MDO301X models):	VSWR \leq 1.5:1 from DC to 100 MHz, typical			
Input termination,	75 Ω, ±1%				
75 Ω, DC coupled (See page 77.)	VSWR ≤ 1.3:1 from DC to 30 MHz, typical				
	VSWR ≤ 1.5:1 from 30 MHz to 60 MHz, typical				
Maximum input voltage	5 V _{RMS} with peaks $\leq \pm 20$ V, (DF<=6.25%)				
(50 Ω and 75 $\Omega)$	There is an over-voltage trip circuit, intended to protect against overloads that might damage termination resistors. A sufficiently large impulse can cause damage regardless of the over-voltage protection circuitry, due to the finite time required to detect the over-voltage condition and respond to it.				
Maximum input voltage	The maximum input voltage at the BNC, 300 V _{RMS} .				
(1 MΩ)	Installation Category II.				
	De-rate at 20 dB/decade between 4.5 MHz and 45 MHz, De-rate 14 db between 45 MHz and 450 MHz. Above 450 MHz, 5 V_{RMS} .				
	Maximum peak input voltage at the BNC, \pm 424 V				

Table 1: Analog channel input and vertical specifications (cont.)

Characteristic	Description				
DC balance	0.2 div with the input DC-50 coupled and 50 coupled a				
(See page 78.)	0.25 div at 2 mV/div with the input DC-50 Ω coupled and 50 Ω terminated				
	0.5 div at 1 mV/div with the input DC-50 Ω coupled and 50 Ω terminated				
	0.2 div with the	e input DC-75 Ω coupled and 75 Ω term	inated		
	0.25 div at 2 m	νV/div with the input DC-75 Ω coupled a	nd 75 Ω terminated		
	0.5 div at 1 m	//div with input DC-75 Ω coupled and 75	ο Ω terminated		
	0.2 div with the	e input DC-1 MΩ coupled and 50 Ω term	ninated		
	0.3 div at 1 m	//div with the input DC-1 M Ω coupled an	d 50 Ω terminated		
	All the above s	specifications are increased by 0.01 divis	sions per °C above 40 °C.		
Delay between channels,	≤ 100 ps betw	een any two channels with input termina	tion set to 50 Ω , DC coupling		
full bandwidth, typical		een any two channels with input termina			
			ne aligned using the Probe Deskew function		
Deskew range	-125 ns to +1	25 ns			
Crosstalk (channel		≤100 MHz	>100 MHz		
isolation), typical	1 MΩ	100:1	30:1		
	50 Ω	100:1	30:1		
	75 Ω	100:1	30:1		
TekVPI Interface	The probe interface allows installing, powering, compensating, and controlling a wide range of probes offering a variety of features.				
	The interface is available on CH1-CH4 front panel inputs. Aux In is available on the front of two-channel instrument only and is fully VPI compliant. Four-channel instruments have no Aux In input.				
Number of digitized bits	8 bits				
	Displayed vertically with 25 digitization levels (DL) per division, 10.24 divisions dynamic range				
			the smallest voltage level change that can so known as the LSB (least significant bit).		
Sensitivity range (coarse)	1 M Ω: 1 mV/div to 10 V/div in a 1-2-5 sequence				
	50 Ω and 75 Ω:	1 mV/div to 1 V/div in a 1-2-5 sequence	e .		
Sensitivity range (fine)	Allows continuous adjustment from 1 mV/div to 10 V/div, 1 MΩ				
	Allows continuous adjustment from 1 mV/div to 1 V/div, 75 Ω				
	Allows continuous adjustment from 1 mV/div to 1 V/div, 50 Ω				
Sensitivity resolution (fine), typical	≤ 1% of current	nt setting			
Position range	±5 divisions				

Table 1: Analog channel input and vertical specifications (cont.)

Characteristic	Description	ption				
\checkmark Analog bandwidth, 50 Ω input termination				f ≤ 30 °C and the band for each °C above 30		
(See page 80.)	Instrument Bandwidth	Vertical Scale Setting				
		10 mV/div to 1 V/div	5 mV/div to 9.98 mV/div	2 mV/div to 4.98 mV/div	1 mV/div to 1.99 mV/div	
	1.00 GHz	DC to 1.0 GHz	DC to 500 MHz	DC to 350 MHz	DC to 150 MHz	
	500 MHz	DC to 500 MHz		DC to 350 MHz	DC to 150 MHz	
	350 MHz	DC to 350 MHz		DC to 350 MHz	DC to 150 MHz	
	200 MHz	DC to 200 MHz		•	DC to 150 MHz	
	100 MHz	DC to 100 MHz				
Analog bandwidth, 75 Ω input termination, typical		The limits stated below are for ambient temperature of \leq 30 °C and the bandwidth selection set to FULL. Reduce the upper bandwidth frequency by 1% for each °C above 30 °C.				
	Instrument		Vertical	Scale Setting		
	Bandwidth	10 mV/div to 1 V/div	5 mV/div to 9.98 mV/div	2 mV/div to 4.98 mV/div	1 mV/div to 1.99 mV/div	
	500 MHz, 350 MHz, and 200 MHz	DC to 200 MHz		DC to 140 MHz	DC to 100 MHz	
	100 MHz	DC to 100 MHz				
Analog bandwidth, 1 M Ω input termination. The				f ≤ 30 °C and the band for each °C above 30		
Analog Bandwidth when the instrument is DC-1M Ω	Instrument	Vertical Scale Setting				
coupled, typical	Bandwidth	2 mV/div to 10 V/div	1 mV/div to 1.99 mV/div			
	1 GHz, 500 MHz, or 350 MHz	DC to 350 MHz	DC to 150 MHz			
	200 MHz	DC to 200 MHz	DC to 150 MHz]		
	100 MHz	DC to 100 MHz				

Table 1: Analog channel input and vertical specifications (cont.)

Characteristic	Description					
Analog Bandwidth, 1 MΩ with Standard Probe,				f ≤ 30 °C and the band for each °C above 30		
typical	Instrument	Vertical Scale Se	Vertical Scale Setting			
	Bandwidth	100 mV/div to 100 V/div	50 mV/div to 99.8 mV/div	20 mV/div to 49.8 mV/div	10 mV/div to 19.9 mV/div	
	1 GHz	DC to 1.00 GHz	DC to 400 MHz	DC to 250 MHz	DC to 150 MHz	
	500 MHz	DC to 500 MHz	DC to 400 MHz	DC to 250 MHz	DC to 150 MHz	
	350 MHz	DC to 350 MHz		DC to 250 MHz	DC to 150 MHz	
	200 MHz	DC to 200 MHz			DC to 150 MHz	
	100 MHz	DC to 100 MHz				
typical	All values in th	ne above table are models assume th	in pS. 1 GHz BW mo	endent of the rise time dels assume the TPP1 200 MHz and 100 MH:	000 probe. 500 MHz	
	Instrument	5 ()				
	Bandwidth	1 mV/div to 1.99 mV/div	2 mV/div to 4.98 mV/div	5 mV/div to 9.98 mV/div	10 mV/div to 1 V/div	
	1 GHz	2,666 ps	1,333 ps	800 ps	400 ps	
	500 MHz	2,666 ps	1,333 ps	800 ps	800 ps	
	350 MHz	2,666 ps	1,333 ps	1,143 ps	1,143 ps	
	200 MHz	2,666 ps	2,000 ps	2,000 ps	2,000 ps	
	100 MHz	4,000 ps	4,000 ps	4,000 ps	4,000 ps	
	Instrument	e)				
	Bandwidth	10 mV to 19.9 mV	20 mV to 49.8 mV	50 mV to 99.8 mV	100 mV to 100 V	
	1 GHz	2,666 ps	1,600 ps	1,000 ps	400 ps	
	500 MHz	2,666 ps	1,600 ps	1,000 ps	800 ps	
	350 MHz	2,666 ps	1,600 ps	1,143 ps	1,143 ps	
	200 MHz	2,666 ps	2,000 ps	2,000 ps	2,000 ps	
	100 MHz	4,000 ps	4,000 ps	4,000 ps	4,000 ps	
Analog bandwidth limit	For instrumen	ts with 1 GHz, 500	MHz or 350 MHz ana	log bandwidth: 20 MI	Hz, 250 MHz, and Fu	
filter selections	For instrumen	ts with 200 MHz ar	nd 100 MHz analog b	andwidth: 20 MHz ar	nd Full	

Table 1: Analog channel input and vertical specifications (cont.)

Characteristic	Description			
Lower frequency limit, AC coupled, typical	< 10 Hz when AC to 1 M Ω coupled The AC coupled lower frequency limits are reduced by a factor of 10 when 10X passive probes are used.			
Upper frequency limit, 250 MHz bandwidth limit filter, typical	250 MHz, +25%, and -25% (all models, except 100 MHz and 200 MHz)			
Upper frequency limit, 20 MHz bandwidth limit filter, typical	20 MHz, ±25% (all models)			
✓ DC gain accuracy (See page 83.)	±2.5% for 1 mV/Div, derated at 0.100%/°C above 30 °C ±2.0% for 2 mV/Div, derated at 0.100%/°C above 30 °C ±1.5% for 5 mV/Div and above, derated at 0.100%/°C above 30 °C ±3.0% Variable Gain, derated at 0.100%/°C above 30 °C			
DC voltage measurement accuracy	Measurement type	DC Accuracy (in volts)		
Sample acquisition mode,	Any sample	±[DC gain accuracy X reading – (offset – position) + Offset Accuracy +0.15 div + 0.6 mV]		
typical	Delta volts between any two samples acquired with the same oscilloscope setup and ambient conditions	±[DC gain accuracy X reading + 0.15 div + 1.2 mV]		
	NOTE. Offset, position, and the the appropriate volts/div term.	constant offset term must be converted to volts by multiplying by		
Average acquisition mode	Average of ≥ 16 waveforms	±[DC gain accuracy X reading – (offset – position) + Offset Accuracy + 0.1 div]		
	Delta volts between any two averages of ≥ 16 waveforms acquired with the same oscilloscope setup and ambient conditions	±[DC gain accuracy X reading + 0.05 div]		
	NOTE. Offset, position, and the constant offset term must be converted to volts by multiplying by the appropriate volts/div term.			
	measurements: High, Low, Max,	cification applies directly to any sample and to the following Min, Mean, Cycle Mean, RMS, and Cycle RMS. The delta volt subtractive calculations involving two of these measurements.		
		e) accuracy specification applies directly to the following pot, Negative Overshoot, Peak-Peak, and Amplitude.		

Table 1: Analog channel input and vertical specifications (cont.)

Characteristic	Description	-			
Offset ranges	Volts/div	Offset range			
	setting	1 M Ω input	50 Ω and 75 Ω	input	
	1 mV/div to 50 mV/div	±1 V	±1 V		
	50.5 mV/div to 99.5 mV/div	±0.5 V	±0.5 V		
	100 mV/div to 500 mV/div	±10 V	±5 V		
	505 mV/div to 995 mV/div	±5 V	±5 V		
	1 V/div to 10 V/div 1	±100 V	±5 V		
		, ,			he 50 Ω and 75 Ω input able) for more information
Offset accuracy	$\pm 10.000 \times 10$				
	±[0.005 X o NOTE. Both appropriate v	the position and	-	must be converted to	volts by multiplying by t
(See page 87.) ✓ Random noise,	NOTE. Both	the position and	-		volts by multiplying by t
(See page 87.) ✓ Random noise, sample acquisition mode, 50 Ω termination setting	NOTE. Both	the position and	constant offset term		volts by multiplying by t
(See page 87.) ✓ Random noise, sample acquisition mode, 50 Ω termination setting	NOTE. Both appropriate v	the position and olts/div term.	constant offset term 50Ω, RMS,	unit in mV	
 (See page 87.) ✓ Random noise, sample acquisition mode, 50 Ω termination setting (See page 90.) 	NOTE. Both appropriate v	the position and olts/div term. MDO305x	constant offset term 50Ω, RMS, MDO303x	unit in mV MDO302x	MDO301x
(See page 87.) Random noise, sample acquisition mode, 50 Ω termination setting (See page 90.) 1 mV, Full BW	NOTE. Both appropriate v MDO31xx 0.21	the position and olts/div term. MDO305x 0.2	constant offset term 50Ω, RMS, MDO303x 0.2	unit in mV MDO302x 0.2	MDO301x 0.19
(See page 87.) ✓ Random noise, sample acquisition mode, 50 Ω termination setting (See page 90.) 1 mV, Full BW 2 mV, Full BW	NOTE. Both appropriate v MDO31xx 0.21 0.33	the position and olts/div term. MDO305x 0.2 0.27	constant offset term 50Ω, RMS, MDO303x 0.2 0.25	unit in mV MDO302x 0.2 0.23	MDO301x 0.19 0.21
(See page 87.) ✓ Random noise, sample acquisition mode, 50 Ω termination setting (See page 90.) 1 mV, Full BW 2 mV, Full BW 5 mV, Full BW	NOTE. Both appropriate v MDO31xx 0.21 0.33 0.55	the position and olts/div term. MDO305x 0.2 0.27 0.36	constant offset term 50Ω, RMS, MDO303x 0.2 0.25 0.36	unit in mV MDO302x 0.2 0.23 0.3	MDO301x 0.19 0.21 0.3
(See page 87.) Random noise, sample acquisition mode, 50 Ω termination setting (See page 90.) 1 mV, Full BW 2 mV, Full BW 5 mV, Full BW 10 mV, Full BW	NOTE. Both appropriate v MDO31xx 0.21 0.33 0.55 0.7	the position and olts/div term. MDO305x 0.2 0.27 0.36 0.5	Solution Solution	unit in mV MDO302x 0.2 0.23 0.3 0.45	MDO301x 0.19 0.21 0.3 0.45
(See page 87.) ✓ Random noise, sample acquisition mode, 50 Ω termination setting (See page 90.) 1 mV, Full BW 2 mV, Full BW 10 mV, Full BW 20 mV, Full BW	NOTE. Both appropriate v MDO31xx 0.21 0.33 0.55 0.7 1	the position and olts/div term. MDO305x 0.2 0.27 0.36 0.5 0.9	Solution Solution	unit in mV MDO302x 0.2 0.23 0.3 0.45 0.9	MDO301x 0.19 0.21 0.3 0.45 0.9
(See page 87.) Random noise, sample acquisition mode, 50 Ω termination setting (See page 90.) 1 mV, Full BW 2 mV, Full BW 5 mV, Full BW 10 mV, Full BW 20 mV, Full BW 50 mV, Full BW 50 mV, Full BW	NOTE. Both appropriate v MDO31xx 0.21 0.33 0.55 0.7 1 3 3	MDO305x 0.2 0.27 0.36 0.5 0.9 2.75	SOΩ, RMS, MDO303x 0.2 0.25 0.36 0.5 0.9 2.75	unit in mV MDO302x 0.2 0.23 0.3 0.45 0.9 2.75	MDO301x 0.19 0.21 0.3 0.45 0.9 2.25
2 mV, Full BW 5 mV, Full BW 10 mV, Full BW 20 mV, Full BW 50 mV, Full BW 100 mV, Full BW	NOTE. Both appropriate v MDO31xx 0.21 0.33 0.55 0.7 1 3 4.5	MDO305x 0.2 0.27 0.36 0.5 0.9 2.75 4.15	Solution Solution	unit in mV MDO302x 0.2 0.23 0.3 0.45 0.9 2.75 4.15	MDO301x 0.19 0.21 0.3 0.45 0.9 2.25 4.15

Table 1: Analog channel input and vertical specifications (cont.)

Characteristic		Description				
1 mV, 250 MHz BW		0.21	0.2	0.2	_	-
	2 mV, 250 MHz BW	0.25	0.23	0.23	-	-
	5 mV, 250 MHz BW	0.35	0.3	0.3	-	-
	10 mV, 250 MHz BW	0.5	0.5	0.5	-	_
	20 mV, 250 MHz BW	1	1	1	-	_
	50 mV, 250 MHz BW	2.75	2.75	2.75	-	_
	100 mV, 250 MHz BW	4.15	4.15	4.15	-	_
	200 mV, 250 MHz BW	10	10	10	-	_
	500 mV, 250 MHz BW	20	20	20	-	-
	1 V, 250 MHz BW	40	40	40	—	_
	1 mV, 20 MHz BW	0.12	0.12	0.12	0.12	0.12
	2 mV, 20 MHz BW	0.15	0.15	0.15	0.15	0.15
	5 mV, 20 MHz BW	0.25	0.25	0.25	0.25	0.25
	10 mV, 20 MHz BW	0.45	0.4	0.4	0.4	0.4
	20 mV, 20 MHz BW	0.8	0.75	0.75	0.75	0.75
	50 mV, 20 MHz BW	2.1	2.1	2.1	2.1	2.1
	100 mV, 20 MHz BW	4.1	4.1	4.1	4.1	4.1
	200 mV, 20 MHz BW	8	8	8	8	8
	500 mV, 20 MHz BW	20	20	20	20	20
	1 V, 20 MHz BW	40	40	40	40	40

Table 1: Analog channel input and vertical specifications (cont.)

Chara	acteristic	Description					
Random noise, sample				Typical, 50Ω, ł	RMS		
•	sition mode, 50 Ω nation setting, typical	MDO31xx	MDO305x	MDO303x	MDO302x	MDO301x	
	1 mV, Full BW	0.179	0.178	0.169	0.178	0.162	
	100 mV, Full BW	2.4	2.05	1.98	1.94	1.88	
	1 V, Full BW	24.67	20.99	20.03	19.41	18.8	

Table 1: Analog channel input and vertical specifications (cont.)

¹ For 50 Ω and 75 Ω path, 1 V/div is the maximum vertical setting.

Digital Channel Acquisition System Specifications

Characteristic	Description			
Threshold voltage range	–15 V to +25 V			
Digital channel timing resolution	Minimum: 2 ns for the main memory Minimum: 121.2 ps for MagniVu memory			
Threshold accuracy (See page 93.)	± [100 mV + 3% of threshold setting after calibration], after valid SPC			
Minimum detectable pulse	2.0 ns Using MagniVu memory. Specified at the input to the P6316 probe with all eight ground inputs connected to the user's ground. Use of lead sets, grabber clips, ground extenders, or other connection accessories may compromise this specification.			
Channel to channel skew (typical)	500 ps Digital Channel to Digital Channel only This is the propagation path skew, and ignores skew contributions due to bandpass distortion, threshold inaccuracies (see Threshold Accuracy), and sample binning (see Digital Channel Timing Resolution).			

Table 2: Digital channel acquisition system specifications

Horizontal And Acquisition System Specifications

Characteristic		Description					
Long-term samp time accuracy (See		±10 ppm over any ≥ 1 ms time interval					
Seconds/division ra	nge	MDO30XX models: 1 ns/div to 1000 sec/div					
		MDO310X mo	dels: 400 ps/div to 1000 s	sec/div			
Peak detect or envelope mode pulse response, typical		Instrument		Minimum pulse width	ı		
		Models at 1 G	Hz BW	> 1.5 ns			
		Models at 500	MHz BW	> 2.0 ns			
		Models at 350	MHz BW	> 3.0 ns			
		Models at 200	MHz BW	> 5.0 ns			
		Models at 100	MHz BW	> 7.0 ns			
Sample-rate range		See Sample R	ate Range detail table. (See page 13.)			
Record length range	e	1K, 10K, 100K	i, 1M, 5M, 10M				
Maximum triggered	acquisition rate	1 and 2 chann	els	3 and 4 channels			
	Bandwidth	FastAcq	DPO	FastAcq	DPO		
-	1 GHz	> 280,000 wfm/sec	> 80,000 wfm/sec	> 230,000 wfm/sec	> 50,000 wfm/see		
-	< 1 GHz	> 230,000 wfm/sec	> 50,000 wfm/sec	> 230,000 wfm/sec	> 50,000 wfm/sec		
Aperture uncertainty (also called "sample		\leq (5 ps + 1 × 10 ⁻⁶ X record duration) _{RMS} , for records having duration \leq 1 minute Record duration = (Record Length) / (Sample Rate)					
Number of waveform acquisition mode	ms for average	2 to 512 waveforms Default of 16 waveforms					
✓ Delta time meas (See page 91.)	surement accuracy	The formula to calculate delta-time measurement accuracy (DTA) for a given instrument setting and input signal is given below (assumes insignificant signal content above Nyquist).					
		SR ₁ = Slew Rate (1 st Edge) around the 1 st point in the measurement					
		SR_2 = Slew Rate (2 nd Edge) around the 2 nd point in the measurement					
		N = input-referred noise (volts _{rms} , refer to the Random Noise, Sample acquisition mode specification)					
		t _{sr} = 1 / (Sample Rate)					
		accuracy spec	se accuracy (refer to the lification above)	Long-term sample rate	and delay time		
		•	measurement duration				
		RD = (Record Length) / (Sample Rate)					

Table 3: Horizontal and acquisition system specifications

Table 3: Horizontal and acquisition system specifications (cont.)

$$DTA_{PP} = \pm 5 \times \sqrt{2 \times \left[\frac{N}{SR_{1}}\right]^{2} + 2 \times \left[\frac{N}{SR_{2}}\right]^{2} + (5ps + 1E^{-6} \times RD)^{2}} + 2 \times t_{sr} + TBA \times t_{p}$$
$$DTA_{RMS} = \sqrt{2 \times \left[\frac{N}{SR_{1}}\right]^{2} + 2 \times \left[\frac{N}{SR_{2}}\right]^{2} + (5ps + 1E^{-6} \times RD)^{2} + \left[\frac{2 \times t_{sr}}{\sqrt{12}}\right]^{2}} + TBA \times t_{p}$$

Assumes that error due to aliasing is insignificant.

The term under the square-root sign is the stability, and is related to the TIE (Time Interval Error). The errors from this term occur throughout a single-shot measurement. The second term is a result of both the absolute center-frequency accuracy and the center-frequency stability of the timebase, and varies between multiple single-shot measurements over the observation interval (the amount of time from the first single-shot measurement to the final single-shot measurement).

Sample Rate Range

(MDO310X with 3	B or 4 channels enabled or all other MDO3000 with 1, 2, 3, or 4 channels enabled)
0	

Characteristic	Descripti	Description					
Sample rate range	Time- /Div	10 M record	5 M record	1 M record	100 K record	10 K record	1 K record
(Analog Channels)	1 ns	2.5 GS/s					
onumeroj	2 ns	2.5 GS/s					
	4 ns	2.5 GS/s					
	10 ns	2.5 GS/s					
	20 ns	2.5 GS/s					
	40 ns	2.5 GS/s					
	80 ns						1.25 GS/s
	100 ns	2.5 GS/s					
	200 ns	2.5 GS/s					500 MS/s
	400 ns	2.5 GS/s					250 MS/s
	800 ns					1.25 GS/s	
	1 µs	2.5 GS/s					100 MS/s
	2 µs	2.5 GS/s				500 MS/s	50 MS/s
	4 µs	2.5 GS/s				250 MS/s	25 MS/s
	8 µs				1.25 GS/s		
	10 µs	2.5 GS/s				100 MS/s	10 MS/s
	20 µs	2.5 GS/s			500 MS/s	50 MS/s	5 MS/s
	40 µs	2.5 GS/s			250 MS/s	25 MS/s	2.5 MS/s
	80 µs			1.25 GS/s			
	100 µs	2.5 GS/s			100 MS/s	10 MS/s	1 MS/s
	200 µs	2.5 GS/s		500 MS/s	50 MS/s	5 MS/s	500 KS/s
	400 µs	2.5 GS/s	1.25 GS/s	250 MS/s	25 MS/s	2.5 MS/s	250 KS/s
	800 µs	1.25 GS/s	625 MS/s				

Table 4: Sample rate range (MDO310X with 3 or 4 channels enabled or all other MDO3000 with 1, 2, 3, or 4	
channels enabled) (cont.)	

Characteristic	tic Description						
Sample rate range (Analog	Time- /Div	10 M record	5 M record	1 M record	100 K record	10 K record	1 K record
Channels) (Cont.)	1 ms			100 MS/s	10 MS/s	1 MS/s	100 KS/s
(00111.)	2 ms	500 MS/s	250 MS/s	50 MS/s	5 MS/s	500 KS/s	50 KS/s
	4 ms	250 MS/s	125 MS/s	25 MS/s	2.5 MS/s	250 KS/s	25 KS/s
	10 ms	100 MS/s	50 MS/s	10 MS/s	1 MS/s	100 KS/s	10 KS/s
	20 ms	50 MS/s	25 MS/s	5 MS/s	500 KS/s	50 KS/s	5 KS/s
	40 ms	25 MS/s	12.5 MS/s	2.5 MS/s	250 KS/s	25 KS/s	2.5 KS/s
	100 ms	10 MS/s	5 MS/s	1 MS/s	100 KS/s	10 KS/s	1 KS/s
	200 ms	5 MS/s	2.5 MS/s	500 KS/s	50 KS/s	5 KS/s	500 S/s
	400 ms	2.5 MS/s	1.25 MS/s	250 KS/s	25 KS/s	2.5 KS/s	250 S/s
	1 s	1 MS/s	500 KS/s	100 KS/s	10 KS/s	1 KS/s	100 S/s
	2 s	500 KS/s	250 KS/s	50 KS/s	5 KS/s	500 S/s	50 S/s
	4 s	250 KS/s	125 KS/s	25 KS/s	2.5 KS/s	250 S/s	25 S/s
	10 s	100 KS/s	50 KS/s	10 KS/s	1 KS/s	100 S/s	10 S/s
	20 s	50 KS/s	25 KS/s	5 KS/s	500 S/s	50 S/s	5 S/s
	40 s	25 KS/s	12.5 KS/s	2.5 KS/s	250 S/s	25 S/s	2.5 S/s
	100 s	10 KS/s	5 KS/s	1 KS/s	100 S/s	10 S/s	
	200 s	5 KS/s	2.5 KS/s	500 S/s	50 S/s	5 S/s	
	400 s	2.5 KS/s	1.25 KS/s	250 S/s	25 S/s	2.5 S/s	
	1000 s	1 KS/s	500 S/s	100 S/s	10 S/s		_

Characteristic	eristic Description						
Sample rate range	Time- /Div	10 M record	5 M record	1 M record	100 K record	10 K record	1 K record
(Analog Channels)	400 ps	5 GS/s					
onamicioj	1 ns	5 GS/s					
	2 ns	5 GS/s					
	4 ns	5 GS/s					
	10 ns	5 GS/s					
	20 ns	5 GS/s					
	40 ns	5 GS/s					2.5 GS/s
	100 ns	5 GS/s	1 GS/s				
	200 ns	5 GS/s					500 MS/s
	400 ns	5 GS/s				2.5 GS/s	250 MS/s
	1 µs	5 GS/s	5 GS/s 1 GS/s				
	2 µs	5 GS/s				500 MS/s	50 MS/s
	4 µs	5 GS/s			2.5 GS/s	250 MS/s	25 MS/s
	10 µs	5 GS/s			1 GS/s	100 MS/s	10 MS/s
	20 µs	5 GS/s			500 MS/s	50 MS/s	5 MS/s
	40 µs	5 GS/s		2.5 GS/s	250 MS/s	25 MS/s	2.5 MS/s
	100 µs	5 GS/s		1 GS/s	100 MS/s	10 MS/s	1 MS/s
	200 µs	5 GS/s	2.5 GS/s	500 MS/s	50 MS/s	5 MS/s	500 KS/s
	400 µs	2.5 GS/s	1.25 GS/s	250 MS/s	25 MS/s	2.5 MS/s	250 KS/s

Table 5: Sample rate range, (MDO310X models with 1 or 2 channels enabled)

Characteristic	Description						
Sample rate range (Analog	Time- /Div	10 M record	5 M record	1 M record	100 K record	10 K record	1 K record
Channels) (Cont.)	1 ms	1 GS/s	500 MS/s	100 MS/s	10 MS/s	1 MS/s	100 KS/s
(0011.)	2 ms	500 MS/s	250 MS/s	50 MS/s	5 MS/s	500 KS/s	50 KS/s
	4 ms	250 MS/s	125 MS/s	25 MS/s	2.5 MS/s	250 KS/s	25 KS/s
	10 ms	100 MS/s	50 MS/s	10 MS/s	1 MS/s	100 KS/s	10 KS/s
	20 ms	50 MS/s	25 MS/s	5 MS/s	500 KS/s	50 KS/s	5 KS/s
	40 ms	25 MS/s	12.5 MS/s	2.5 MS/s	250 KS/s	25 KS/s	2.5 KS/s
	100 ms	10 MS/s	5 MS/s	1 MS/s	100 KS/s	10 KS/s	1 KS/s
	200 ms	5 MS/s	2.5 MS/s	500 KS/s	50 KS/s	5 KS/s	500 S/s
	400 ms	2.5 MS/s	1.25 MS/s	250 KS/s	25 KS/s	2.5 KS/s	250 S/s
	1 s	1 MS/s	500 KS/s	100 KS/s	10 KS/s	1 KS/s	100 S/s
	2 s	500 KS/s	250 KS/s	50 KS/s	5 KS/s	500 S/s	50 S/s
	4 s	250 KS/s	125 KS/s	25 KS/s	2.5 KS/s	250 S/s	25 S/s
	10 s	100 KS/s	50 KS/s	10 KS/s	1 KS/s	100 S/s	10 S/s
	20 s	50 KS/s	25 KS/s	5 KS/s	500 S/s	50 S/s	5 S/s
	40 s	25 KS/s	12.5 KS/s	2.5 KS/s	250 S/s	25 S/s	2.5 S/s
	100 s	10 KS/s	5 KS/s	1 KS/s	100 S/s	10 S/s	
	200 s	5 KS/s	2.5 KS/s	500 S/s	50 S/s	5 S/s	
	400 s	2.5 KS/s	1.25 KS/s	250 S/s	25 S/s	2.5 S/s	
	1000 s	1 KS/s	500 S/s	100 S/s	10 S/s		

Table 5: Sample rate range, (MDO310X models with 1 or 2 channels enabled) (cont.)

Trigger Specifications

Table	6:	Trigger	specifications
-------	----	---------	----------------

Characteristic	Description				
Trigger level ranges	Source		Sensitivity		
	Any input channel		 ±8 divisions from center of screen, ±8 divisions from 0 V when vertical LF reject trigger coupling is selected 		
	Aux In (External)		±8 V		
	Line		Not applicable		
	The line trigger lev This specification a		50% of the line voltage. pulse thresholds.		
Trigger level	For signals having	rise and fall times	≥ 10 ns, the limits are as follows:		
accuracy, DC coupled, typical	Source		Range		
coupied, typical	Any channel		±0.20 divisions		
	Aux In (external trig	gger)	±(10% of setting + 25 mV)		
	Line		Not applicable		
Lowest frequency for "Set Level to 50%" function, typical	45 Hz				
Trigger holdoff range	20 ns minimum to	8 seconds maximu	m		
Trigger sensitivity	Edge trigger,	Trigger Source	Sensitivity		
	DC coupled, typical	Any analog channel	1 mV/div to 4.98 mV/div: 0.75 div from DC to 50 MHz, increasing to 1.3 div at instrument bandwidth.		
			\geq 5 mV/div: 0.40 divisions from DC to 50 MHz, increasing to 1 div at instrument bandwidth		
		Aux in (External)	200 mV from DC to 50 MHz, increasing to 500 mV at 200 MHz		
		Line	Not applicable		
	Edge trigger, not DC coupled,	Trigger Coupling	Typical Sensitivity		
	typical	AC	1.5 times the DC Coupled limits for frequencies above 10 Hz. Attenuates signals below 10 Hz		
		NOISE REJ	2.5 times the DC-coupled limits		
		HF REJ	1.5 times the DC-coupled limit from DC to 50 kHz. Attenuates signals above 50 kHz		
		LF REJ	1.5 times the DC-coupled limits for frequencies above 50 kHz. Attenuates signals below 50 kHz		

Characteristic	Description				
	Logic (pattern) trigger, DC coupled, typical:		1.0 division from DC to maximum bandwidth		
	Trigger using a log DC coupled, typic	5 .	1.0 division from DC to maximum ban	dwidth	
	Delay-by-events s DC coupled, typic		1.0 division from DC to maximum ban	dwidth	
	Runt trigger, typic	al:	≥1.0 division from DC to maximum ba	Indwidth	
	Pulse-width and g	litch trigger, typical:	1.0 division, from DC to Max Bandwid	th.	
	Video trigger,	The limits for bo	th delayed and main trigger are as follow	vs:	
	typical	Source	Typical Sensitivity		
		Any analog input channel	0.6 to 2.5 divisions of video sync tip		
		Aux In (External)	Video not supported through Aux In (External) input		
Aux In (External	Maximum input voltage:		At front panel connector, 300 $V_{\mbox{\tiny RMS}},$ Installation Category II;		
rigger)			Derate at 20 dB/decade above 3 MHz to 30 V_{RMS} at 30 MHz, 10 dB/decade above 30 MHz		
			Based upon sinusoidal or DC input signal. Excursion above 300 V should be less than 100 ms duration and the duty factor is limited to < 44%. RMS signal level must be limited to 300 V If these values are exceeded, damage to the instrument may result.		
	Bandwidth, typica	l:	> 250 MHz		
Edge, Pulse, and Logic trigger			h (includes MDO310X models X models with 500 MHz upgrade):	≥1 GHz	
bandwidth, typical			idth (includes MDO305X models dels with 500 MHz upgrade):	≥500 MHz	
			vidth (includes MDO303X models ≥500 MHz vith 350 MHz upgrade):		
		ith 200 MHz bandw 01X models with 20	vidth (includes MDO302X models ≥200 MHz 0 MHz upgrade):		
	For instruments w	ith 100 MHz bandw	vidth (MDO301X models): ≥200 MHz		
Time accuracy	Time range		Accuracy		
for Pulse-width triggering	1 ns to 500 ns		±(20% of setting + 0.5 ns)		
	520 ns to 8 s		±(0.01% of setting + 100 ns)		

Characteristic	Description							
Video trigger formats and field rates	Triggers from negative sync composite video, field 1 or field 2 for interlaced systems, any field, specific line, or any line for interlaced or non-interlaced systems. Supported systems include NTSC, PAL, SECAM.							
	1080i/50, 1080i/60,	Standard Video formats are: Trigger on 480p/60, 576p/50, 720p/30, 720p/50, 720p/60, 875i/60, 1080i/50, 1080i/60, 1080p/24, 1080p/24sF, 1080p/25, 1080p/30, 1080p/50, 1080p/60, and custom bi-level and tri-level sync video standards.						
Logic trigger,	For all vertical settings, the minimums are:							
minimum logic or re-arm time, typical	Trigger type		Minimum pulse width	Minimum re-arm time	Minimum time between channels 1			
	Logic		Not applicable	2 ns	2 ns			
	Time Qualified Logi	С	4 ns	2 ns	2 ns			
Setup/hold time violation trigger								
Minimum clock	For all vertical settin	ngs, the minimum	clock pulse widths ar	re:				
pulse widths, typical	Clock Active ²		Clock Inactive ²					
	User hold time + 2.5	5 ns ³	2 ns					
Setup and hold	The limits are as follows;							
time ranges	Feature Min		Мах					
	Setup time ⁴	–0.5 ns	1.024 ms					
	Hold time ⁴	1 ns	1.024 ms					
	Setup + Hold time ⁴	0.5 ns	2.048 ms					
	NOTE. Input coupl	ing on clock and d	ata channels must b	e the same.				
Minimum pulse width and	Trigger type	Minimum pulse width	Minimum rearm time					
rearm time	Glitch	4 ns	2 ns + 5% of glitch	width setting				
	Pulse-width	4 ns	2 ns + 5% of width upper limit setting					
		NOTE. For the pulse-width trigger class, pulse-width refers to the width of the pulse being measured. The rearm time refers to the time between pulses.						
	Runt	4 ns	2 ns					
				se width refers to the w the time between pulse				
	Time-qualified runt	4 ns	8.5 ns + 5% of wid	th setting				
	Slew rate	4 ns	8.5 ns + 5% of del	ta time setting				
		NOTE. For the slew rate trigger class, pulse width refers to the delta time being measured. The rearm time refers to the time it takes the signal to cross the two trigger thresholds again.						

Characteristic	Description			
Rise/fall time trigger, delta time range	4 ns to 8 seconds			
Glitch, pulse-width, or time-qualified runt trigger, time range	4 ns to 8 seconds			
B trigger	Trigger after events, minimum pulse width, typical: ⁵		1 / (2 X Rated Instrument Bandwidth)	
(A/B sequence trigger), time range	Trigger after events, maximum event	frequency, typical: ⁵	[Rated Instrument Bandwidth] or 500 MHz, whichever is lower	
	Minimum time between arm and trigg	er	8 ns	
	B trigger after time, time range:		8 ns to 8 s	
	B trigger after events, event range:		1 to 4,000,000	
Standard serial bus interface triggers	Maximum serial trigger bits:	128 bits		
I²C (Requires an	Address Triggering:	7 and 10 bit user specified address, as well as General Call START byte, HS-mode, EEPROM, and CBUS		
MDO3EMBD	Data Trigger:	1 to 5 bytes of user specified data		
app. module)	Trigger On:	Start Repeated Start Stop, Missing Ack Address		
		Data		
		Address and Data		
	Maximum Data Rate:	10 Mb/s		
SPI	Data Trigger:	1 to 16 bytes of use	er specified data	
(Requires an MDO3EMBD app. module)	Trigger On:	SS Active MOSI MISO MOSI and MISO		
	Maximum Data Rate:	10 Mb/s		
		TU IVID/S		

aracteristic	Description	
RS-232/422/	Data Trigger:	Tx Data, Rx Data
485/UART	Trigger On:	Tx Start Bit
(Requires a MDO3COMP		Rx Start Bit
app. module)		Tx End of Packet
opp: measure)		Rx End of Packet
		Tx Data
		Rx Data
		Tx Parity Error
		Rx Parity Error
	Maximum Data Rate:	10 Mb/s
CAN (Requires an MDO3AUTO	Data Trigger:	1 to 8 bytes of user specified data, including qualifiers of equa to (=), not equal to (<>), less than (<), greater than (>), less tha or equal to (<=), greater than or equal to (>=)
app. module)	Trigger On:	Start of Frame
		Type of Frame
		Identifier, Data
		Identifier and Data
		End of Frame
		Missing Ack
		Bit Stuffing Error
	Frame Type:	Data, Remote, Error, Overload
	Identifier:	Standard (11 bit) and Extended (29 bit) identifiers
	Maximum Data Rate:	1 Mb/s
LIN (Requires a MDO3AUTO	Data Trigger:	1 to 8 Bytes of user-specified data, including qualifiers of equa to (=), not equal to (<>), less than (<), greater than (>), less tha or equal to (<=), greater than or equal to (>=)
app. module)	Trigger On :	Sync
		Identifier
		Data
		Identifier & Data
		Wakeup Frame
		Sleep Frame
		Error
	Maximum Data Rate:	1 Mb/s (by LIN definition, 20 kbit/s)

 Table 6: Trigger specifications (cont.)

naracteristic	Description	
FlexRay (Requires a	Indicator Bits	Normal Frame, Payload Frame, Null Frame, Sync Frame, Startup Frame
MDO3FLEX app. module)	Identifier Trigger	11 bits of user-specified data, equal to (=),not equal to <>, less than (<), greater than (>), less than or equal to (<=), greater than or equal to (>=), Inside Range, Outside Range.
	Cycle Count Trigger	6 bits of user-specified data, equal to (<=), greater than or equato (>=), Inside Range, Outside Range.
	Header Fields Trigger	40 bits of user-specified data comprising Indicator Bits, Identifie Payload Length, Header CRC, and Cycle Count, equal to (=).
	Data Trigger	1 – 16 Bytes of user-specified data, with 0 to 253, or "don't carbytes of data offset, including qualifiers of equal to (=), not equ to <>, less than (<), greater than (>), less than or equal to (<=) greater than or equal to (>=), Inside Range, Outside Range.
	End Of Frame	User-chosen types Static, Dynamic (DTS), and All.
	Error	Header CRC, Trailer CRC, Null Frame-static, Null Frame-dynamic, Sync Frame, Startup frame
	Trigger on	Start of Frame, Indicator Bits, Identifier, Cycle Count, Header Fields, Data, Identifier & Data, End of Frame, or Error
MIL-STD-1553	Trigger on:	Sync
(Requires a		Word Type (Command, Status, Data)
MDO3AERO app. module)		Command Word (set the following individually: RT Address (trigger when equal to (=), not equal to <>, less than (<), great than (>), less than or equal to (<=), greater than or equal to (>= inside range, outside range), T/R, Sub-Address/Mode, Data Word Count/Mode Code, And Parity)
		Status Word (set the following individually: RT address (trigge when equal to (=), not equal to <>, less than (<), greater than (>), less than or equal to (<=), greater than or equal to (>=), inside range, outside range), message error, instrumentation, service request bit, broadcast command received, busy, subsystem flag, dynamic bus control acceptance (DBCA), terminal flag, and parity)
		Data Word (user-specified 16-bit data value)
		Error (Sync, Parity, Manchester, Non-Contiguous Data
		Idle Time (minimum time selectable from 4 μs to 100 μs; maximum time selectable from 12 μs to 100 μs; trigger on < minimum, > maximum, inside range, outside range)
	Maximum Data Rate:	Up to 1 Mb/s (for automated decoding of bus)

Characteristic	Description	
l ² S (Requires a MDO3AUDIO app. module)	Data Trigger:	32 bits of user-specified data in a left word, right word, or either, including qualifiers of equal to (=), not equal to <>, less than (<), greater than (>), less than or equal to (<=), greater than or equal to (>=), inside range, outside range.
	Trigger on:	Word Select
		Data
	Maximum Data Rate:	12.5 Mb/s
Left Justified (Requires a MDO3AUDIO app. module)	Data Trigger:	32 bits of user-specified data in a left word, right word, or either, including qualifiers of equal to (=), not equal to (<>), less than (<), greater than (>), less than or equal to (<=), greater than or equal to (>=), inside range, outside range
	Trigger on:	Word Select
		Data
	Maximum Data Rate:	12.5 Mb/s
Right Justified (Requires a MDO3AUDIO app. module)	Data Trigger:	32 bits of user-specified data in a left word, right word, or either, including qualifiers of equal to (=), not equal to <>, less than (<), greater than (>), less than or equal to (<=), greater than or equal to (>=), inside range, outside range
, ,	Trigger on:	Word Select
		Data
	Maximum Data Rate:	12.5 Mb/s
TDM (Requires a MDO3AUDIO app. module)	Data Trigger:	32 bits of user-specified data in a channel 0-7, including qualifiers of equal to (=), not equal to <>, less than (<), greater than (>), less than or equal to (<=), greater than or equal to (>=), inside range, outside range
,	Trigger on:	Frame Sync
		Data
	Maximum Data Rate:	25 Mb/s

 Table 6: Trigger specifications (cont.)

¹ For logic, time between channels refers to the length of time a logic state derived from more than one channel must exist to be recognized. For Time Qualified Logic events, the time is the minimum time between a main and delayed event that will be recognized if more than one channel is used.

An active pulse width is the width of the clock pulse from its active edge (as defined through the Define Inputs button on the lower menu and the Clock Edge button on the side menu) to its inactive edge. An inactive pulse width is the width of the pulse from its inactive edge to its active edge.

³ The User hold time is the number selected by the user through the Setup and Hold trigger menu.

Setup + Hold time is the algebraic sum of the Setup Time and the Hold Time programmed by the user. For Setup time, positive numbers mean a data transition before the clock.

For Hold time, positive numbers mean a data transition after the clock edge.

⁵ Trigger after events is the time between the last A trigger event and the first B trigger event. Trigger after time is the time between the end of the time period and the B trigger event.

Display Specifications

Table 7: Display specifications

Characteristic	Description
Display type	9" WVGA LCD display
	Display Area: 198 mm (H) X 111.696 mm (V).
Display resolution	800 X 480 pixels, each made up of 3 vertical stripe sub-pixels colored red, green, and blue
Minimum Luminance, typical	300 cd/m² at IBL = 5.0 mA _{ms} /lamp

Input/Output Port Specifications

Characteristic	Description		
Ethernet interface	Standard on all models: 10/100 Mb/s		
GPIB interface	Available as an optional accessory that connects to USB Device and USB Host por with the TEK-USB-488 GPIB to USB Adapter		
	Control interface	is incorporated in the instrument user interface	
USB interface	1 Device and 2 Host connectors (all models)		
Device port	One USB 2.0 High Speed port. Also supports Full Speed and Slow Speed Modes		
Host ports	Two USB 2.0 High Speed ports. One on front, one on rear		
Video signal output	A 15 pin, VGA RGB-type connector		
Probe compensator output voltage and frequency, typical	Output voltage: Default Mode: 0 to 2.5 V amplitude, $\pm 2\%$ (Source Impedance of 1 K Ω) TPPXXXX Cal Mode: 0 to 2.5 V amplitude, $\pm 5\%$ (Source Impedance of $\leq 25 \Omega$) Frequency: 1 kHz $\pm 25\%$		
Auxiliary output (AUX OUT)	 Selectable Output: Main Trigger, Event, or AFG Main Trigger: HIGH to LOW transition indicates the trigger occurred Event Out: The instrument will output a negative edge during a specified trigge event in a test application. A falling edge occurs when there is a specified event in a test application (i.e. t waveform crosses the violation threshold in the limit / mask test application). A rising edge occurs when the trigger system begins waiting for the next test application event. AFG: The trigger output signal from the AFG. 		
	Characteristic	Limits	
	Vout (HI)	\ge 2.25 V open circuit; \ge 0.9 V into a 50 Ω load to ground	
	Vout (LO)	\leq 0.7 V into a load of \leq 4 mA; \leq 0.25 V into a 50 Ω load to ground	

Table 8: Input/Output port specifications

Power Source Specifications

Characteristic	Description	
Source voltage	100 V to 240 V ±10%	
Source frequency	100 V to 240 V: 50/60 Hz	
	115 V: 400 Hz ±10%	
Fuse rating	T3.15 A, 250 V	
	The fuse is not customer replaceable.	

Table 9: Power source specifications

Data Storage Specifications

Characteristic	Description
Nonvolatile memory retention time, typical	No time limit for front-panel settings, saved waveforms, setups, and calibration constants
Real-time clock	A programmable clock providing time in years, months, days, hours, minutes, and seconds

Environmental Specifications

Table 11: Environmental specifications	Table 11	: Environn	nental sp	ecifications
--	----------	------------	-----------	--------------

Characteristic	Description
Temperature	Operating: -10 °C to +55 °C (+14 °F to +131 °F)
	Nonoperating: -40 °C to +71 °C (-40 °F to +160 °F)
Humidity	Operating: 5% to 90% relative humidity (% RH) at up to +40 °C, 5% to 60% RH above +40 °C up to +55 °C, non-condensing
	Nonoperating: 5% to 90% RH (Relative Humidity) at up to +40 °C, 5% to 60% RH above +40 °C up to +55 °C 5% to 40% RH above +55 °C up to +71 °C, non-condensing
Altitude	Operating: 3,000 m (9,843 feet)
	Nonoperating: 12,000 m (39,370 feet)
Acoustic noise emission	Sound power level: 32.0 dBA in accordance with ISO 9296

Mechanical Specifications

Characteristic	Description		
Dimensions	Height	mm	In.
	Handle down	203.2	8.0
	Handle up	254	10.3
	Width	416.6	16.4
	Depth	147.4	5.8
	Weight	kg	Lb.
	Stand alone, no front cover	4.2	9.2
	With accessories & carry case	6.8	15.0
	Packaged for domestic shipment	8.6	19.0

Table 12: Mechanical specifications

P6316 Digital Probe Input Characteristics

Table 13: P6316 Digital probe input characteristics

Characteristic	Description	
Number of input channels	16 Digital Inputs	
Input resistance, typical	101 KΩ to ground	
Input capacitance, typical	8 pF 1	
Minimum Input Signal Swing, typical	500 mV _{p-p} 1	
Maximum Input Signal Swing, typical	+30 V, –20 V	
Maximum Input Dynamic Range	50 V_{p-p} , dependent on threshold setting	
Channel-to-channel skew	500 ps	
	Digital channel to digital channel only.	
	This is the propagation path skew. It ignores skew contributions due to bandpass distortion, threshold inaccuracies, and sample binning.	

Specified at the input to the P6316 probe with all eight ground inputs connected to the user's ground. Use of leadsets, grabber clips, ground extenders, or other connection accessories may compromise this specification.

RF Input Specifications

The following table shows the RF input specifications for the MDO3000 Series oscilloscopes.

Characteristic	Description		
Center frequency range	9 kHz to 3.0 GHz (with MDO3SA installed)		
	9 kHz to 1.0 GHz (Any model at 1 GHz BW without MDO3SA installed)		
	9 kHz to 500 MHz (Any model at 500 MHz BW without MDO3SA installed)		
	9 kHz to 350 MHz (Any model at 350 MHz BW without MDO3SA installed)		
	9 kHz to 200 MHz (Any model at 200 MHz BW without MDO3SA installed)		
	9 kHz to 100 MHz (Any m	nodel at 100 MHz without MDO3SA installed)	
Resolution bandwidth range	RBW Range for Windowi Kaiser (default): 30 Hz – Rectangular: 20 Hz – 150 Hamming: 20 Hz – 150 M Hanning: 20 Hz – 150 M Blackman-Harris: 30 Hz – Flat-Top: 50 Hz – 150 MI	150 MHz 0 MHz MHz Hz – 150 MHz	
	Adjusted in 1-2-3-5 seque		
Kaiser RBW shape factor	$60 \text{ db/3 db Shape factor} \le 4:1$		
✓ Reference frequency error (cumulative)	Cumulative Error: ±10 x 10-6		
	Includes allowances for Aging per Year, Reference Frequency Calibration Accuracy, and Temperature Stability.		
	Valid over the recommend	ded 1 year calibration interval, from –10 $^\circ\mathrm{C}$ to +55 $^\circ\mathrm{C}$.	
		log channels share the same reference frequency. uracy is tested by the Long-term Sample Rate and ecks.	
Marker frequency measurement accuracy	±(([Reference Frequency	Error] x [Marker Frequency]) + (span / 750 + 2)) Hz	
	Reference Frequency Error = 10 ppm (10 Hz/MHz)		
	Example, assuming the span is set to 10 kHz and the marker is at 1,500 MHz, this would result in a Frequency Measurement Accuracy of $\pm((10 \text{ Hz}/1 \text{ MHz x } 1,500 \text{ MHz}) + (10 \text{ kHz} / 750 + 2)) = \pm 15.015 \text{ kHz}.$		
	Marker Frequency with Span/RBW ≤ 1000:1		
	Reference Frequency Error with Marker level to displayed noise level > 30 dB		
Phase noise	10 kHz: < –81 dBc/Hz (–85 dBc/Hz, typical)		
	100 kHz: < –97 dBc/Hz (–101 dBc/Hz, typical)		
	1 MHz: < –118 dBc/Hz (–122 dBc/Hz, typical)		
	Phase noise measured offset from 1 GHz CW signal		
Displayed average noise level (DANL)	Frequency range	DANL	
	9 kHz – 50 kHz	< –109 dBm/Hz (< –113 dBm/Hz, typical)	
	50 kHz – 5 MHz	< –126 dBm/Hz (< –130 dBm/Hz, typical)	
	5 MHz – 2 GHz	< –136 dBm/Hz (< –140 dBm/Hz, typical)	

Table 14: RF input specifications

Table 14: RF input specifications (cont.)

✓ Displayed average noise level	9 kHz - 50 kHz –117 dBm/Hz		
(DANL) with TPA-N-PRE Preamp attached	50 kHz - 5 MHz –138 dBm/Hz		
ลและแซน	50 kHz - BW (MDO3SA not148 dBm/Hz installed)		
	5 MHz - 2 GHz (MDO3SA –148 dBm/Hz installed)		
	2 GHz - 3 GHz (MDO3SA –138 dBm/Hz installed)		
Input vertical range	Vertical Measurement range: +20 dBm to DANL.		
	Vertical setting of 1 dB/div to 20 dB/div in a 1-2-5 sequence.		
Attenuation range	Attenuator Settings from 10 to 30 dB, in 5 dB steps		
Spectrum trace length (points)	751 points		
Spurious response (SFDR)	2nd harmonic distortion >100 MHz: < -55 dBc (< -60 dBc typical)		
	with auto settings on and signals 10 dB below reference level		
	2nd harmonic distortion: 9 kHz to 100 MHz: < -55 dBc (< -60 dBc typical)		
	with auto settings on, signals 10 dB below reference level, and reference level \leq –5 dBm		
	3rd harmonic distortion >100 MHz: < -53 dBc (< -58 dBc typical)		
	with auto settings on and signals 10 dB below reference level		
	3rd harmonic distortion: 9 kHz to 100 MHz: < -55 dBc (< -60 dBc typical)		
	with auto settings on, signals 10 dB below reference level, and reference level \leq –5 dBm		
	2nd order intermodulation distortion: >15 MHz: < -55 dBc (< -60 dBc typical)		
	with auto settings on and signals 10 dB below reference level		
	2nd order intermodulation distortion: 9 kHz to 15 MHz: < -47 dBc (< -52 dBc, typical)		
	with auto settings on, signals 10 dB below reference level, and reference level \leq –5 dBm		
	3rd order intermodulation distortion: > 15 MHz		
	< –55 dBc, (<–60 dBc, typical),		
	with auto settings on and signals 10 dB below reference level		
	3rd order intermodulation distortion: 9 kHz to 15 MHz		
	< –55 dBc (<–60 dBc, typical),		
	with auto settings on and signals 10 dB below reference level and reference level \leq –5 dBm		
	-45 dBc (-50 dBc typical) for side bands < 25 kHz offset from the carrier.		
	–55 dBc (–60 dBc typical) for side bands \geq 25 kHz offset from the carrier		
Residual spurious response	< –78 dBm		
	< -67 dBm at 2.5 GHz		
	< -76 dBm at 1.25 GHz		
	≤ –15 dBm reference level and RF input terminated with 50 Ω		

Adjacent channel power ratio dynamic range, typical	–58 dBc			
Frequency measurement resolution	1 Hz			
Span	Span adjustable in 1-2-5	sequence		
	Variable Resolution = 1%	of the next span setting		
Level display range	Log Scale and Units: dB	n, dBmV, dBµV, dBµW, dBn	nA, dBµA	
	Measurement Points: 1,0	000		
	Marker Level Readout R	esolution: Log Scale: 0.1 dB	}	
	Maximum Number of RF	Traces: 4		
	Trace Functions: Maximu Slice (Uses normal trace	ım Hold; Average; Minimum)	Hold; Normal; Spectrogram	
	Detectors: Positive-Peak	, negative-peak, sample, ave	erage	
Reference level	Setting Range: -130 dBi	n to +20 dBm, in steps of 5 o	dBm	
	Default Setting: 0 dBm ref level			
Vertical position	–100 divs to +100 divs (displayed in dB)			
Maximum operating input level	Average Continuous Power: +20 dBm (0.1 W)			
	DC maximum before damage: ±40 V _{dc}			
	Max "No damage" 33 dBm (2 W) CW			
	Peak Pulse Power: +45 dBm (32 W)			
	Peak Pulse Power defined as <10 μ s pulse width, <1% duty cycle, and reference level of \geq +10 dBm.			
Resolution bandwidth (RBW) accuracy	Max RBW % Error = (0.5/(25 x WF)) * 100			
	"WF" represents the Window Factor and is set by the window method being used.			
	Method	WF	RBW error	
	Rectangular	0.89	2.25%	
	Hamming	1.30	1.54%	
	Hanning	1.44	1.39%	
	Blackman-Harris	1.90	1.05%	
	Kaiser	2.23	0.90%	
	Flat-Top	3.77	0.53%	
Level measurement uncertainty	< ±1.2 dB, < ±0.6 dB (ty	pical), 18 °C - 28 °C tempera	ature range	
	$< \pm 2.0 \text{ dB}, -10 \text{ °C to 55 °C}$			
	Specification applies to when the signal-to-noise ratio > 40 dB.			
Occupied bandwidth accuracy, typical	± Span/750			
	•			

Table 14: RF input specifications (cont.)

Arbitrary Function Generator Features

Table 15: AFG Features

Characteristic	Description					
Function types		Arbitrary, Sine, Square, Pulse, Ramp, Triangle, DC Level, Gaussian, Lorentz, Exponential Rise/Fall, Sine(x)/x, Random Noise, Haversine, Cardiac				
Amplitude range	Values are peak-to-peak voltages					
	Waveform	50 Ω	1 ΜΩ			
	Arbitrary	10 mV to 2.5 V	20 mV to 5 V			
	Sine	10 mV to 2.5 V	20 mV to 5 V			
	Square	10 mV to 2.5 V	20 mV to 5 V			
	Pulse	10 mV to 2.5 V	20 mV to 5 V			
	Ramp	10 mV to 2.5 V	20 mV to 5 V			
	Triangle	10 mV to 2.5 V	20 mV to 5 V			
	Gaussian	10 mV to 1.25 V	20 mV to 2.5 V			
	Lorentz	10 mV to 1.2 V	20 mV to 2.4 V			
	Exponential rise	10 mV to 1.25 V	20 mV to 2.5 V			
	Exponential fall	10 mV to 1.25 V	20 mV to 2.5 V			
	Sine(x)/x	10 mV to 1.5 V	20 mV to 3.0 V			
	Random noise	10 mV to 2.5 V	20 mV to 5 V			
	Haversine	10 mV to 1.25 V	20 mV to 2.5 V			
	Cardiac	10 mV to 2.5 V	20 mV to 5 V			
Maximum sample rate	250 MS/s					
Arbitrary function record length	128k samples					

Arbitrary Function Generator Characteristics

Table 16: AFG Characteristics

Characteristic	Description		
Sine waveform	Frequency range: 0.1 Hz to 50 MHz		
	Frequency setting resolution: 0.1 Hz		
	Amplitude flatness (typical):		
	± 0.5 dB at 1 kHz ± 1.5 dB for <20 mV _{pp} amplitudes		
	Total harmonic distortion (typical): 1% at 50 Ω		
	Spurious free dynamic range (typical): -40 dB ($V_{pp} \ge 0.1 \text{ V}$); 30 dB ($V_{pp} < 0.1 \text{ V}$), 50 Ω load		
Square/pulse waveform	Frequency range: 0.1 Hz to 25 MHz		
	Frequency setting resolution: 0.1 Hz		
	Duty cycle range: 10% - 90% or 10 ns minimum pulse, whichever is larger		
	Duty cycle resolution: 0.1%		
	Minimum pulse width (typical): 10 ns		
	Rise/fall time (typical): 5 ns, 10% to 90%		
	Pulse width resolution: 100 ps		
	Overshoot (typical): <2% for signal steps greater than 100 mV		
	Asymmetry (typical): ±1% ±5 ns, at 50% duty cycle		
Ramp/Triangle waveform	Frequency range: 0.1 Hz to 500 kHz		
	Frequency setting resolution: 0.1 Hz		
	Variable symmetry: 0% to 100%		
	Symmetry resolution: 0.1%		
	DC level range (typical): ± 2.5 V in to Hi-Z; ± 1.25 V into 50 Ω		
	Gaussian Pulse, Lorentz Pulse, Haversine Maximum Frequency (typical): 5 MHz		
	Exponential rise/fall maximum frequency (typical): 5 MHz		
	Sine(x)/x maximum frequency (typical): 2 MHz		
Random noise waveform	Amplitude range: 20 mV_{pp} to 5 V_{pp} in to Hi-Z; 10 mV_{pp} to 2.5 V_{pp} into 50 Ω		
Sine and ramp frequency accuracy	130 ppm (frequency ≤10 kHz); 50 ppm (frequency > 10 kHz)		
Square and pulse frequency accuracy	130 ppm (frequency ≤10 kHz); 50 ppm (frequency > 10 kHz)		
Signal amplitude resolution	500 μV (50 Ω)		
	1 mV (HiZ)		
V Signal amplitude accuracy	±[(1.5% of peak-to-peak amplitude setting) + (1.5% of DC offset setting) + 1 mV] (frequency = 1 kHz)		

DC offset range	±2.5 V into Hi-Z ±1.25 V into 50 Ω
	±1.20 V III(0 00 12
DC offset resolution	500 μV (50 Ω)
	1 mV (HiZ)
✓ DC offset accuracy	±[(1.5% of offset setting) + 1 mV]
	Add 3 mV of uncertainty per 10 °C change from 25 °C ambient

Table 16: AFG Characteristics (cont.)

Digital Voltmeter/Counter

Table 17: Digital voltmeter/counter

Characteristic	Description
Measurement types	AC+DC _{rms} , DC _{rms} , AC _{rms} , frequency count
Voltage resolution	4 digits
Voltage accuracy	DC: ±(2 mV + [(((4 * (Vertical Scale Voltage)) / (Absolute Input Voltage)) + 1)% of Absolute Input Voltage] + (0.5% of Absolute Offset Voltage))
	DC example: an input channel set up with +2 V offset and 1 V/div measuring a -5 V signal would have ±(2 mV + [(((4 * 1) / 5) + 1)% of 5 V] + [0.5% of 2 V]) = ±(2 mV + [1.8% of 5 V] + [0.5% of 2 V]) = ±(2 mV + 90 mV + 10 mV) = ±102 mV. This is roughly ±2% of the input voltage.
	AC: ±2% (40 Hz to 1 kHz)
	AC (typical): ±2% (20 Hz to 10 kHz)
	For AC measurements, the input channel vertical settings must allow the V_{pp} input signal to cover between 4 and 8 divisions.
Frequency resolution	5 digits
Frequency accuracy	±(10 µHz/Hz + 1 count)
Frequency counter source	Any analog input channel.
Frequency counter maximum input	100 MHz for 100 MHz models
frequency	150 MHz for all other models
	Trigger Sensitivity limits must be observed for reliable frequency measurements.

Performance Verification

This chapter contains performance verification procedures for the specifications marked with the ν symbol. The following equipment, or a suitable equivalent, is required to complete these procedures.

Table 18: Required equipment

Description	Minimum requirements	Examples
DC voltage source	3 mV to 100 V, ±0.1% accuracy	Fluke 9500B Oscilloscope Calibrator
Leveled sine wave generator	9 kHz to 3,000 MHz, ±4% amplitude accuracy	with a 9530 Output Module An appropriate BNC-to-0.1 inch pin
Time mark generator	80 ms period, ±1 ppm accuracy, rise time < 50 ns	adapter between the Fluke 9530 and P6316 probe
50 Ω BNC cable	Male-to-male connectors	Tektronix part number 012-0057-01 (43 inch)
BNC feed-through termination	50 Ω	Tektronix part number 011-0049-02
RF signal generator	9 kHz to 3 GHz, -20 dBm to + 10 dBm	Anritsu MG3690C series with options 2, 3, 4, 15, 22
Power meter	Use with Power sensor	Rhode & Schwarz NRX
Power sensor	-30 dBm to +10 dBm	Rhode & Schwarz NRP-Z98
Frequency counter	0.1 Hz to 50 MHz, 5 ppm accuracy	Tektronix FCA3000
DMM	DC Voltage: 0.1% accuracy AC RMS Voltage: 0.2% accuracy	Tektronix DMM4040

You may need additional cables and adapters, depending on the actual test equipment you use.

These procedures cover all MDO3000 models. Please disregard any checks that do not apply to the specific model you are testing.

Print the test record on the following pages and use it to record the performance test results for your oscilloscope.

NOTE. Completion of the performance verification procedure does not update the stored time and date of the latest successful adjustment. The date and time are updated only when the adjustment procedures in the service manual are successfully completed.

The performance verification procedures verify the performance of your instrument. They do not adjust your instrument. If your instrument fails any of the performance verification tests, you should perform the factory adjustment procedures as described in the *MDO3000 Series Service Manual*.

Upgrade the Firmware

For the best functionality, you can upgrade the oscilloscope firmware. To upgrade the firmware, follow these steps:

- 1. Open a Web browser and go to www.tektronix.com/software/downloads to locate the most recent firmware upgrade.
- 2. Download the latest firmware for your oscilloscope onto your PC.
- 3. Unzip the files and copy the "firmware.img" file into the root folder of a USB flash drive.
- 4. Power off your oscilloscope.
- 5. Insert the USB flash drive into a USB Host port on the front or back of the oscilloscope.
- 6. Power on the oscilloscope. The oscilloscope automatically recognizes the replacement firmware and installs it.

If the instrument does not install the firmware, rerun the procedure. If the problem continues, contact qualified service personnel.

NOTE. Do not power off the oscilloscope or remove the USB flash drive until the oscilloscope finishes installing the firmware.

- 7. Power off the oscilloscope and remove the USB flash drive.
- 8. Power on the oscilloscope.
- 9. Push the Utility button on the front-panel.
- 10. Push Utility Page on the lower menu.
- 11. Turn Multipurpose knob "a" and select Config.
- 12. Push About on the lower menu. The oscilloscope displays the firmware version number.
- 13. Confirm that the version number matches that of the new firmware.

The oscilloscope displays a message when the installation is complete.

Test Record

Print this section for use during the Performance Verification.

Model number	Serial number	Procedure performed by	Date

Test	Passed	Failed
Self Test		

Input Termination Tests

Performance				
checks	Vertical scale	Low limit	Test result	High limit
Channel 1				
Channel 1 Input	10 mV/div	990 kΩ		1.01 MΩ
mpedance, 1 MΩ	100 mV/div	990 kΩ		1.01 MΩ
	1 V/div	990 kΩ		1.01 MΩ
Channel 1 Input	10 mV/div	49.5 Ω		50.5 Ω
Impedance, 50 Ω	100 mV/div	49.5 Ω		50.5 Ω
Channel 1 Input	10 mV/div	74.25 Ω		75.75 Ω
mpedance, 75 Ω	100 mV/div	74.25 Ω		75.75 Ω
NOTE. This setting s not available on MDO310X models.				
Channel 2				
Channel 2 Input	10 mV/div	990 kΩ		1.01 MΩ
mpedance, 1 MΩ	100 mV/div	990 kΩ		1.01 MΩ
	1 V/div	990 kΩ		1.01 MΩ
Channel 2 Input Impedance, 50 Ω	10 mV/div	49.5 Ω		50.5 Ω
	100 mV/div	49.5 Ω		50.5 Ω
Channel 2 Input	10 mV/div	74.25 Ω		75.75 Ω
mpedance, 75 Ω	100 mV/div	74.25 Ω		75.75 Ω
NOTE. This setting s not available on MDO310X models.				
Channel 3 ¹				
Channel 3 Input	10 mV/div	990 kΩ		1.01 MΩ
mpedance, 1 MΩ	100 mV/div	990 kΩ		1.01 MΩ
	1 V/div	990 kΩ		1.01 MΩ
Channel 3 Input	10 mV/div	49.5 Ω		50.5 Ω
mpedance, 50 Ω	100 mV/div	49.5 Ω		50.5 Ω
Channel 3 Input	10 mV/div	74.25 Ω		75.75 Ω
mpedance, 75 Ω	100 mV/div	74.25 Ω		75.75 Ω
NOTE . This setting is not available on MDO310X models.				
Channel 4 ¹				
Channel 4 Input	10 mV/div	990 kΩ		1.01 MΩ
mpedance, 1 MΩ	100 mV/div	990 kΩ		1.01 MΩ
	1 V/div	990 kΩ		1.01 MΩ

Performance checks	Vertical scale	Low limit	Test result	High limit
Channel 4, Input Impedance, 50 Ω	10 mV/div	49.5 Ω		50.5 Ω
	100 mV/div	49.5 Ω		50.5 Ω
Channel 4, Input Impedance, 75 Ω	10 mV/div	74.25 Ω		75.75 Ω
	100 mV/div	74.25 Ω		75.75 Ω
IOTE. This setting s not available on IDO310X models.				

¹ Channels 3 and 4 are only on four-channel oscilloscopes.

DC Balance Tests

Table 19: DC Balance

Performance checks	Vertical scale	Low limit (div)	Test result	High limit (div)
Channel 1				
Channel 1 DC Balance,	1 mV/div	-0.500		0.500
50 Ω, 20 MHz BW	2 mV/div	-0.250		0.250
	10 mV/div	-0.200		0.200
	100 mV/div	-0.200		0.200
	1 V/div	-0.200		0.200
Channel 1 DC Balance,	1 mV/div	-0.500		0.500
75 Ω, 20 MHz BW	2 mV/div	-0.250		0.250
	10 mV/div	-0.200		0.200
	100 mV/div	-0.200		0.200
	1 V/div	-0.200		0.200
hannel 1 DC Balance,	1 mV/div	-0.300		0.300
$M\Omega$, 20 MHz BW	2 mV/div	-0.200		0.200
	10 mV/div	-0.200		0.200
	100 mV/div	-0.200		0.200
	1 V/div	-0.200		0.200
hannel 1 DC Balance,	1 mV/div	-0.500		0.500
0 Ω, 250 MHz BW	2 mV/div	-0.250		0.250
	10 mV/div	-0.200		0.200
	100 mV/div	-0.200		0.200
	1 V/div	-0.200		0.200
hannel 1 DC Balance,	1 mV/div	-0.500		0.500
5 Ω, 250 MHz BW	2 mV/div	-0.250		0.250
	10 mV/div	-0.200		0.200
	100 mV/div	-0.200		0.200
	1 V/div	-0.200		0.200
hannel 1 DC Balance,	1 mV/div	-0.300		0.300
MΩ, 250 MHz BW	2 mV/div	-0.200		0.200
	10 mV/div	-0.200		0.200
	100 mV/div	-0.200		0.200
	1 V/div	-0.200		0.200

Performance checks	Vertical scale	Low limit (div)	Test result	High limit (div)
Channel 1 DC Balance,	1 mV/div	-0.500		0.500
50 Ω, Full BW	2 mV/div	-0.250		0.250
	10 mV/div	-0.200		0.200
	100 mV/div	-0.200		0.200
	1 V/div	-0.200		0.200
Channel 1 DC Balance,	1 mV/div	-0.5 mV		0.5 mV
75 Ω, Full BW	2 mV/div	-0.500		0.500
	10 mV/div	-0.250		250
	100 mV/div	-0.200		0.200
	1 V/div	-0.200		0.200
Channel 1 DC Balance,	1 mV/div	-0.300		0.300
1 MΩ, Full BW	2 mV/div	-0.200		0.200
	10 mV/div	-0.200		0.200
	100 mV/div	-0.200		0.200
	1 V/div	-0.200		0.200
Channel 2				
Channel 2 DC Balance,	1 mV/div	-0.500		0.500
50 Ω, 20 MHz BW	2 mV/div	-0.250		0.250
	10 mV/div	-0.200		0.200
	100 mV/div	-0.200		0.200
	1 V/div	-0.200		0.200
Channel 2 DC Balance,	1 mV/div	-0.500		0.500
75 Ω, 20 MHz BW	2 mV/div	-0.250		0.250
	10 mV/div	-0.200		0.200
	100 mV/div	-0.200		0.200
	1 V/div	-0.200		0.200
Channel 2 DC Balance,	1 mV/div	-0.300		0.300
1 MΩ, 20 MHz BW	2 mV/div	-0.200		0.200
	10 mV/div	-0.200		0.200
	100 mV/div	-0.200		0.200
	1 V/div	-0.200		0.200

Performance checks	Vertical scale	Low limit (div)	Test result	High limit (div)
Channel 2 DC Balance,	1 mV/div	-0.500		0.500
50 Ω, 250 MHz BW	2 mV/div	-0.250		0.250
	10 mV/div	-0.200		0.200
	100 mV/div	-0.200		0.200
	1 V/div	-0.200		0.200
Channel 2 DC Balance,	1 mV/div	-0.500		0.500
75 Ω, 250 MHz BW	2 mV/div	-0.250		0.250
	10 mV/div	-0.200		0.200
	100 mV/div	-0.200		0.200
	1 V/div	-0.200		0.200
Channel 2 DC Balance	1 mV/div	-0.300		0.300
1 MΩ, 250 MHz BW	2 mV/div	-0.2000		0.200
	10 mV/div	-0.200		0.200
	100 mV/div	-0.200		0.200
	1 V/div	-0.200		0.200
Channel 2 DC Balance,	1 mV/div	-0.500		0.500
50 Ω, Full BW	2 mV/div	-0.250		0.250
	10 mV/div	-0.200		0.200
	100 mV/div	-0.200		0.200
	1 V/div	-0.200		0.200
Channel 2 DC Balance,	1 mV/div	-0.500		0.500
′5 Ω, Full BW	2 mV/div	-0.250		0.250
	10 mV/div	-0.200		0.200
	100 mV/div	-0.200		0.200
	1 V/div	0.200		0.200
Channel 2 DC Balance,	1 mV/div	-0.300		0.300
MΩ, Full BW	2 mV/div	-0.200		0.200
	10 mV/div	-0.200		0.200
	100 mV/div	-0.200		0.200
	1 V/div	-0.200		0.200

Performance checks	Vertical scale	Low limit (div)	Test result	High limit (div)
Channel 3 ¹				
Channel 3 DC Balance,	1 mV/div	-0.500		0.500
50 Ω, 20 MHz BW	2 mV/div	-0.250		0.250
	10 mV/div	-0.200		0.200
	100 mV/div	-0.200		0.200
	1 V/div	-0.200		0.200
Channel 3 DC Balance,	1 mV/div	-0.500		0.500
75 Ω, 20 MHz BW	2 mV/div	-0.250		0.250
	10 mV/div	-0.200		0.200
	100 mV/div	-0.200		0.200
	1 V/div	-0200		0.200
Channel 3 DC Balance,	1 mV/div	-0.300		0.300
1 MΩ, 20 MHz BW	2 mV/div	-0.200		0.200
	10 mV/div	-0.200		0.200
	100 mV/div	-0.200		0.200
	1 V/div	-0.200		0.200
Channel 3 DC Balance,	1 mV/div	-0.500		0.500
50 Ω, 250 MHz BW	2 mV/div	-0.250		0.250
	10 mV/div	-0.200		0.200
	100 mV/div	-0.200		0.200
	1 V/div	-0.200		0.200
Channel 3 DC Balance,	1 mV/div	-0.500		0.500
75 Ω, 250 MHz BW	2 mV/div	-0.250		0.250
	10 mV/div	-0.200		0.200
	100 mV/div	-0.200		0.200
	1 V/div	-0.200		0.200
Channel 3 DC Balance,	1 mV/div	-0.300		0.300
1 MΩ, 250 MHz BW	2 mV/div	-0.200		0.200
	10 mV/div	-0.200		0.200
	100 mV/div	-0.200		0.200
	1 V/div	-0.200		0.200

Performance checks	Vertical scale	Low limit (div)	Test result	High limit (div)
Channel 3 DC Balance,	1 mV/div	-0.500		0.500
50 Ω, Full BW	2 mV/div	-0.250		0.250
	10 mV/div	-0.200		0.200
	100 mV/div	-0.200		0.200
	1 V/div	-0.200		0.200
Channel 3 DC Balance,	1 mV/div	-0.500		0.500
5 Ω, Full BW	2 mV/div	-0.250		0.250
	10 mV/div	-0.200		0.200
	100 mV/div	-0.200		0.200
	1 V/div	-0.200		0.200
Channel 3 DC Balance,	1 mV/div	-0.300		0.300
MΩ, Full BW	2 mV/div	-0.200		0.200
	10 mV/div	-0.200		0.200
	100 mV/div	-0.200		0.200
	1 V/div	-0.200		0.200
Channel 4 ¹				
Channel 4 DC Balance,	1 mV/div	-0.500		0.500
0 Ω, 20 MHz BW	2 mV/div	-0.250		0.250
	10 mV/div	-0.200		0.200
	100 mV/div	-0.200		0.200
	1 V/div	-0.200		0.200
hannel 4 DC Balance,	1 mV/div	-0.500		0.500
5 Ω, 20 MHz BW	2 mV/div	-0.250		0.250
	10 mV/div	-0.200		0.200
	100 mV/div	-0.200		0.200
	1 V/div	-0.200		0.200
nannel 4 DC Balance,	1 mV/div	-0.300		0.300
MΩ, 20 MHz BW	2 mV/div	-0.200		0.200
	10 mV/div	-0.200		0.200
	100 mV/div	-0.200		0.200
	1 V/div	-0.200		0.200

Performance checks	Vertical scale	Low limit (div)	Test result	High limit (div)
Channel 4 DC Balance,	1 mV/div	-0.500		0.500
50 Ω, 250 MHz BW	2 mV/div	-0.250		0.250
	10 mV/div	-0.200		0.200
	100 mV/div	-0.200		0.200
	1 V/div	-0.200		0.200
Channel 4 DC Balance,	1 mV/div	-0.500		0.500
75 Ω, 250 MHz BW	2 mV/div	-0.250		0.250
	10 mV/div	-0.200		0.200
	100 mV/div	-0.200		0.200
	1 V/div	-0.200		0.200
Channel 4 DC Balance,	1 mV/div	-0.300		0.300
1 MΩ, 250 MHz BW	2 mV/div	-0.2000		0.200
	10 mV/div	-0.200		0.200
	100 mV/div	-0.200		0.200
	1 V/div	-0.200		0.200
Channel 4 DC Balance,	1 mV/div	-0.500		0.500
50 Ω, Full BW	2 mV/div	-0.250		0.250
	10 mV/div	-0.200		0.200
	100 mV/div	-0.200		0.200
	1 V/div	-0.200		0.200
Channel 4 DC Balance,	1 mV/div	-0.500		0.500
′5 Ω, Full BW	2 mV/div	-0.250		0.250
	10 mV/div	-0.200		0.200
	100 mV/div	-0.200		0.200
	1 V/div	-0.200		0.200
Channel 4 DC Balance,	1 mV/div	-0.300		0.300
MΩ, Full BW	2 mV/div	-0.200		0.200
	10 mV/div	-0.200		0.200
	100 mV/div	-0.200		0.200
	1 V/div	-0.200		0.200

Table 19: DC Balance (cont.)

1 Channels 3 and 4 are only on four-channel oscilloscopes.

Analog Bandwidth Tests, 50 $\boldsymbol{\Omega}$

Table 20: Bandwidth

Bandwidth at Channel	Termination	Vertical scale	V _{in- pp}	V _{bw-pp}	Limit	Test result Gain = V _{bw-pp} /V _{in-pp}
1	50 Ω	10 mV/div			≥ 0.707	
	50 Ω	5 mV/div			≥ 0.707	
	50 Ω	2 mV/div			≥ 0.707	
	50 Ω	1 mV/div			≥ 0.707	
2	50 Ω	10 mV/div			≥ 0.707	
	50 Ω	5 mV/div			≥ 0.707	
	50 Ω	2 mV/div			≥ 0.707	
	50 Ω	1 mV/div			≥ 0.707	
31	50 Ω	10 mV/div			≥ 0.707	
	50 Ω	5 mV/div			≥ 0.707	
	50 Ω	2 mV/div			≥ 0.707	
	50 Ω	1 mV/div			≥ 0.707	
4 ¹	50 Ω	10 mV/div			≥ 0.707	
	50 Ω	5 mV/div			≥ 0.707	
	50 Ω	2 mV/div			≥ 0.707	
	50 Ω	1 mV/div			≥ 0.707	

1 Channels 3 and 4 are only on four-channel oscilloscopes

DC Gain Accuracy Tests

Table	21:	DC	Gain	Accuracy
-------	-----	----	------	----------

Performance checks	Vertical scale	Low limit	Test result	High limit
Channel 1	1 mV/div	-2.5%		2.5%
0 V offset, 0 V vertical position,	2 mV/div	-2.0%		2.0%
20 MHz BW, 1 M Ω	4.98 mV/div	-3.0%		3.0%
	5 mV/div	-1.5%		1.5%
	10 mV/div	-1.5%		1.5%
	20 mV/div	-1.5%		1.5%
	49.8 mV	-3.0%		3.0%
	50 mV/div	-1.5%		1.5%
	100 mV/div	-1.5%		1.5%
	200 mV/div	-1.5%		1.5%
	500 mV/div	-1.5%		1.5%
	1 V/div	-1.5%		1.5%
Channel 2	1 mV/div	-2.5%		2.5%
0 V offset, 0 V vertical position,	2 mV/div	-2.0%		2.0%
20 MHz BW, 1 M Ω	4.98 mV/div	-3.0%		3.0%
	5 mV/div	-1.5%		1.5%
	10 mV/div	-1.5%		1.5%
	20 mV/div	-1.5%		1.5%
	49.8 mV	-3.0%		3.0%
	50 mV/div	-1.5%		1.5%
	100 mV/div	-1.5%		1.5%
	200 mV/div	-1.5%		1.5%
	500 mV/div	-1.5%		1.5%
	1 V/div	-1.5%		1.5%

Performance checks	Vertical scale	Low limit	Test result	High limit
Channel 3 ¹	1 mV/div	-2.5%		2.5%
0 V offset, 0 V vertical position,	2 mV/div	-2.0%		2.0%
20 MHz BW, 1 MΩ	4.98 mV/div	-3.0%		3.0%
	5 mV/div	-1.5%		1.5%
	10 mV/div	-1.5%		1.5%
	20 mV/div	-1.5%		1.5%
	49.8 mV	-3.0%		3.0%
	50 mV/div	-1.5%		1.5%
	100 mV/div	-1.5%		1.5%
	200 mV/div	-1.5%		1.5%
	500 mV/div	-1.5%		1.5%
	1 V/div	-1.5%		1.5%
Channel 4 ¹	1 mV/div	-2.5%		2.5%
0 V offset, 0 V vertical position,	2 mV/div	-2.0%		2.0%
$20 \text{ MHz BW}, 1 \text{ M}\Omega$	4.98 mV/div	-3.0%		3.0%
	5 mV/div	-1.5%		1.5%
	10 mV/div	-1.5%		1.5%
	20 mV/div	-1.5%		1.5%
	49.8 mV	-3.0%		3.0%
	50 mV/div	-1.5%		1.5%
	100 mV/div	-1.5%		1.5%
	200 mV/div	-1.5%		1.5%
	500 mV/div	-1.5%		1.5%
	1 V/div	-1.5%		1.5%

Table 21: DC Gain Accuracy (cont.)

1 Channels 3 and 4 are only on four-channel oscilloscopes.

DC Offset Accuracy Tests

Table	22:	DC	Offset	Accuracy
-------	-----	----	--------	----------

Performance checks	Vertical scale	Vertical offset ¹	Low limit	Test result	High limit
All models					
Channel 1	1 mV/div	700 mV	696.2 mV		703.8 mV
20 MHz BW, 1 MΩ	1 mV/div	–700 mV	–703.8 mV		–696.2 mV
	2 mV/div	700 m	696.1 mV		703.9 mV
	2 mV/div	–700 mV	–703.9 mV		–696.1 mV
	10 mV/div	1 V	993 mV		1007 mV
	10 mV/div	–1 V	–1007 mV		–993 mV
	100 mV/div	10.0 V	9.930 V		10.07 V
	100 mV/div	–10.0 V	–10.07 V		-9.930 V
	1 V/div	100 V	99.30 V		100.7 V
	1 V/div	-100 V	–100.7 V		-99.30 V
	1.01 V/div	100 V	99.30 V		100.7 V
	1.01 V/div	-100 V	–100.7 V		-99.30 V
Channel 2	1 mV/div	700 mV	696.2 mV		703.8 mV
20 MHz BW, 1 MΩ	1 mV/div	–700 mV	-703.8 mV		-696.2 mV
	2 mV/div	700 mV	696.1 mV		703.9 mV
	2 mV/div	–700 mV	–703.9 mV		–696.1 mV
	10 mV/div	1 V	993 mV		1007 mV
	10 mV/div	-1 V	–1007 mV		–993 mV
	100 mV/div	10.0 V	9.930 V		10.07 V
	100 mV/div	–10.0 V	–10.07 V		–9.930 V
	1 V/div	100 V	99.30 V		100.7 V
	1 V/div	-100 V	–100.7 V		-99.30 V
	1.01 V/div	100 V	99.30 V		100.7 V
	1.01 V/div	-100 V	–100.7 V		-99.30 V

Performance checks	Vertical scale	Vertical offset ¹	Low limit	Test result	High limit
				Test Tesuit	
Channel 3 ² 20 MHz BW, 1 MΩ	1 mV/div	700 mV	696.2 mV		703.8 mV
,	1 mV/div	–700 mV	-703.8 mV		–696.2 mV
	2 mV/div	700 mV	696.1 mV		703.9 mV
	2 mV/div	–700 mV	–703.9 mV		-696.1 mV
	10 mV/div	1 V	993 mV		1007 mV
	10 mV/div	–1 V	–1007 mV		–993 mV
	100 mV/div	10.0 V	9.930 V		10.07 V
	100 mV/div	–10.0 V	–10.07 V		–9.930 V
	1 V/div	100 V	99.30 V		100.7 V
	1 V/div	–100 V	–100.7 V		–99.30 V
	1.01 V/div	100 V	99.30 V		100.7 V
	1.01 V/div	–100 V	–100.7 V		–99.30 V
Channel 4 ²	1 mV/div	700 mV	696.2 mV		703.8 mV
20 MHz BW, 1 MΩ	1 mV/div	–700 mV	–703.8 mV		–696.2 mV
	2 mV/div	700 mV	696.1 mV		703.9 mV
	2 mV/div	–700 mV	–703.9 mV		-696.1 mV
	10 mV/div	1 V	993 mV		1007 mV
	10 mV/div	–1 V	–1007 mV		–993 mV
	100 mV/div	10.0 V	9.930 V		10.07 V
	100 mV/div	–10.0 V	–10.07 V		–9.930 V
	1 V/div	100 V	99.30 V		100.7 V
	1 V/div	–100 V	–100.7 V		–99.30 V
	1.01 V/div	100 V	99.30 V		100.7 V
	1.01 V/div	–100 V	–100.7 V		-99.30 V

Table 22: DC Offset Accuracy (cont.)

1 Use this value for both the calibrator output and the oscilloscope offset setting.

² Channels 3 and 4 are only on four-channel oscilloscopes.

Sample Rate and Delay Time Accuracy

Table 23: Sample Rate and Delay Time Accuracy

Performance checks	Low limit	Test result	High limit
Sample Rate and Delay Time Accuracy	-2 division		+2 division

Random Noise, Sample Acquisition Mode Tests

Random Noise, Sampl	e Acquisition Mode	Bandwidth Selection	Test result	High limit
For instruments with	Channel 1	Full		4.50 mV
1 GHz bandwidth (includes MDO310X		250 MHz		4.15 mV
models as well as		20 MHz	-	4.10 mV
MDO305X/303X/302 X/301X models with	Channel 2	Full		4.50 mV
1 GHz upgrade)		250 MHz	-	4.15 mV
		20 MHz	-	4.10 mV
	Channel 3 ¹	Full		4.50 mV
		250 MHz		4.15 mV
		20 MHz		4.10 mV
	Channel 4 ¹	Full		4.50 mV
		250 MHz		4.15 mV
		20 MHz		4.10 mV
For instruments with	Channel 1	Full		4.15 mV
500 MHz bandwidth (includes MDO305X		250 MHz		4.15 mV
models as well as		20 MHz		4.10 mV
MDO303X/302X/301X models with 500 MHz	Channel 2	Full		4.15 mV
upgrade)		250 MHz		4.15 mV
		20 MHz		4.10 mV
	Channel 3 ¹	Full		4.15 mV
		250 MHz		4.15 mV
		20 MHz		4.10 mV
	Channel 4 ¹	Full		4.15 mV
		250 MHz		4.15 mV
		20 MHz		4.10 mV

Table 24: Random Noise, Sample Acquisition Mode

Random Noise, Sampl	e Acquisition Mode	Bandwidth Selection	Test result	High limit
For instruments with	Channel 1	Full		4.15 mV
350 MHz bandwidth (includes MDO303X models as well as		250 MHz		4.15 mV
		20 MHz		4.10 mV
MDO302X/301X models with 350 MHz	Channel 2	Full		4.15 mV
upgrade)		250 MHz		4.15 mV
		20 MHz		4.10 mV
	Channel 3 ¹	Full		4.15 mV
		250 MHz		4.15 mV
		20 MHz		4.10 mV
	Channel 4 ¹	Full		4.15 mV
		250 MHz		4.15 mV
		20 MHz		4.10 mV
For instruments with	Channel 1	Full		4.15 mV
200 MHz bandwidth (MDO302X models		20 MHz		4.10 mV
as well as MDO301X	Channel 2	Full		4.15 mV
models with 200 MHz upgrade)		20 MHz		4.10 mV
	Channel 3	Full		4.15 mV
		20 MHz		4.10 mV
	Channel 4	Full		4.15 mV
		20 MHz		4.10 mV
For instruments with	Channel 1	Full		4.15 mV
100 MHz bandwidth (MDO301X models)		20 MHz		4.10 mV
(Channel 2	Full		4.15 mV
		20 MHz		4.10 mV
	Channel 3 ¹	Full		4.15 mV
		20 MHz		4.10 mV
	Channel 4 ¹	Full		4.15 mV
		20 MHz		4.10 mV

Table 24: Random Noise, Sample Acquisition Mode (cont.)

1 Channels 3 and 4 are only on four-channel oscilloscopes.

Delta Time Measurement Accuracy Tests (MDO301X and MDO302X models)

Table 25:	Delta	Time	Measurement	Accuracy
-----------	-------	------	-------------	----------

MDO V/Div	Source V _{pp}	Test Result	High Limit
100 mV	800 mV		232 ps
500 mV	4 V		232 ps
1 V	4 V		233 ps
MDO = 40 ns/Div,	Source frequency = 24	MHz	
MDO V/Div	Source V _{pp}	Test Result	High Limit
5 mV	40 mV		309 ps
100 mV	800 mV		273 ps
500 mV	4 V		270 ps
1 V	4 V		355 ps
MDO = 400 ns/Div	, Source frequency = 2.4	4 MHz	
MDO V/Div	Source V _{pp}	Test Result	High Limit
5 mV	40 mV		2.04 ns
100 mV	800 mV		1.43 ns
500 mV	4 V		1.38 ns
1 V	4 V		2.70 ns
MDO = 4 µs/Div, \$	Source frequency = 240	kHz	
MDO V/Div	Source V _{pp}	Test Result	High Limit
5 mV	40 mV		20.3 ns
100 mV	800 mV		14.1 ns
500 mV	4 V		13.6 ns
1 V	4 V		26.9 ns
MDO = 40 µs/Div,	Source frequency = 24	kHz	
MDO V/Div	Source V _{pp}	Test Result	High Limit
5 mV	40 mV		203 ns
100 mV	800 mV		141 ns
500 mV	4 V		136 ns
1 V	4 V		269 ns
MDO = 400 µs/Div	v, Source frequency = 2.4	4 kHz	
MDO V/Div	Source V _{pp}	Test Result	High Limit

Channel 1

Table 25: Delta Time Measurement Accuracy (cont.)

Channel 2

100 mV	800 mV		1.41 µs
500 mV	4 V		1.36 µs
1 V	4 V		2.69 µs
MDO = 4 ns/Div, S	Source frequency = 240 I	/Hz (does not apply to 1	00 and 200 MHz models
MDO V/Div	Source V _{pp}	Test Result	High Limit
100 mV	800 mV		232 ps
500 mV	4 V		232 ps
1 V	4 V		233 ps
MDO = 40 ns/Div,	Source frequency = 24	MHz	
MDO V/Div	Source V _{pp}	Test Result	High Limit
5 mV	40 mV		309 ps
100 mV	800 mV		273 ps
500 mV	4 V		270 ps
1 V	4 V		355 ps
MDO = 400 ns/Div	v, Source frequency = 2.	4 MHz	
MDO V/Div	Source V _{pp}	Test Result	High Limit
5 mV	40 mV		2.04 ns
100 mV	800 mV		1.43 ns
500 mV	4 V		1.38 ns
1 V	4 V		2.70 ns
MDO = 4 µs/Div, S	Source frequency = 240	kHz	
MDO V/Div	Source V _{pp}	Test Result	High Limit
5 mV	40 mV		20.3 ns
100 mV	800 mV		14.1 ns
500 mV	4 V		13.6 ns
1 V	4 V		26.9 ns
MDO = 40 µs/Div,	Source frequency = 24	kHz	
MDO V/Div	Source V _{pp}	Test Result	High Limit
5 mV	40 mV		203 ns
100 mV	800 mV		141 ns
500 mV	4 V		136 ns
1 V	4 V		269 ns

Channel 3¹

Table 25: Delta Time Measurement Accuracy (cont.)

MDO V/Div	Source V _{pp}	Test Result	High Limit
5 mV	40 mV		2.03 µs
100 mV	800 mV		1.41 µs
500 mV	4 V		1.36 µs
1 V	4 V		2.69 µs
MDO = 4 ns/Div, S		MHz (does not apply to 1	
MDO V/Div	Source V _{pp}	Test Result	High Limit
100 mV	800 mV		232 ps
500 mV	4 V		232 ps
1 V	4 V		233 ps
MDO = 40 ns/Div	Source frequency = 24	MHz	
MDO V/Div	Source V _{pp}	Test Result	High Limit
5 mV	40 mV		309 ps
100 mV	800 mV		273 ps
500 mV	4 V		270 ps
1 V	4 V		355 ps
MDO = 400 ns/Di	v, Source frequency = 2.	4 MHz	
MDO V/Div	Source V _{pp}	Test Result	High Limit
5 mV	40 mV		2.04 ns
100 mV	800 mV		1.43 ns
500 mV	4 V		1.38 ns
1 V	4 V		2.70 ns
MDO = 4 µs/Div,	Source frequency = 240	kHz	
MDO V/Div	Source V _{pp}	Test Result	High Limit
5 mV	40 mV		20.3 ns
100 mV	800 mV		14.1 ns
500 mV	4 V		13.6 ns
1 V	4 V		26.9 ns
MDO = 40 µs/Div,	Source frequency = 24	kHz	I
MDO V/Div	Source V _{pp}	Test Result	High Limit
5 mV	40 mV		203 ns
100 mV	800 mV		141 ns
500 mV	4 V		136 ns

1 V	4 V		269 ns		
MDO = 400 µs/Div, Source frequency = 2.4 kHz					
MDO V/Div	Source V _{pp}	Test Result	High Limit		
5 mV	40 mV		2.03 µs		
100 mV	800 mV		1.41 µs		
500 mV	4 V		1.36 µs		
1 V	4 V		2.69 µs		

Channel 4¹

MDO = 4 ns/Div, S	Source frequency = 240 M	/Hz (does not apply to 1	00 and 200 MHz models)
MDO V/Div	Source V _{pp}	Test Result	High Limit
100 mV	800 mV		232 ps
500 mV	4 V		232 ps
1 V	4 V		233 ps
MDO = 40 ns/Div,	Source frequency = 24	MHz	
MDO V/Div	Source V _{pp}	Test Result	High Limit
5 mV	40 mV		309 ps
100 mV	800 mV		273 ps
500 mV	4 V		270 ps
1 V	4 V		355 ps
MDO = 400 ns/Div	v, Source frequency = 2.	4 MHz	
MDO V/Div	Source V _{pp}	Test Result	High Limit
5 mV	40 mV		2.04 ns
100 mV	800 mV		1.43 ns
500 mV	4 V		1.38 ns
1 V	4 V		2.70 ns
MDO = 4 µs/Div, §	Source frequency = 240	kHz	
MDO V/Div	Source V _{pp}	Test Result	High Limit
5 mV	40 mV		20.3 ns
100 mV	800 mV		14.1 ns
500 mV	4 V		13.6 ns
1 V	4 V		26.9 ns
MDO = 40 µs/Div,	Source frequency = 24	kHz	
MDO V/Div	Source V _{pp}	Test Result	High Limit
5 mV	40 mV		203 ns

Table 25: Delta Time Measurement Accuracy (cont.)

100 mV	800 mV		141 ns
500 mV	4 V		136 ns
1 V	4 V		269 ns
MDO = 400 µs/Div	/, Source frequency = 2.	4 kHz	
MDO V/Div	Source V _{pp}	Test Result	High Limit
	Source V _{pp}	Test Result	
5 mV	40 mV		2.03 µs
5 mV	40 mV		2.03 µs

¹ Channels 3 and 4 are only on four-channel oscilloscopes.

Delta Time Measurement Accuracy Tests (MDO303X and MDO305X models)

Table 26: Delta Time Measurement Accuracy

Channel 1

MDO V/Div	Source V _{pp}	Test Result	High Limit
100 mV	800 mV		232 ps
500 mV	4 V		232 ps
1 V	4 V		233 ps
MDO = 40 ns/Div	, Source frequency = 24	MHz	•
MDO V/Div	Source V _{pp}	Test Result	High Limit
5 mV	40 mV		336 ps
100 mV	800 mV		273 ps
500 mV	4 V		270 ps
1 V	4 V		355 ps
MDO = 400 ns/Di	v, Source frequency = 2.	4 MHz	
MDO V/Div	Source V _{pp}	Test Result	High Limit
5 mV	40 mV		2.44 ns
100 mV	800 mV		1.43 ns
500 mV	4 V		1.38 ns
1 V	4 V		2.70 ns

5 mV	40 mV		24.2 ns
100 mV	800 mV		14.1 ns
500 mV	4 V		13.6 ns
1 V	4 V		26.9 ns
MDO = 40 µs/Div,	Source frequency = 24	kHz	·
MDO V/Div	Source V _{pp}	Test Result	High Limit
5 mV	40 mV		242 ns
100 mV	800 mV		141 ns
500 mV	4 V		136 ns
1 V	4 V		269 ns
MDO = 400 µs/Div	v, Source frequency = 2.	4 kHz	
MDO V/Div	Source V _{pp}	Test Result	High Limit
5 mV	40 mV		2.42 µs
100 mV	800 mV		1.41 µs
500 mV	4 V		1.36 µs
1 V	4 V		2.69 µs

Channel 2

MDO = 4 ns/Div, S	Source frequency = 240 I	MHz (does not apply to 1	00 and 200 MHz models)
MDO V/Div	Source V _{pp}	Test Result	High Limit
100 mV	800 mV		232 ps
500 mV	4 V		232 ps
1 V	4 V		233 ps
MDO = 40 ns/Div,	Source frequency = 24	MHz	
MDO V/Div	Source V _{pp}	Test Result	High Limit
5 mV	40 mV		336 ps
100 mV	800 mV		273 ps
500 mV	4 V		270 ps
1 V	4 V		355 ps
MDO = 400 ns/Div	v, Source frequency = 2.	4 MHz	
MDO V/Div	Source V _{pp}	Test Result	High Limit
5 mV	40 mV		2.44 ns
100 mV	800 mV		1.43 ns
500 mV	4 V		1.38 ns
1 V	4 V		2.70 ns

MDO = 4 µs/Div,	Source frequency = 240	kHz	
MDO V/Div	Source V _{pp}	Test Result	High Limit
5 mV	40 mV		24.2 ns
100 mV	800 mV		14.1 ns
500 mV	4 V		13.6 ns
1 V	4 V		26.9 ns
MDO = 40 µs/Div,	Source frequency = 24	kHz	
MDO V/Div	Source V _{pp}	Test Result	High Limit
5 mV	40 mV		242 ns
100 mV	800 mV		141 ns
500 mV	4 V		136 ns
1 V	4 V		269 ns
MDO = 400 µs/Div	v, Source frequency = 2.	4 kHz	
MDO V/Div	Source V _{pp}	Test Result	High Limit
5 mV	40 mV		2.42 µs
100 mV	800 mV		1.41 µs
500 mV	4 V		1.36 µs
1 V	4 V		2.69 µs

Table 26: Delta Time Measurement Accuracy (cont.)

Channel 3¹

MDO = 4 ns/Div, Sour	ce frequency = 240 MHz (does not apply to 100 ar	id 200 MHz models)
MDO V/Div	Source V _{pp}	Test Result	High Limit
100 mV	800 mV		232 ps
500 mV	4 V		232 ps
1 V	4 V		233 ps
MDO = 40 ns/Div, Sou	rce frequency = 24 MHz		
MDO V/Div	Source V _{pp}	Test Result	High Limit
5 mV	40 mV		336 ps
100 mV	800 mV		273 ps
500 mV	4 V		270 ps
1 V	4 V		355 ps
MDO = 400 ns/Div, So	ource frequency = 2.4 MH	Z	
MDO V/Div	Source V _{pp}	Test Result	High Limit
5 mV	40 mV		2.44 ns
100 mV	800 mV		1.43 ns

500 mV	4 V		1.38 ns
1 V	4 V		2.70 ns
MDO = 4 µs/Div, S	Source frequency = 240	kHz	
MDO V/Div	Source V _{pp}	Test Result	High Limit
5 mV	40 mV		24.2 ns
100 mV	800 mV		14.1 ns
500 mV	4 V		13.6 ns
1 V	4 V		26.9 ns
MDO = 40 µs/Div,	Source frequency = 24	kHz	
MDO V/Div	Source V _{pp}	Test Result	High Limit
5 mV	40 mV		242 ns
100 mV	800 mV		141 ns
500 mV	4 V		136 ns
1 V	4 V		269 ns
MDO = 400 µs/Div	v, Source frequency = 2.4	4 kHz	
MDO V/Div	Source V _{pp}	Test Result	High Limit
5 mV	40 mV		2.42 µs
100 mV	800 mV		1.41 µs
500 mV	4 V		1.36 µs
1 V	4 V		2.69 µs

Channel 4¹

MDO = 4 ns/Div, Sourc	ns/Div, Source frequency = 240 MHz (does not apply to 100 and 200 MHz models)		
MDO V/Div	Source V _{pp}	Test Result	High Limit
100 mV	800 mV		232 ps
500 mV	4 V		232 ps
1 V	4 V		233 ps
MDO = 40 ns/Div, Sour	ce frequency = 24 MHz		
MDO V/Div	Source V _{pp}	Test Result	High Limit
5 mV	40 mV		336 ps
100 mV	800 mV		273 ps
500 mV	4 V		270 ps
1 V	4 V		355 ps
MDO = 400 ns/Div, Sou	irce frequency = 2.4 MH	2	
MDO V/Div	Source V _{pp}	Test Result	High Limit

Table 26:	Delta	Time	Measurement	Accuracy	(cont.)
-----------	-------	------	-------------	----------	---------

	-		
5 mV	40 mV		2.44 ns
100 mV	800 mV		1.43 ns
500 mV	4 V		1.38 ns
1 V	4 V		2.70 ns
MDO = 4 µs/Div, S	ource frequency = 240	kHz	
MDO V/Div	Source V _{pp}	Test Result	High Limit
5 mV	40 mV		24.2 ns
100 mV	800 mV		14.1 ns
500 mV	4 V		13.6 ns
1 V	4 V		26.9 ns
MDO = 40 µs/Div,	Source frequency = 24	kHz	
MDO V/Div	Source V _{pp}	Test Result	High Limit
5 mV	40 mV		242 ns
100 mV	800 mV		141 ns
500 mV	4 V		136 ns
1 V	4 V		269 ns
MDO = 400 µs/Div	, Source frequency = 2.4	4 kHz	
MDO V/Div	Source V _{pp}	Test Result	High Limit
5 mV	40 mV		2.42 µs
100 mV	800 mV		1.41 µs
500 mV	4 V		1.36 µs
1 V	4 V		2.69 µs
		•	

1 Channels 3 and 4 are only on four-channel oscilloscopes.

Delta Time Measurement Accuracy Tests (MDO310X models)

Table 27:	Delta	Time	Measurement Accuracy
-----------	-------	------	-----------------------------

Channel	1

MDO V/Div	Source V _{pp}	Test Result	High Limit
100 mV	800 mV		117 ps
500 mV	4 V		117 ps
1 V	4 V		119 ps

MDO V/Div	Source V _{pp}	Test Result	High Limit
5 mV	40 mV		386 ps
100 mV	800 mV		192 ps
500 mV	4 V		185 ps
1 V	4 V		293 ps
MDO = 400 ns/Di	v, Source frequency = 2.	4 MHz	
MDO V/Div	Source V _{pp}	Test Result	High Limit
5 mV	40 mV		3.69 ns
100 mV	800 mV		1.55 ns
500 mV	4 V		1.45 ns
1 V	4 V		2.70 ns
MDO = 4 µs/Div,	Source frequency = 240	kHz	1
MDO V/Div	Source V _{pp}	Test Result	High Limit
5 mV	40 mV		36.8 ns
100 mV	800 mV		15.3 ns
500 mV	4 V		14.3 ns
1 V	4 V		26.9 ns
MDO = 40 µs/Div	, Source frequency = 24	kHz	
MDO V/Div	Source V _{pp}	Test Result	High Limit
5 mV	40 mV		368 ns
100 mV	800 mV		153 ns
500 mV	4 V		143 ns
1 V	4 V		269 ns
MDO = 400 µs/Di	v, Source frequency = 2.	4 kHz	I
MDO V/Div	Source V _{pp}	Test Result	High Limit
5 mV	40 mV		3.68 µs
100	800 mV		1.53 µs
100 mV			
500 mV	4 V		1.43 µs

Table 27: Delta Time Measurement Accuracy (cont.)

MDO = 4 ns/Div, Source frequency = 240 MHz MDO V/Div Source V_{pp} Test Result High Limit 100 mV 800 mV 117 ps 117 ps 500 mV 4 V 117 ps 117 ps

Channel 2

T I I 07		
Table 27:	Delta Time	Measurement Accuracy (cont.)

1 V	4 V		119 ps
MDO = 40 ns/Div,	Source frequency = 24	MHz	
MDO V/Div	Source V_{pp}	Test Result	High Limit
5 mV	40 mV		386 ps
100 mV	800 mV		192 ps
500 mV	4 V		185 ps
1 V	4 V		293 ps
MDO = 400 ns/Di	v, Source frequency = 2.	4 MHz	
MDO V/Div	Source V _{pp}	Test Result	High Limit
5 mV	40 mV		3.69 ns
100 mV	800 mV		1.55 ns
500 mV	4 V		1.45 ns
1 V	4 V		2.70 ns
MDO = 4 µs/Div,	Source frequency = 240	kHz	·
MDO V/Div	Source V _{pp}	Test Result	High Limit
5 mV	40 mV		36.8 ns
100 mV	800 mV		15.3 ns
500 mV	4 V		14.3 ns
1 V	4 V		26.9 ns
MDO = 40 µs/Div	Source frequency = 24	kHz	
MDO V/Div	Source V _{pp}	Test Result	High Limit
5 mV	40 mV		368 ns
100 mV	800 mV		153 ns
500 mV	4 V		143 ns
1 V	4 V		269 ns
MDO = 400 µs/Di	v, Source frequency = 2.	4 kHz	
MDO V/Div	Source V _{pp}	Test Result	High Limit
5 mV	40 mV		3.68 µs
100 mV	800 mV		1.53 µs
500 mV	4 V		1.43 µs
1 V	4 V		2.69 µs

Channel 3¹

MDO = 4 ns/Div, Sourc	e frequency = 240 MHz		
MDO V/Div	Source V _{pp}	Test Result	High Limit

100 mV	800 mV		117 ps
500 mV	4 V		117 ps
1 V	4 V		119 ps
MDO = 40 ns/Div,	Source frequency = 24	MHz	
MDO V/Div	Source V _{pp}	Test Result	High Limit
5 mV	40 mV		386 ps
100 mV	800 mV		192 ps
500 mV	4 V		185 ps
1 V	4 V		293 ps
MDO = 400 ns/Div	, Source frequency = 2.	4 MHz	
MDO V/Div	Source V _{pp}	Test Result	High Limit
5 mV	40 mV		3.69 ns
100 mV	800 mV		1.55 ns
500 mV	4 V		1.45 ns
1 V	4 V		2.70 ns
MDO = 4 µs/Div, S	Source frequency = 240	kHz	
MDO V/Div	Source V _{pp}	Test Result	High Limit
5 mV	40 mV		36.8 ns
100 mV	800 mV		15.3 ns
500 mV	4 V		14.3 ns
1 V	4 V		26.9 ns
MDO = 40 µs/Div,	Source frequency = 24	kHz	
MDO V/Div	Source V _{pp}	Test Result	High Limit
5 mV	40 mV		368 ns
100 mV	800 mV		153 ns
500 mV	4 V		143 ns
1 V	4 V		269 ns
MDO = 400 µs/Div	, Source frequency = 2.	4 kHz	
MDO V/Div	Source V _{pp}	Test Result	High Limit
5 mV	40 mV		3.68 µs
100 mV	800 mV		1.53 µs
	4.17		1.43 µs
500 mV	4 V		1.45 µs
500 mV 1 V	4 V 4 V		2.69 µs

Table 27: Delta Time Measurement Accuracy (cont.)

Channel 4¹

MDO V/Div	Source V _{pp}	Test Result	High Limit
100 mV	800 mV		117 ps
500 mV	4 V		117 ps
1 V	4 V		119 ps
MDO = 40 ns/Div,	Source frequency = 24	MHz	
MDO V/Div	Source V _{pp}	Test Result	High Limit
5 mV	40 mV		386 ps
100 mV	800 mV		192 ps
500 mV	4 V		185 ps
1 V	4 V		293 ps
MDO = 400 ns/Di	v, Source frequency = 2.4	4 MHz	
MDO V/Div	Source V _{pp}	Test Result	High Limit
5 mV	40 mV		3.69 ns
100 mV	800 mV		1.55 ns
500 mV	4 V		1.45 ns
1 V	4 V		2.70 ns
MDO = 4 µs/Div, S	Source frequency = 240	kHz	L.
MDO V/Div	Source V _{pp}	Test Result	High Limit
5 mV	40 mV		36.8 ns
100 mV	800 mV		15.3 ns
500 mV	4 V		14.3 ns
1 V	4 V		26.9 ns
MDO = 40 µs/Div,	Source frequency = 24	kHz	
MDO V/Div	Source V _{pp}	Test Result	High Limit
5 mV	40 mV		368 ns
100 mV	800 mV		153 ns
500 mV	4 V		143 ns
1 V	4 V		269 ns
MDO = 400 µs/Di	v, Source frequency = 2.	4 kHz	
MDO V/Div	Source V _{pp}	Test Result	High Limit
5 mV	40 mV		3.68 µs
100 mV	800 mV		1.53 µs

Table 27: Delta Time Measurement Accuracy (cont.)

500 mV	4 V	1.43 µs
1 V	4 V	2.69 µs

1 Channels 3 and 4 are only on four-channel oscilloscopes.

Digital Threshold Accuracy Tests (with MDO3MSO option)

Digital channel	Threshold	V _s .	V _{s+}	Low limit	Test result V _{sAvg} = (V _{s-} + V _{s+})/2	High limit
D0	0 V			-0.1 V		0.1 V
	4 V			3.78 V		4.22 V
D1	0 V			-0.1 V		0.1 V
	4 V			3.78 V		4.22 V
D2	0 V			-0.1 V		0.1 V
	4 V			3.78 V		4.22 V
D3	0 V			-0.1 V		0.1 V
	4 V			3.78 V		4.22 V
D4	0 V			-0.1 V		0.1 V
	4 V			3.78 V		4.22 V
D5 0 V 4 V	0 V			-0.1 V		0.1 V
	4 V			3.78 V		4.22 V
D6 0 V	0 V			-0.1 V		0.1 V
	4 V			3.78 V		4.22 V
D7	0 V			-0.1 V		0.1 V
	4 V			3.78 V		4.22 V
D8 0	0 V			-0.1 V		0.1 V
	4 V			3.78 V		4.22 V
D9	0 V			-0.1 V		0.1 V
	4 V			3.78 V		4.22 V
D10	0 V			-0.1 V		0.1 V
	4 V			3.78 V		4.22 V
D11	0 V			-0.1 V		0.1 V
	4 V			3.78 V		4.22 V
D12	0 V			-0.1 V		0.1 V
	4 V			3.78 V		4.22 V
D13	0 V			-0.1 V		0.1 V
	4 V			3.78 V		4.22 V
D14	0 V			-0.1 V		0.1 V
	4 V			3.78 V		4.22 V

Table 28: Digital Threshold Accuracy (with MDO3MSO option)

Digital Thresh	Digital Threshold Accuracy (with MDO3MSO option)						
Digital channel	Threshold	V _s .	V _{s+}	Low limit	Test result V _{sAvg} = (V _s + V _{s+})/2	High limit	
D15	0 V			-0.1 V		0.1 V	
	4 V			3.78 V		4.22 V	

Table 28: Digital Threshold Accuracy (with MDO3MSO option) (cont.)

Displayed Average Noise Level Tests (DANL)

Table 29: Displayed Average Noise Level

Performance checks		Low limit	Test result	High limit
All models	9 kHz – 50 kHz	N/A		–109 dBm/Hz
	50 kHz – 5 MHz	N/A		–126 dBm/Hz
	5 MHz – BW (MDO3SA not installed)	N/A		–136 dBm/Hz
	5 MHz – 2 GHz (MDO3SA installed)	N/A		–136 dBm/Hz
	2 GHz – 3 GHz (MDO3SA installed)	N/A		–126 dBm/Hz

Residual Spurious Response Tests

Table 30: Residual Spurious Response

Residual Spurious	Response			
Performance check	S	Low limit	Test result	High limit
All models	9 kHz to 50 kHz	N/A		–78 dBm
	50 kHz to 5 MHz	N/A		–78 dBm
	5 MHz to 2 GHz (not 1.25 GHz)	N/A		–78 dBm
	1.25 GHz (MDO3SA installed)	N/A		–76 dBm
	2 GHz to 3 GHz (not 2.5 GHz) (MDO3SA installed)	N/A		–78 dBm
	2.5 GHz (MDO3SA installed)	N/A		–69 dBm

Level Measurement Uncertainty Tests

Table 31: Level Measurement Uncertainty

Level Measure	ment Uncertainty				
Performance c	hecks		Low limit	Test result	High limit
+10 dBm	All models	9 kHz	–1.2 dB		+1.2 dB
		50 kHz	–1.2 dB		+1.2 dB
		100 kHz – 900 kHz	–1.2 dB		+1.2 dB
		1 MHz – 9 MHz	–1.2 dB		+1.2 dB
		10 MHz - 90 MHz	–1.2 dB		+1.2 dB
		100 MHz – BW	–1.2 dB		+1.2 dB
0 dBm	All models	9 kHz	–1.2 dB		+1.2 dB
		50 kHz	–1.2 dB		+1.2 dB
		100 kHz – 900 kHz	–1.2 dB		+1.2 dB
		1 MHz – 9 MHz	–1.2 dB		+1.2 dB
		10 MHz - 90 MHz	–1.2 dB		+1.2 dB
		100 MHz – BW	–1.2 dB		+1.2 dB
–15 dBm	All models	9 kHz	–1.2 dB		+1.2 dB
		50 kHz	–1.2 dB		+1.2 dB
		100 kHz – 900 kHz	–1.2 dB		+1.2 dB
		1 MHz – 9 MHz	–1.2 dB		+1.2 dB
		10 MHz – 90 MHz	–1.2 dB		+1.2 dB
		100 MHz – BW	–1.2 dB		+1.2 dB

Functional check with a TPA-N-PRE Preamp Attached

Table 32: Functional check with a TPA-N-PRE Preamp attached

Functional check with a TPA-N-PRE Preamp attached					
Performance che	cks	Limit	Test result		
All models	1.7 GHz	≤ 1.5 dB			
	2.9 GHz	≤ 1.5 dB			

Displayed Average Noise Level (DANL) with a TPA-N-PRE Preamp Attached

Performance checks		Low limit	Test result	High limit
All models	9 kHz - 50 kHz	N/A		–117 dBm/Hz
	50 kHz - 5 MHz	N/A		–138 dBm/Hz
	50 kHz - BW (MDO3SA not installed)	N/A		–148 dBm/Hz
	5 MHz - 2 GHz (MDO3SA installed)	N/A		–148 dBm/Hz
	2 GHz - 3 GHz (MDO3SA installed)	N/A		–138 dBm/Hz

Auxiliary (Trigger) Output Tests

Table 34: Auxiliary (Trigger) Output Tests

Auxiliary (Trigger) Output Tests						
Performance checks		Low limit	Test result	High limit		
Trigger Output	High 1 MΩ	≥ 2.25 V		_		
	Low 1 MΩ	_		≤ 0.7 V		
	High 50 Ω	≥ 0.9 V		_		
	Low 50 Ω	_		≤ 0.25 V		

AFG Sine and Ramp Frequency Accuracy Tests

Table 35: AFG Sine and Ramp Frequency Accuracy Tests

Performance checks		Low limit	Test result	High limit
All models	Sine Wave at 10 kHz, 2.5 V, 50 Ω	9.9987 kHz		10.0013 kHz
	Sine Wave at 50 MHz, 2.5 V, 50 Ω	49.9975 MHz		50.0025 MHz

AFG Sine and Ramp Frequency Accuracy

AFG Square and Pulse Frequency Accuracy Tests

AFG Square and Pulse Frequency Accuracy						
Performance checks		Low limit	Test result	High limit		
All models	Square Wave at 25 kHz, 2.5 V, 50 Ω	24.99875 kHz		25.00125 kHz		
	Square Wave at 25 MHz, 2.5 V, 50 Ω	24.99875 MHz		25.00125 MHz		

Table 36: AFG Square and Pulse Frequency Accuracy Tests

AFG Signal Amplitude Accuracy Tests

Table 37: AFG Signal Amplitude Accuracy Tests

AFG Signal Amplitude Accuracy										
Performance checks		Low limit	Test result	High limit						
All models	Square Wave 20 mV _{pp} @ 1 kHz, 50 Ω, 0 V Offset	9.35 mV		10.65 mV						
	Square Wave 1 V_{pp} @ 1 kHz, 50 Ω , 0.2 V Offset	490.5 mV		509.5 mV						

AFG DC Offset Accuracy Tests

Table 38: AFG DC Offset Accuracy Tests

AFG DC Offset Accurac	у				
Performance checks		Low limit	Test result	High limit	
All models	20 mV DC offset @ 50 Ω	18.7 mV		21.3 mV	
	1 V DC offset @ 50 Ω	984 mV		1.016 V	

DVM Voltage Accuracy Tests (DC)

Channel 1					
Vertical Scale	Input Voltage	Offset Voltage	Low Limit	Test Result	High Limit
1	-5	-5	-5.117		-4.883
0.5	-2	-2	-2.052		-1.948
0.5	-1	-0.5	-1.0345		-0.9655
0.2	-0.5	-0.5	-0.5175		-0.4825
0.01	0.002	0	0.00042		0.00442
0.2	0.5	0.5	0.4825		0.5175
0.5	1	0.5	0.9655		1.0345
0.5	2	2	1.948		2.052
1	5	5	4.883		5.117
Channel 2			•		
Vertical Scale	Input Voltage	Offset Voltage	Low Limit	Test Result	High Limit
1	-5	-5	-5.117		-4.883
0.5	-2	-2	-2.052		-1.948
0.5	-1	-0.5	-1.0345		-0.9655
0.2	-0.5	-0.5	-0.5175		-0.4825
0.01	0.002	0	0.00042		0.00442
0.2	0.5	0.5	0.4825		0.5175
0.5	1	0.5	0.9655		1.0345
0.5	2	2	1.948		2.052
1	5	5	4.883		5.117
Channel 3 ¹					
Vertical Scale	Input Voltage	Offset Voltage	Low Limit	Test Result	High Limit
1	-5	-5	-5.117		-4.883
0.5	-2	-2	-2.052		-1.948
0.5	-1	-0.5	-1.0345		-0.9655
0.2	-0.5	-0.5	-0.5175		-0.4825
0.01	0.002	0	0.00042		0.00442
0.2	0.5	0.5	0.4825		0.5175
0.5	1	0.5	0.9655		1.0345
0.5	2	2	1.948		2.052
1	5	5	4.883		5.117

Table 39: DVM Voltage Accuracy (DC)

Channel 4 ¹									
Vertical Scale	Input Voltage	Offset Voltage	Low Limit	Test Result	High Limit				
1	-5	-5	-5.117		-4.883				
0.5	-2	-2	-2.052		-1.948				
0.5	-1	-0.5	-1.0345		-0.9655				
0.2	-0.5	-0.5	-0.5175		-0.4825				
0.01	0.002	0	0.00042		0.00442				
0.2	0.5	0.5	0.4825		0.5175				
0.5	1	0.5	0.9655		1.0345				
0.5	2	2	1.948		2.052				
1	5	5	4.883		5.117				

Table 39: DVM Voltage Accuracy (DC) (cont.)

1 Channels 3 and 4 are only on four-channel oscilloscopes.

DVM Voltage Accuracy Tests (AC)

Table 40:	DVM	Voltage	Accuracy	(AC)
-----------	-----	---------	----------	------

Channel 1				
Vertical Scale	Input Signal	Low Limit	Test Result	High Limit
5 mV	20 mV $_{\rm pp}$ at 1 kHz	9.800 mV		10.200 mV
10 mV	50 mV $_{\rm pp}$ at 1 kHz	24.5 mV		25.500 mV
100 mV	$0.5 V_{pp}$ at 1 kHz	245.000 mV		255.000 mV
200 mV	1 V _{pp} at 1 kHz	490.000 mV		510.000 mV
1 V	5 V _{pp} at 1 kHz	2.450 mV		2.550 mV
Channel 2				
Vertical Scale	Input Signal	Low Limit	Test Result	High Limit
5 mV	20 mV _{pp} at 1 kHz	9.800 mV		10.200 mV
10 mV	50 mV _{pp} at 1 kHz	24.5 mV		25.500 mV
100 mV	0.5 V _{pp} at 1 kHz	245.000 mV		255.000 mV
200 mV	1 V _{pp} at 1 kHz	490.000 mV		510.000 mV
1 V	5 V _{pp} at 1 kHz	2.450 mV		2.550 mV
Channel 3 ¹				
Vertical Scale	Input Signal	Low Limit	Test Result	High Limit
5 mV	20 mV _{pp} at 1 kHz	9.800 mV		10.200 mV
10 mV	50 mV _{pp} at 1 kHz	24.5 mV		25.500 mV
100 mV	0.5 V _{pp} at 1 kHz	245.000 mV		255.000 mV
200 mV	1 V _{pp} at 1 kHz	490.000 mV		510.000 mV
1 V	5 V _{pp} at 1 kHz	2.450 mV		2.550 mV
Channel 4 ¹				
Vertical Scale	Input Signal	Low Limit	Test Result	High Limit
5 mV	20 mV _{pp} at 1 kHz	9.800 mV		10.200 mV
10 mV	50 mV $_{\rm pp}$ at 1 kHz	24.5 mV		25.500 mV
100 mV	$0.5 V_{pp}$ at 1 kHz	245.000 mV		255.000 mV
200 mV	1 V _{pp} at 1 kHz	490.000 mV		510.000 mV
1 V	5 V _{pp} at 1 kHz	2.450 mV		2.550 mV

1 Channels 3 and 4 are only on four-channel oscilloscopes.

DVM Frequency Accuracy Tests and Maximum Input Frequency

Table 41: DVM Frequency Accuracy

	Nominal	Low Limit	Test Result	High Limit
	9.0000 Hz	8.9998 Hz		9.0002 Hz
	99.000 Hz	98.998 Hz		99.002 Hz
	999.00 Hz	998.98 Hz		999.02 Hz
	99.000 kHz	98.998 kHz		99.002 kHz
	999.00 kHz	998.98 kHz		999.02 kHz
	150 MHz 2	149.99 MHz		150.01 MHz
Channel 2		·		·
	9.0000 Hz	8.9998 Hz		9.0002 Hz
	99.000 Hz	98.998 Hz		99.002 Hz
	999.00 Hz	998.98 Hz		999.02 Hz
	99.000 kHz	98.998 kHz		99.002 kHz
	999.00 kHz	998.98 kHz		999.02 kHz
	150 MHz ²	149.99 MHz		150.01 MHz
Channel 3 ¹		·		·
	9.0000 Hz	8.9998 Hz		9.0002 Hz
	99.000 Hz	98.998 Hz		99.002 Hz
	999.00 Hz	998.98 Hz		999.02 Hz
	99.000 kHz	98.998 kHz		99.002 kHz
	999.00 kHz	998.98 kHz		999.02 kHz
	150 MHz ²	149.99 MHz		150.01 MHz
Channel 4 ¹				·
	9.0000 Hz	8.9998 Hz		9.0002 Hz
	99.000 Hz	98.998 Hz		99.002 Hz
	999.00 Hz	998.98 Hz		999.02 Hz
	99.000 kHz	98.998 kHz		99.002 kHz
	999.00 kHz	998.98 kHz		999.02 kHz
	150 MHz 2	149.99 MHz		150.01 MHz

1 Channels 3 and 4 are only on four-channel oscilloscopes.

2 Verifies the maximum frequency.

Performance Verification Procedures

The following three conditions must be met prior to performing these procedures:

- 1. The oscilloscope must have been operating continuously for twenty (20) minutes in an environment that meets the operating range specifications for temperature and humidity.
- You must perform a signal path compensation (SPC). (See Self Tests System Diagnostics and Signal Path Compensation section below.) If the operating temperature changes by more than 10 °C (18 °F), you must perform the signal path compensation again.
- 3. You must connect the oscilloscope and the test equipment to the same AC power circuit. Connect the oscilloscope and test instruments into a common power strip if you are unsure of the AC power circuit distribution. Connecting the oscilloscope and test instruments into separate AC power circuits can result in offset voltages between the equipment, which can invalidate the performance verification procedure.

The time required to complete all the procedures is approximately one hour.



WARNING. Some procedures use hazardous voltages. To prevent electrical shock, always set voltage source outputs to 0 V before making or changing any interconnections.

Self Tests — System Diagnostics and Signal Path Compensation

These procedures use internal routines to verify that the oscilloscope functions and passes its internal self tests. No test equipment or hookups are required. Start the self test with these steps:

Run the System Diagnostics (may take several minutes):

- 1. Disconnect all probes and cables from the oscilloscope inputs.
- 2. Push Default Setup on the front-panel to set the instrument to the factory default settings.
- 3. Push Utility .
- 4. Push Utility Page on the lower menu, and turn Multipurpose knob "a" to select Self Test.
- 5. Push Self Test on the lower menu. The Loop X Times side menu button will be set to Loop 1 Times.
- 6. Push OK Run Self Test on the side menu.
- 7. Wait while the self test runs. When the self test completes, a dialog box displays the results of the self test.
- 8. Cycle the oscilloscope power off and back on before proceeding.

NOTE. Remember to cycle the oscilloscope power off and back on before proceeding.

Run the signal path compensation routine (may take 5 to 15 minutes):

- 1. Push Default Setup on the front panel.
- 2. Push Utility .
- 3. Push Utility Page on the lower menu.
- 4. Turn Multipurpose knob "a" to select Calibration.
- 5. Push Signal Path on the lower menu.

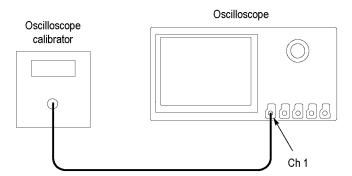
- 6. Push OK-Compensate Signal Paths on the side menu.
- 7. When the signal path compensation is complete, push Menu Off twice to clear the dialog box and Self Test menu.
- 8. Check the **Signal Path** button on the lower menu to verify that the status is **Pass**. If it does not pass, run the test again. If it still does not pass, recalibrate the instrument or have the instrument serviced by qualified service personnel.

Check Input Termination, DC Coupled (Resistance)

This test checks the Input Termination for 1 MΩ, 75 Ω or 50 Ω settings.

NOTE. The 75 Ω setting is not available on MDO310X instruments.

1. Connect the output of the oscilloscope calibrator (for example, Fluke 9500) to the oscilloscope channel 1 input, as shown below.



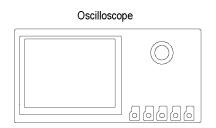
- 2. Push Default Setup on the front panel to set the instrument to the factory default settings.
- 3. Push the channel button on the front panel for the oscilloscope channel that you are testing, as shown in the test record (for example, 1, 2, 3, or 4).
- 4. Confirm that the oscilloscope termination and calibrator impedance are both set to 1 M Ω . The default **Termination** setting is 1 M Ω .
- 5. Turn the Vertical Scale knob to set the vertical scale, as shown in the test record (for example, 10 mV/div, 100 mV/div, 1 V/div). (See page 36, *Input Termination Tests*.)
- 6. Measure the input resistance of the oscilloscope with the calibrator. Record this value in the test record.
- 7. Repeat steps 5 and 6 for each volt/division setting in the test record.
- 8. Change the oscilloscope termination to 75 Ω and calibrator impedance to 50 Ω and repeat steps 5 through 7.
- **9.** Change the oscilloscope termination to 50 Ω and repeat steps 5 through 7.
- Repeat steps 4 through 9 for each channel listed in the test record and relevant to the model of oscilloscope that you are testing, as shown in the test record (for example, 2, 3, or 4).

Check DC Balance

This test checks the DC balance.

You do not need to connect the oscilloscope to any equipment to run this test. The only piece of equipment needed is a BNC feed-through 50 Ω terminator.

1. For 50 Ω coupling, attach a 50 Ω terminator to the channel input of the oscilloscope being tested.



- 2. Push Default Setup on the front panel to set the instrument to the factory default settings.
- 3. Push the channel button on the front panel for the oscilloscope channel that you are testing, as shown in the test record (for example, 1, 2, 3, or 4).
- 4. Set the oscilloscope termination to 50 Ω . Push Termination on the lower menu to select 50 Ω .
- 5. Push Bandwidth on the lower menu, and push the appropriate bandwidth button on the side menu for 20MHz, 150MHz, or Full, as given in the test record.
- 6. Turn the Horizontal Scale knob to 1 ms/division.

NOTE. Step 6 only needs to be done once, at the beginning of the test.

- 7. Turn the Vertical Scale knob to set the vertical scale, as shown in the test record (for example, 1 mV/div, 2 mV/div, 10 mV/div, 10 mV/div, 1 V/div).
- 8. Push Acquire on the front panel.

NOTE. Steps 8, 9, and 10 only need to be performed once, at the beginning of this test.

- 9. Push Mode on the lower menu, and then, if needed, push Average on the side menu.
- 10. If needed, adjust the number of averages to 16 using Multipurpose knob "a" .
- 11. Push the Trigger Menu button on the front panel.

NOTE. Steps 11, 12, and 13 only need to be performed once, at the beginning of this test.

- 12. Push Source on the lower menu.
- 13. Select the AC Line trigger source on the side menu using Multipurpose knob "a". You do not need to connect an external signal to the oscilloscope for this DC Balance test.
- 14. On the front panel, push the **Measure** button on the Wave Inspector.

NOTE. Steps 14 though 17 must be performed once for each input channel under test.

- 15. Push Add Measurement on the lower menu.
- Use Multipurpose knob "b" to select the Mean measurement. If needed, use Multipurpose knob "b" to select the channel input being tested.
- 17. Push OK Add Measurement on the side menu, and then Menu Off on the front panel.
- View the mean measurement value in the display and enter that mean value as the test result in the test record. (See page 38, DC Balance Tests.)

NOTE. Translate the mean value into divisions for use in the test record. To do this, divide the voltage value by the vertical scale value. (e.g.0.2 V / (1 V / division) = 0.2 divisions)

- **19.** Repeat step 7 and step 18 for each volts/division value listed in the results table.
- 20. Push the channel button on the front panel, then change the oscilloscope bandwidth (for example, 20 MHz, 150 MHz, or Full), and repeat step 7, step 18, and step 19.
- **21.** For 1 M Ω coupling, change the oscilloscope termination to 1 M Ω and repeat steps 5 through 20.
- 22. Repeat steps 3 through 20 for each channel combination listed in the test record and relevant to your model of oscilloscope (for example, 1, 2, 3, or 4).

NOTE. The BNC 50 Ω terminator needs to be moved to next input channel.

23. For 75 Ω coupling, change the oscilloscope termination to 75 Ω and repeat steps 5 through 20.

NOTE. The BNC 50 Ω terminator needs to be moved to next input channel.

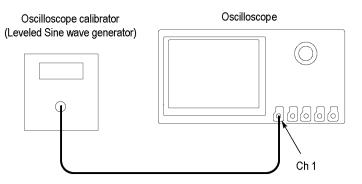
24. Repeat steps 3 through 20 for each channel combination listed in the test record and relevant to your model of oscilloscope (for example, 1, 2, 3, or 4).

NOTE. The BNC 50 Ω terminator needs to be moved to next input channel.

Check Analog Bandwidth, 50 Ω

This test checks the bandwidth at 50 Ω for each channel.

1. Connect the output of the leveled sine wave generator (for example, Fluke 9500) to the oscilloscope channel 1 input as shown below.



- 2. Push Default Setup on the front panel to set the instrument to the factory default settings.
- 3. Push channel button 1, 2,3, or 4 for the channel that you want to check.
- 4. Set the calibrator to 50 Ω output impedance (50 Ω source impedance) and to generate a sine wave.
- 5. Set the oscilloscope termination to 50 Ω . Push Termination on the lower menu to select 50 Ω .
- Turn the Vertical Scale knob to set the vertical scale, as shown in the test record (for example, 1 mV/div, 2 mV/div, 5 mV/div).
- 7. Push Acquire on the front panel.
- 8. Confirm that the mode is set to **Sample**. If not, push **Mode** on the lower menu, if needed, and then push the **Sample** side bezel button.
- 9. Adjust the signal source to at least 6 vertical divisions at the selected vertical scale with a set frequency of 50 kHz. For example, at 5 mV/div, use a ≥ 30 mV_{p-p} signal; at 2 mV/div, use a ≥ 12 mV_{p-p} signal; at 1 mV/div, use a ³ 6 mV_{p-p} signal. Use a sine wave for the signal source.
- 10. Turn the Horizontal Scale knob to 40 µs/division.
- 11. On the front panel, push the **Measure** button on the Wave Inspector, and then push **Add Measurement** on the lower menu.

NOTE. Steps 11 though 14 must be performed once for each input channel under test.

- 12. Use Multipurpose knob "b" to select the Peak-to-peak measurement. Use Multipurpose knob "a" to select the input channel being tested, and then push OK Add Measurement on the side menu.
- 13. Push More on the lower menu to select Gating, and then push Off (Full Record) on the side menu.
- **14.** Push **Menu Off** on the front panel. This will allow you to see the display. Note the mean V_{p-p} of the signal. Call this reading V_{in-pp} .

Record the mean value of V_{in-pp} (for example, 816 mV) in the test record. (See page 44, Analog Bandwidth Tests, 50 Ω .)

15. Turn the Horizontal Scale knob to 10 ns/division.

16. Adjust the signal source to the maximum bandwidth frequency for the bandwidth and model desired, as shown in the following worksheet. Measure V_{p-p} of the signal on the oscilloscope using statistics, as in the previous step, to get the mean V_{p-p}. Call this reading V_{bw-pp}.

Record the value of V_{bw-pp} in the test record.

NOTE. For more information on the contents of this worksheet, refer to the Analog Channel Input and Vertical Specifications table. (See page 1, Analog Channel Input And Vertical Specifications.)

Table 42: Maximum Bandwidth Frequency worksheet

Termination	Vertical Scale	Maximum Bandwidth Frequency			
For instruments with 1 GH (includes MDO310X mode	Iz bandwidth Is as well as MDO305X/303X/302X/301X	models with 1 GHz upgrade):			
50 Ω	10 mV/div 1 GHz				
50 Ω	5 mV/div	500 MHz			
50 Ω	2 mV/div	350 MHz			
50 Ω	1 mV/div	150 MHz			
For instruments with 500 I (includes MDO305X mode	MHz bandwidth Is as well as MDO303X/302X/301X mode	els with 500 MHz upgrade):			
50 Ω	5 mV/div	500 MHz			
50 Ω	2 mV/div	350 MHz			
50 Ω	1 mV/div	150 MHz			
For instruments with 350 I (includes MDO303X mode	MHz bandwidth Is as well as MDO302X/301X models wit	h 350 MHz upgrade):			
50Ω	5 mV/div	350 MHz			
50Ω	2 mV/div	350 MHz			
50Ω	1 mV/div	150 MHz			
For instruments with 200 I (includes MDO302X mode	MHz bandwidth Is as well as MDO301X models with 200	MHz upgrade):			
50 Ω	2 mV/div	200 MHz			
50 Ω	1 mV/div	150 MHz			
For instruments with 100 I (MDO301X models):	MHz bandwidth				
50 Ω	1 mV/div	100 MHz			

17. Use the values of *V*_{bw-pp} and *V*_{in-pp} obtained above and stored in the test record to calculate the *Gain* at bandwidth with the following equation:

Gain = V_{bw-pp} / V_{in-pp} .

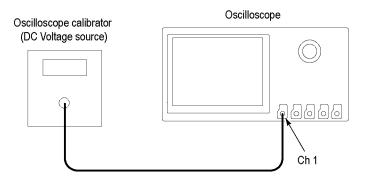
18. To pass the performance measurement test, Gain should be ≥ 0.707 . Enter *Gain* in the test record.

- 19. Repeat steps 9 through 17 for the other oscilloscope volts/div settings listed in the test record.
- 20. Repeat steps 3 through 18 for each channel combination listed in the test record and relevant to your model of oscilloscope (for example, 1, 2, 3, or 4).

Check DC Gain Accuracy

This test checks the DC gain accuracy.

 Connect the oscilloscope to a DC voltage source. If using the Fluke 9500 calibrator, connect the calibrator head to the oscilloscope channel to test.



- 2. Push Default Setup on the front panel to set the instrument to the factory default settings.
- 3. Push channel button 1, 2,3, or 4 to select the channel that you want to check.
- 4. Confirm that the oscilloscope termination and calibrator impedance are both set to 1 M Ω . On the oscilloscope, push **Termination** on the lower menu to select 1 M Ω .
- 5. Push 20 MHz on the side menu to select the bandwidth (push Bandwidth on the lower menu, if necessary, to activate the Bandwidth menu).
- 6. Push Acquire on the front panel.
- 7. Push Mode on the lower menu, and then push Average on the side menu. Use the default number of averages (16).
- 8. On the front panel, push the Measure button on the Wave Inspector, and then Add Measurement on the lower menu.
- 9. Use Multipurpose knob "b" to select the Mean measurement. Use Multipurpose knob "a" to select the input channel to be tested.
- 10. Push OK Add Measurement on the side menu.
- 11. Push the Trigger Menu button on the front panel.
- 12. Push Source on the lower menu.
- 13. Turn Multipurpose knob "a" to select AC Line as the trigger source. Push Menu Off on the front panel.
- 14. Turn the vertical Scale knob to the next setting to measure, as shown in the Gain Expected worksheet below.
- Set the DC Voltage Source to V_{negative}. Push Measure on the front panel, then push More on the lower menu to select Statistics. Push Reset Statistics on the side menu, and then push Menu Off on the front panel.
- 16. Enter the mean reading into Gain Expected worksheet below as V_{negative-measured}.
- 17. Set the DC Voltage Source to V_{positive}. Push More on the lower menu to select Statistics, push the Reset Statistics on the side menu, and then push Menu Off on the front panel. Enter the mean reading into the Gain Expected worksheet as V_{positive-measured}.

Oscillo- scope Vertical Scale Set- ting	VdiffExpected	V _{negative}	V _{positive}	V _{negative-} measured	V _{positive-} measured	V _{diff}	Test Result (Gain Accuracy)
1 mV/div	7 mV	–3.5 mV	+3.5 mV				
2 mV/div	14 mV	–7 mV	+7 mV				
4.98 mV	34.86 mV	–17.43 mV	+17.43 mV				
5 mV	35 mV	–17.5 mV	+17.5 mV				
10 mV	70 mV	–35 mV	+35 mV				
20 mV	140 mV	–70 mV	+70 mV				
49.8 mV	348.6 mV	–174.3 mV	+174.3 mV				
50 mV	350 mV	–175 mV	+175 mV				
100 mV	700 mV	–350 mV	+350 mV				
200 mV	1400 mV	–700 mV	+700 mV				
500 mV	3500 mV	–1750 mV	+1750 mV				
1.0 V	7000 mV	–3500 mV	+3500 mV				

Table 43: Gain Expected worksheet - channel 1

Table 44: Gain Expected worksheet - channel 2

Oscillo- scope Vertical Scale Set- ting	V _{diffExpected}	V _{negative}	V _{positive}	V _{negative-} measured	V _{positive-} measured	V _{diff}	Test Result (Gain Accuracy)
1 mV/div	7 mV	–3.5 mV	+3.5 mV				
2 mV/div	14 mV	–7 mV	+7 mV				
4.98 mV	34.86 mV	–17.43 mV	+17.43 mV				
5 mV	35 mV	–17.5 mV	+17.5 mV				
10 mV	70 mV	–35 mV	+35 mV				
20 mV	140 mV	–70 mV	+70 mV				
49.8 mV	348.6 mV	–174.3 mV	+174.3 mV				
50 mV	350 mV	–175 mV	+175 mV				
100 mV	700 mV	–350 mV	+350 mV				
200 mV	1400 mV	–700 mV	+700 mV				
500 mV	3500 mV	–1750 mV	+1750 mV				
1.0 V	7000 mV	–3500 mV	+3500 mV				

Oscillo- scope Vertical Scale Set- ting	V _{diffExpected}	V _{negative}	V _{positive}	V _{negative-} measured	V _{positive-} measured	V _{diff}	Test Result (Gain Accuracy)
1 mV/div	7 mV	–3.5 mV	+3.5 mV				
2 mV/div	14 mV	–7 mV	+7 mV				
4.98 mV	34.86 mV	–17.43 mV	+17.43 mV				
5 mV	35 mV	–17.5 mV	+17.5 mV				
10 mV	70 mV	–35 mV	+35 mV				
20 mV	140 mV	–70 mV	+70 mV				
49.8 mV	348.6 mV	–174.3 mV	+174.3 mV				
50 mV	350 mV	–175 mV	+175 mV				
100 mV	700 mV	–350 mV	+350 mV				
200 mV	1400 mV	–700 mV	+700 mV				
500 mV	3500 mV	–1750 mV	+1750 mV				
1.0 V	7000 mV	–3500 mV	+3500 mV				

Table 45: Gain Expected worksheet - channel 3

Table 46: Gain Expected worksheet - channel 4

Oscillo- scope Vertical Scale Set- ting	V _{diffExpected}	V _{negative}	V _{positive}	V _{negative-} measured	V _{positive-} measured	V _{diff}	Test Result (Gain Accuracy)
1 mV/div	7 mV	–3.5 mV	+3.5 mV				
2 mV/div	14 mV	–7 mV	+7 mV				
4.98 mV	34.86 mV	–17.43 mV	+17.43 mV				
5 mV	35 mV	–17.5 mV	+17.5 mV				
10 mV	70 mV	–35 mV	+35 mV				
20 mV	140 mV	–70 mV	+70 mV				
49.8 mV	348.6 mV	–174.3 mV	+174.3 mV				
50 mV	350 mV	–175 mV	+175 mV				
100 mV	700 mV	–350 mV	+350 mV				
200 mV	1400 mV	–700 mV	+700 mV				
500 mV	3500 mV	–1750 mV	+1750 mV				
1.0 V	7000 mV	-3500 mV	+3500 mV				

18. Calculate V_{diff} as follows:

V_{diff} = |V_{negative-measured} - V_{positive-measured} |

Enter V_{diff} in the Gain Expected worksheet.

19. Calculate GainAccuracy as follows:

 $GainAccuracy = ((V_{diff} - V_{diffExpected})/V_{diffExpected}) \times 100\%$

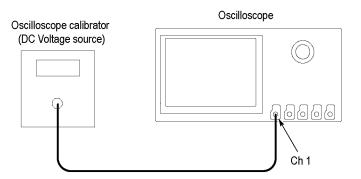
Write down *GainAccuracy* in the Gain Expected worksheet and in the test record. (See page 45, *DC Gain Accuracy Tests*.)

- 20. Repeat steps 14 through 18 for each volts/division value in the test record.
- 21. Repeat steps 3 through 19 for each channel of the oscilloscope that you want to check.

Check Offset Accuracy

This test checks the offset accuracy.

 Connect the oscilloscope to a DC voltage source to run this test. If using the Fluke 9500 calibrator as the DC voltage source, connect the calibrator head to the oscilloscope channel to test.



- 2. Push Default Setup on the front panel to set the instrument to the factory default settings.
- 3. Push channel button 1,2,3, or 4 to select the channel you want to check.
- Confirm that the oscilloscope termination and calibrator impedance are both set to 1 MΩ. Push Termination on the lower menu to select 1 MΩ.
- Set the calibrator to the vertical offset value shown in the test record (for example, 700 mV for a 1 mV/div setting). Set the calibrator impedance to match the termination setting for the oscilloscope.
- 6. On the oscilloscope, push More on the lower menu repeatedly, to select Offset.
- 7. Set the oscilloscope to the vertical offset value shown in the test record (for example, 700 mV for a 1 mV/div setting).
- 8. Turn the vertical Scale knob to match the value in the test record (for example, 1 mV/division).
- 9. Turn the Horizontal Scale knob to 1 ms/div.
- **10.** Push **Bandwidth** on the lower menu.
- 11. Push 20 MHz on the side menu.
- 12. Check that the vertical position is set to 0 divs. If not, turn the appropriate Vertical Position knob to set the position to 0 divs.

Or, push More on the lower menu repeatedly to select Position, and then push Set to 0 divs on the side menu.

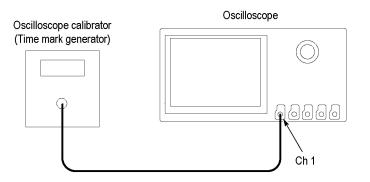
- **13.** Push **Acquire** on the front panel.
- 14. Push Mode on the lower menu, and then push Average on the side menu. Use the default number of averages (16).
- **15.** Push the Trigger **Menu** button on the front panel.
- 16. Push Source on the lower menu.
- 17. Turn Multipurpose knob "a" to select AC Line as the trigger source.
- 18. On the front panel, push the **Measure** button on the Wave Inspector.
- 19. Push Add Measurement on the lower menu.
- 20. Use Multipurpose knob "b" to select the Mean measurement. Use Multipurpose knob "a" to select the input channel to be tested.

- 21. Push OK Add Measurement on the side menu, and then Menu Off on the front panel. The mean value should appear in a measurement pane at the bottom of the display.
- 22. Enter the measured value in the test record. (See page 47, DC Offset Accuracy Tests.)
- 23. Repeat the procedure (steps 6, 7, 8 and 22) for each volts/division setting shown in the test record.
- 24. Repeat all steps, starting with step 1, for each oscilloscope channel you want to check.

Check Long-term Sample Rate and Delay Time Accuracy

This test checks the sample rate and delay time accuracy (time base).

- 1. Push Default Setup on the oscilloscope front panel to set the instrument to the factory default settings.
- 2. Connect the output of the time mark generator to the oscilloscope channel 1 input using a 50 Ω cable. Use the time mark generator with a 50 Ω source with the oscilloscope set for internal 50 Ω termination.



- 3. Set the time mark generator to 80 ms. Use a time mark waveform with a fast rising edge.
- 4. Set the mark amplitude to 1 V_{pp}.
- 5. Set the oscilloscope vertical Scale to 500 mV/div.
- 6. Set the Horizontal Scale to 20 ms/div.
- 7. Adjust the Trigger Level for a triggered display.
- 8. Adjust the vertical Position knob to center the time mark on center screen.
- 9. Adjust the Horizontal Position knob counterclockwise to set the delay to exactly 80 ms.
- **10.** Set the **Horizontal Scale** to 400 ns/div.
- **11.** Compare the rising edge of the marker to the center horizontal graticule. The rising edge should be within ±2 divisions of the center graticule. Enter the deviation in the test record. (See page 49, *Sample Rate and Delay Time Accuracy*.)

NOTE. One division of displacement from graticule center corresponds to a 5 ppm time base error.

Check Random Noise, Sample Acquisition Mode

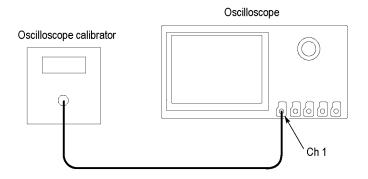
This test checks random noise. You do not need to connect any test equipment to the oscilloscope for this test.

- 1. Disconnect everything connected to the oscilloscope inputs.
- Push Default Setup on the front panel to set the instrument to the factory default settings. This sets the oscilloscope to Channel 1, Full Bandwidth, 1 MΩ input termination, 100 mV/div, and 4.00 µs/div.
- 3. Set Horizontal to 10 ms/div.
- 4. Set CH1 Vertical Channel Setting to 50 Ω termination and the desired bandwidth.
- 5. Set up the measurements to do RMS and Mean measurement of selected channel and record the measurement.
- 6. Calculate RMS noise voltage = Square root of (RMS² Mean²), and record the result.
- 7. The calculated RMS noise voltage from step 6 should be less than the high limit in the test record (the calculated maximum RMS noise).
- 8. Repeat the above test for all other input channels. Channels 3 and 4 are only available on three or four channel oscilloscopes.

Check Delta Time Measurement Accuracy

This test checks the Delta time measurement accuracy (DTA) for a given instrument setting and input signal.

- 1. Set the sine wave generator output impedance to 50 Ω .
- 2. Push the oscilloscope front-panel Default Setup button, and then push Menu Off.
- 3. Connect a 50 Ω coaxial cable from the signal source to the oscilloscope channel being tested.



- 4. Push the channel 1 button to display the channel 1 menu.
- 5. Push Termination on the lower menu to set the channel to 50 Ω .
- 6. Push the Trigger Menu button on the front panel, and then, if necessary, set the trigger source to the channel being tested:
 - a. Push Source on the lower menu.
 - b. Use the Multipurpose a knob to select the channel being tested.
- 7. On the front panel, push the **Measure** button on the Wave Inspector, and then push **Add Measurement** on the lower menu.
- 8. Use Multipurpose Knob "b" to select the Burst Width measurement, and then push OK Add Measurement on the side menu. Use Multipurpose Knob "a" to select the input channel to be tested.
- Push More on the lower menu to select Statistics and, if necessary, use Multipurpose Knob "a" to set the Mean & Std Dev Samples to 100, as shown in the side menu.
- 10. Push Menu Off on the front panel to remove the Statistics menu.
- **11.** Refer to the Test Record *Delta Time Measurement Accuracy* table. (See page 60, *Delta Time Measurement Accuracy Tests (MDO310X models)*.) Set the oscilloscope and the signal source as directed there.
- Push More on the lower menu to select Statistics, and then push Reset Statistics. Wait five or 10 seconds for the
 oscilloscope to acquire all the samples before taking the reading.
- 13. Verify that the Std Dev is less than the upper limit shown for each setting, and note the reading in the Test Record.
- 14. Repeat steps 11 through 13 for each setting combination shown in the Test Record for the channel being tested.
- 15. Push the channel button on the front panel for the current channel to shut off the channel. Push the channel button for the next channel to be tested, and move the coaxial cable to the appropriate input on the oscilloscope. Only the channel being tested should be enabled
- 16. Repeat steps 5 through 15 until all channels have been tested.

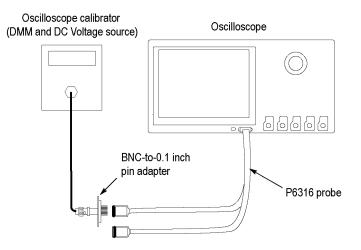
NOTE. For this test, enable only one channel at a time. If three or more channels are enabled at the same time, the maximum sample rate is reduced and the limits in the Test Record are no longer valid.

Check Digital Threshold Accuracy (with MDO3MSO option)

For models with the MDO3MSO option only, this test checks the threshold accuracy of the digital channels. This procedure applies to digital channels D0 through D15, and to channel threshold values of 0 V and +4 V.

- 1. Connect the P6316 digital probe to the MDO3000 series instrument.
- Connect the P6316 Group 1 pod to the DC voltage source to run this test. You will need a BNC-to-0.1 inch pin adapter to complete the connection.

NOTE. If using the Fluke 9500 calibrator as the DC voltage source, connect the calibrator head to the P6316 Group 1 pod. You will need a BNC-to-0.1 inch pin adapter to complete the connection.



- 3. Push Default Setup on the front panel to set the instrument to the factory default settings.
- 4. Push **D15-D0** on the front panel.
- 5. Push D15-D0 On/Off on the lower menu.
- 6. Push Turn On D7 D0 and Turn On D15 D8 on the side menu. The instrument will display the 16 digital channels.
- 7. Push Thresholds on the lower menu.
- 8. Before you change the threshold value, push **Fine** on the front panel to turn off the fine adjustment and make adjusting the value quicker.

Turn Multipurpose knob "a" (for channels D7 - D0) or Multipurpose knob "b" (for channels D15 - D8) to set the threshold value to 0.00 V (0 V/div).

The thresholds are set for the 0 V threshold check. You need to record the test values in the test record row for 0 V for each digital channel. (See page 66, *Digital Threshold Accuracy Tests (with MDO3MSO option)*.)

- 9. Push the Trigger Menu button on the front panel.
- 10. Push Source on the lower menu, and then turn Multipurpose knob "a" to select the appropriate channel, such as D0.

By default, the Type is set to Edge, Coupling is set to DC, Slope is set to Rising, Mode is set to Auto, and Level is set to match the threshold of the channel being tested.

 Set the DC voltage source (Vs) to -400 mV. Wait 3 seconds. Check the logic level of the corresponding digital channel in the display. If the channel is a static logic level high (green), change the DC voltage source Vs to -500 mV.

12. Increment Vs by +20 mV. Wait 3 seconds and check the logic level of the corresponding digital channel in the display. If the channel is at a static logic level high (green), record the Vs value as in the 0 V row of the test record.

If the channel is a logic level low (blue) or is alternating between high and low, repeat this step (increment Vs by 20 mV, wait 3 seconds, and check for a static logic high). Continue until a value for **Vs-** is found.

NOTE. In this procedure, the channel might not change state until after you pass the set threshold level.

- 13. Push Slope on the lower menu to change the slope to Falling.
- Set the DC voltage source (Vs) to +400 mV. Wait 3 seconds. Check the logic level of the corresponding digital channel in the display.

If the channel is a static logic level low (blue), change the DC voltage source Vs to +500 mV.

15. Decrement Vs by -20 mV. Wait 3 seconds and check the logic level of the corresponding digital channel in the display. If the channel is at a static logic level low, record the Vs value as Vs+ in the 0 V row of the test record.

If the channel is a logic level high (green) or is alternating between high and low, repeat this step (decrement Vs by 20 mV, wait 3 seconds, and check for a static logic low). Continue until a value for **Vs+** is found.

16. Find the average, V_{sAvg} = (Vs- + Vs+)/2. Record the average as the test result in the test record.

Compare the test result to the limits. If the result is between the limits, continue with the procedure to test the channel at the +4 V threshold value.

- 17. The remaining part of this procedure is for the +4 V threshold test. Push D15-D0 on the front panel. The Thresholds menu should display.
- With the Fine button on the front panel turned off, turn Multipurpose knob "a" (for channels D7 D0) or Multipurpose knob "b" (for channels D15 D8) to set the threshold value to 4.00 V (+4.0 V/div). To remove the menu from the display, push Menu Off on the front panel.
- Set the DC voltage source (Vs) to +4.4 V. Wait 3 seconds. Check the logic level of the corresponding digital channel in the display.

If the channel is a static logic level low (blue), change the DC voltage source Vs to +4.5 V.

20. Decrement Vs by -20 mV. Wait 3 seconds and check the logic level of the corresponding digital channel in the display. If the channel is at a static logic level low, record the Vs value as Vs+ in the 4 V row of the test record.

If the channel is a logic level high (green) or is alternating between high and low, repeat this step (decrement Vs by 20 mV, wait 3 seconds, and check for a static logic low). Continue until a value for **Vs+** is found.

- 21. Push the Trigger Menu button on the front panel.
- 22. Push the Slope lower-bezel button to change the slope to Rising.
- 23. Set the DC voltage source (Vs) to +3.6 V. Wait 3 seconds. Check the logic level of the corresponding digital channel in the display.

If the channel is a static logic level high (green), change the DC voltage source Vs to +3.5 V.

24. Increment Vs by +20 mV. Wait 3 seconds and check the logic level of the corresponding digital channel in the display. If the channel is at a static logic level high, record the Vs value as in the 4 V row of the test record.

If the channel is a logic level low (blue) or is alternating between high and low, repeat this step (increment Vs by 20 mV, wait 3 seconds, and check for a static logic high). Continue until a value for **Vs-** is found.

25. Find the average, $V_{sAvg} = (Vs - + Vs +)/2$. Record the average as the test result in the test record.

Compare the test result to the limits. If the result is between the limits, the channel passes the test.

- 26. Push D15-D0 on the front panel. The Thresholds menu should display.
- **27.** Repeat the procedure starting with step 8 for each remaining digital channel in the pod.
- 28. Disconnect the P6316 Group 1 pod from the BNC-to-0.1 inch pin adapter and connect the Group 2 pod in its place.
- 29. Repeat the procedure starting with step 8 for each digital channel in the Group 2 pod.

Check Displayed Average Noise Level (DANL)

This test does not require an input signal.

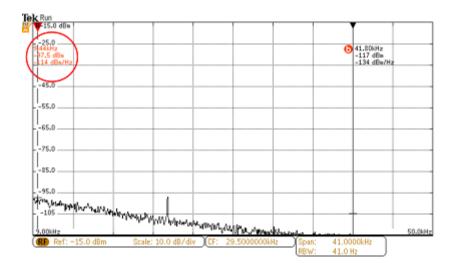
The test measures the average internal noise level of the instrument, ignoring residual spurs.

It checks these ranges:

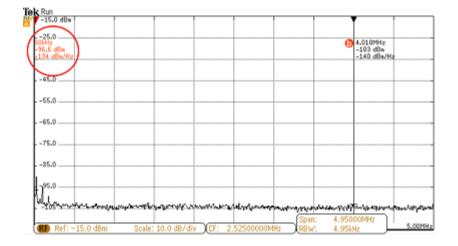
- 9 kHz to 50 kHz (all models)
- 50 kHz to 5 MHz (all models)
- 5 MHz to BW (MDO3SA not installed)
- 5 MHz to 2 GHz (MDO3SA installed)
- 2 GHz to 3 GHz (MDO3SA installed)

NOTE. If the specific measurement frequency results in measuring a residual spur that is visible above the noise level, the DANL specification applies not to the spur but to the noise level on either side of the spur. Please refer to the Spurious Response specifications.

- 1. Initial oscilloscope setup:
 - a. Terminate the RF input in 50 Ω with no input signal applied.
 - b. Push the Default Setup button on the front panel.
 - c. Push the front-panel RF button to turn on the RF channel and display the bottom-bezel RF menu.
 - **d.** *Turn on the average trace as follows:* Push the bottom-bezel **Spectrum Traces** button and set Normal to Off. Push the side-bezel **Average** button to set the Average Traces to On.
 - e. *Turn on the average detection as follows:* Push the bottom-bezel **Detection Method** button. Push the side-bezel button to set the detection method to **Manual**. Push the side-bezel **Average Trace** button. Set the detection method to Average.
 - f. Set the reference level to -15 dBm as follows: Push the front-panel Ampl button. Push the side-bezel Ref Level button. Set the Ref Level to -15.0 dBm.
 - **g.** Set the start and stop frequency as follows: Push the front-panel **Freq/Span** button. Push the side-bezel **Start** button. Set the start frequency to 9 kHz. Push the side-bezel **Stop** button. Set the stop frequency to 50 kHz.
- 2. Check from 9 kHz to 50 kHz (all models):
 - a. Set Manual Marker (a) at the frequency with the highest noise level as follows: Push the Markers front-panel button. Push the Manual Markers side bezel button to turn on the markers. Turn Multipurpose knob a to move the marker to the frequency at the noise threshold (highest point of noise), ignoring any spurs. For this span, it should be near 9 kHz on the far left of the screen. See the following figure.



- b. Record the noise threshold value (in dBm/Hz) in the test record and compare it to the instrument specification.
- 3. In the test record, enter the result at this frequency (9 kHz).
- 4. Check from 50 kHz to 5 MHz (all models):
 - a. Set the stop frequency to 5 MHz.
 - b. Set the start frequency to 50 kHz.
 - c. Set Manual Marker (a) at the frequency of the highest noise, ignoring any spurs.
 - d. Set the center frequency as follows: Push the R To Center side-bezel button.
 - e. Set the span to 10 MHz as follows: Push the side-bezel Span button. Set the Span to 10 MHz.
 - f. Record the highest noise value (in dBm/Hz) in the test record and compare it to the instrument specification.



5. In the test record, enter the result at this frequency (50 kHz).

- 6. Check from 5 MHz to BW (MDO3SA not installed):
 - a. Set the stop frequency to the maximum bandwidth.
 - b. Set the start frequency to 5 MHz.
 - c. Set Manual Marker (a) at the frequency of the highest noise, ignoring any spurs.
 - d. Set the center frequency as follows: Push the R To Center side-bezel button.
 - e. Set the span to 10 MHz as follows: Push the side-bezel Span button. Set the Span to 10 MHz.
 - f. Record the highest noise value (in dBm/Hz) in the test record and compare it to the instrument specification.
- 7. Check from 5 MHz to 2 GHz (MDO3SA installed).
 - a. Set the stop frequency to 2 GHz.
 - b. Set the start frequency to 5 MHz.
 - c. Set Manual Marker (a) at the frequency of the highest noise, ignoring any spurs.
 - d. Set the center frequency as follows: Push the R To Center side-bezel button.
 - e. Set the span to 10 MHz as follows: Push the side-bezel Span button. Set the Span to 10 MHz.
 - f. Record the highest noise value (in dBm/Hz) in the test record and compare it to the instrument specification.
- 8. Check from 2 GHz to 3 GHz (MDO3SA installed).
 - a. Set the stop frequency to 3 GHz.
 - b. Set the start frequency to 2 GHz.
 - c. Set Manual Marker (a) at the frequency of the highest noise, ignoring any spurs.
 - d. Set the center frequency as follows: Push the R To Center side-bezel button.
 - e. Set the span to 10 MHz as follows: Push the side-bezel Span button. Set the Span to 10 MHz.
 - f. Record the highest noise value (in dBm/Hz) in the test record and compare it to the instrument specification.

Check Residual Spurious Response

This check verifies that the oscilloscope meets the specification for residual spurious response. This check does not require an input signal.

- 1. Initial Setup:
 - **a.** Terminate the oscilloscope RF input in 50 Ω with no input signal applied.
 - b. Push Default Setup.
 - c. Turn on RF.
 - d. Turn on Average Trace. Push the bottom-bezel Spectrum Traces button and set Normal to Off. Push the side-bezel Average button to set Average Traces to On.
 - e. Set Ref Level to -15 dBm. Push the front-panel Ampl button. Push the side-bezel Ref Level button. Set the Ref Level to -15 dB.
- 2. Check in the range of 9 kHz to 50 kHz (all models).
 - a. Set Start Frequency to 9 kHz. Push the front-panel Freq/Span button. Push the side-bezel Start button. Set the start frequency to 9 kHz.
 - b. Set Stop Frequency to 50 kHz. Push the side-bezel Stop button. Set the stop frequency to 50 kHz.
 - c. Observe any spurs above -78 dBm and note them in the test record.
- 3. Check in the range of 50 kHz to 5 MHz (all models).
 - a. Set Stop Frequency to 5 MHz.
 - b. Set Start Frequency to 50 kHz.
 - c. Observe any spurs above -78 dBm and note them in the test record.
- 4. Check in the range of 5 MHz to Maximum Bandwidth (MDO3SA not installed):
 - a. Set Stop Frequency to the maximum bandwidth.
 - b. Set Start Frequency to 5 MHz.
 - c. Set RBW to 100 kHz. Push the BW front-panel button. Turn the Multipurpose a knob counter-clockwise to change the RBW to 100 kHz.
 - d. Observe any spurs above -78 dBm and note them in the test record.
- 5. Check in the range of 5 MHz to 2 GHz (MDO3SA installed):
 - a. Set Stop Frequency to 2 GHz.
 - b. Set Start Frequency to 5 MHz.
 - c. Set RBW to 100 kHz. Push the BW front-panel button. Turn the Multipurpose a knob counter-clockwise to change the RBW to 100 kHz.
 - d. Check the spur level at 1.25 GHz, if present. Push the Markers front-panel button and then push the Manual Markers side-bezel button to turn on manual markers. Turn the Multipurpose a knob to line up Marker a on the

1.25 GHz spur, if it is present. Adjust the marker until the horizontal dash on the marker sits on top of the spur. Note the spur level in the test record.

- e. Observe any spurs above -78 dBm in the rest of the span, and note them in the test record.
- 6. Check in the range of 2 GHz to 3 GHz (MDO3SA installed):
 - a. Set Stop Frequency to the 3 GHz.
 - b. Set Start Frequency to 2 GHz.
 - c. Set RBW to 100 kHz.
 - d. Check the spur level at 2.5 GHz, if present. Push the Markers front-panel button and then push the Manual Markers side-bezel button to turn on manual markers. Turn the Multipurpose a knob to line up Marker a on the 2.5 GHz spur, if it is present. Adjust the marker until the horizontal dash on the marker sits on top of the spur. Note the spur level in the test record.
 - e. Observe any spurs above -78 dBm in the rest of the span, and note them in the test record.

Check Level Measurement Uncertainty

This test checks the level measurement uncertainty at three reference levels: +10 dBm, 0 dBm, and -15 dBm. This check uses the generator to step frequencies across four spans to verify that the instrument meets the specification.

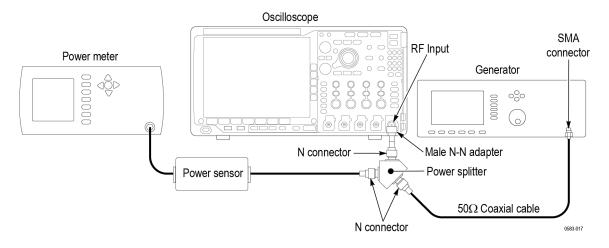
For this check, you will need the following equipment, which is described in the Required Equipment table. (See Table 18 on page 33.)

- RF Signal Generator
- Power meter
- Power sensor
- Power splitter
- Adapters and cables as shown in the following figure.

WARNING. The generator is capable of providing dangerous voltages. Be sure to set the generator to off or 0 volts before connecting, disconnecting, and/or moving the test hookup during the performance of this procedure.

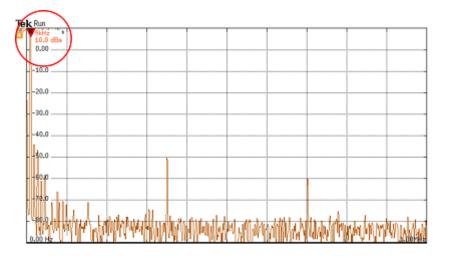
NOTE. Use an SMA connector with the Anritsu generator. Equipment damage will result if an N connector is used.

1. Connect the equipment as shown in the following figure.

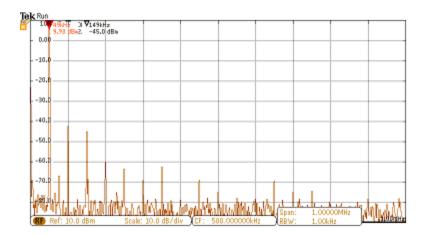


- 2. Initial oscilloscope setup:
 - a. Push the Default Setup button on the front panel.
 - b. Push the front-panel RF button to turn on the RF channel.

- **3.** Check at +10 dBm:
 - a. Set the reference level to +10 dBm as follows: Push the front-panel Ampl button. Push the side-bezel Ref Level button. Set the Ref Level to +10 dBm.
 - **b.** Set the frequency range as follows:
 - = Push the front-panel **Freq/Span** button.
 - = Push the side-bezel Start button.
 - Set the start frequency to 0 Hz.
 - = Push the side-bezel **Stop** button.
 - Set the stop frequency to 1 MHz.
 - c. Set the generator to provide a 9 kHz, +10 dBm signal.
 - d. At 9 kHz, determine the test result as follows:
 - Note the reading on the power meter and the readout for the Reference marker on the oscilloscope. See the following figure.



- Calculate the difference between the two readings. This is the test result.
- e. In the test record, enter the result at this frequency (9 kHz).
- f. Set the generator to provide a 50 kHz, +10 dBm signal.
- g. At 50 kHz, determine the test result as follows:
 - Note the reading on the power meter and the readout for the Reference marker on the oscilloscope. See the following figure.



- Calculate the difference between the two readings. This is the test result.
- h. In the test record, enter the result at this frequency (50 kHz).
- i. Step the generator, in 100 kHz intervals, through frequencies from 100 kHz to 900 kHz. At each interval, determine the test result as follows:
 - Note the reading on the power meter and the readout for the Reference marker on the oscilloscope.
 - Calculate the difference between the two readings. This is the test result.
- j. In the test record, enter the greatest result determined within this frequency range (100 kHz 900 kHz).
- **k.** Change the frequency range as follows:
 - Change the stop frequency to 9.2 MHz.
 - Change the start frequency to 980 kHz.
- I. Set the generator to provide a 1 MHz, +10 dBm signal.
- m. Step the generator, in 1 MHz intervals, through frequencies from 1 MHz to 9 MHz. At each interval, determine the test result as follows:
 - Note the reading on the power meter and the readout for the Reference marker on the oscilloscope.
 - Calculate the difference between the two readings. This is the test result.
- n. In the test record, enter the greatest result determined within this frequency range (1 MHz to 9 MHz).
- o. Change the frequency range as follows:
 - Change the stop frequency to 92 MHz.
 - Change the start frequency to 9.8 MHz.
- p. Set the generator to provide a 10 MHz, +10 dBm signal.
- q. Step the generator, in 10 MHz intervals, through frequencies from 10 MHz to 90 MHz. At each interval, determine the test result as follows:
 - Note the reading on the power meter and the readout for the Reference marker on the oscilloscope.
 - Calculate the difference between the two readings. This is the test result.
- r. In the test record, enter the greatest result determined within this frequency range (10 MHz to 90 MHz).

For all models without the MSO3MDO 3 GHz option (steps p through u)

- p. Change the frequency range as follows:
 - Change the stop frequency to the maximum bandwidth.
 - Change the start frequency to 99 MHz.
- s. Set the generator to provide a 100 MHz, +10 dBm signal.
- t. Step the generator, in 100 MHz intervals, through frequencies from 100 MHz to the maximum bandwidth. At each interval, determine the test result as follows:
 - Note the reading on the power meter and the readout for the Reference marker on the oscilloscope.
 - Calculate the difference between the two readings. This is the test result.
- u. In the test record, enter the greatest result determined within this frequency range (100 MHz to 3 GHz).

For models with the MSO3MDO 3 GHz option (steps v through y).

- v. Change the frequency range as follows:
 - Change the stop frequency to 3 GHz.
 - Change the start frequency to 99 MHz.
- w. Set the generator to provide a 100 MHz, +10 dBm signal.
- **x.** Step the generator, in 100 MHz intervals, through frequencies from 100 MHz to 3 GHz. At each interval, determine the test result as follows:
 - Note the reading on the power meter and the readout for the Reference marker on the oscilloscope.
 - Calculate the difference between the two readings. This is the test result.
- y. In the test record, enter the greatest result determined within this frequency range (100 MHz to 3 GHz).
- 4. Repeat the previous step with these changes:
 - a. Set the reference level to 0 dBm.
 - b. Set the generator level to 0 dBm.
- 5. Repeat the previous step with these changes:
 - **a.** Set the reference level to -15 dBm.
 - b. Set the generator level to -15 dBm.

Functional Check of the MDO3000 with a TPA-N-PRE Attached to its RF Input

The following instructions apply to situations where the MDO3000 has a TPA-N-PRE preamplifier attached to its RF input

Perform the following functional check to ensure proper operation of the TPA-N-PRE/MDO3000 system.

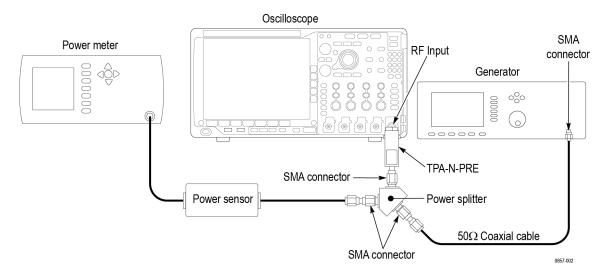
For this check, you will need the following equipment, which is described in the Required Equipment table. (See Table 18 on page 33.)

- RF Signal Generator
- Power meter
- Power sensor
- Power splitter
- Adapters and cables as shown in the following figure.

WARNING. The generator is capable of providing dangerous voltages. Be sure to set the generator to off or 0 volts before connecting, disconnecting, and/or moving the test hookup during the performance of this procedure.

NOTE. Use an SMA connector with the Anritsu generator. Equipment damage will result if an N connector is used.

1. Connect the equipment as shown in the following figure.



- 2. Initial oscilloscope setup:
 - a. Push the front-panel Default Setup button.
 - b. Push the front-panel RF button to turn on the RF channel.
 - c. Push the Menu button on the TPA-N-PRE preamplifier. On the MDO3000, verify that the side-menu Mode button is set to Auto.

- 3. Check at 1.7 GHz
 - a. Set the reference level to -15 dBm as follows: Push the front-panel Ampl button. Push the side-bezel Ref Level button. Set the Ref Level to -15 dBm.
 - **b.** Set the frequency range as follows:
 - = Push the front-panel **Freq/Span** button.
 - = Push the side-bezel **Center Frequency** button.
 - = Set the center frequency to 1.7 GHz.
 - = Push the side-bezel **Span** button.
 - Set the span to 50 MHz.
 - **c.** Set the generator to provide a 1.7 GHz, –20 dBm signal.
 - **d.** Note the reading on the power meter and the readout for the Reference marker on the oscilloscope. See the following figure:

k Run					
-15.0 dBw		1.70000GHs -19.9 dBis			
25.0		-1717 000			
35.0					
-45,0					
55.0					
65.0					
75.0					
85.0		- Au			
and the second second	entertante in Albaneta por	and the second	and provident	gartstannigetyre.cl	antonhalipay
105					
			Span:	50.0000MHz	۱I
Ref: -15.0 dBm	Scale: 10.0 dB/div	CF: 1.70000000G	Hz (RBW)	50.0kHz	1,735

- e. The absolute difference between the two readings should be small (~ 1.5 dB or less). If the MDO3000 reading is too low, tighten the preamp more firmly to the MDO3000 by hand and check the reading again.
- f. Check at the -30 dBm reference level.
 - = Set the generator to provide a 1.7 GHz, -35 dBm signal.
 - Set the MDO3000's reference level to -30 dBm.
 - Compare the MDO3000 and the power meter readings as before. The absolute difference between the readings should be ~1.5 dB or less. If the MDO3000 reading is too low, tighten the preamp more firmly to the MDO3000 by hand and check the reading again.
- 4. Check at 2.9 GHz
 - a. Set the reference level to -15 dBm as follows: Push the front-panel Ampl button. Push the side-bezel Ref Level button. Set the Ref Level to -15 dBm.
 - **b.** Set the frequency range as follows:
 - Set the center frequency to 2.9 GHz.
 - Set the span to 50 MHz.
 - c. Set the generator to provide a 2.9 GHz, -20 dBm signal.
 - d. Note the reading on the power meter and the readout for the Reference marker on the oscilloscope.
 - e. The absolute difference between the two readings should be small (~ 1.5 dB or less). If the MDO3000 reading is too low, tighten the preamp more firmly to the MDO3000 by hand and check the reading again.
 - f. Check at the -30 dBm reference level.
 - = Set the generator to provide a 2.9 GHz, -35 dBm signal.
 - Set the MDO3000's reference level to -30 dBm.
 - Compare the MDO3000 and the power meter readings as before. The absolute difference between the readings should be ~1.5 dB or less. If the MDO3000 reading is too low, tighten the preamp more firmly to the MDO3000 by hand and check the reading again.

Check Displayed Average Noise Level (DANL) with a TPA-N-PRE Attached:

This test does not require an input signal.

The test measures the average internal noise level of the instrument, ignoring residual spurs.

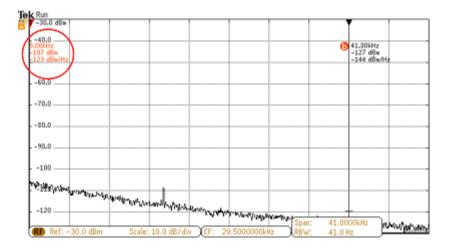
It checks these ranges:

- 9 kHz to 50 kHz (all models)
- 50 kHz to 5 MHz (all models)
- 5 MHz to BW (MDO3SA not installed)
- 5 MHz to 2 GHz (MDO3SA installed)
- 2 GHz to 3 GHz (MDO3SA installed)

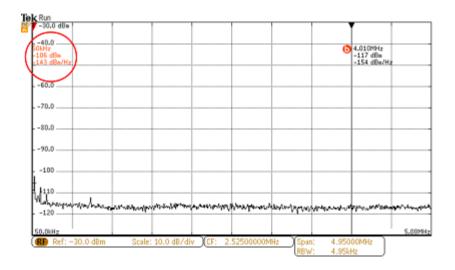
NOTE. If the specific measurement frequency results in measuring a residual spur that is visible above the noise level, the DANL specification applies not to the spur but to the noise level on either side of the spur. Please refer to the Spurious Response specifications.

- 1. Initial oscilloscope setup:
 - a. Terminate the TPA-N-PRE preamp input in 50 Ω and make sure that no input signal is applied.
 - b. Push the front-panel Default Setup button.
 - c. Push the front-panel RF button to turn on the RF channel and display the bottom-bezel RF menu.
 - d. Turn on the average trace as follows:
 - = Push the bottom-bezel Spectrum Traces button.
 - Push the side-bezel Average button to set average trace to On.
 - Set the side-bezel Normal to Off.
 - d. Turn on average detection as follows:
 - = Push the bottom-bezel **Detection Method** button.
 - Push the side-bezel button to set the detection method to Manual.
 - = Push the side-bezel Average Trace button.
 - Set the detection method to **Average**.
 - e. Push the Menu button on the TPA-N-PRE preamplifier. On the MDO3000, verify that the side-bezel Mode button is set to Auto.
 - f. Set the reference level to -30.0 dBm as follows:
 - = Push the front-panel Ampl button.
 - Push the side-bezel Ref Level button.
 - Set the Ref Level to -30.0 dBm.
- 2. Check from 9 kHz to 50 kHz (all models):
 - a. Set the stop and start frequencies as follows:

- = Push the front-panel **Freq/Span** button.
- Push the side-bezel Stop button.
- Set the stop frequency to 50 kHz.
- Push the side-bezel Start button.
- Set the start frequency to 9 kHz.
- Wait 60 seconds. Due to the low RBW for this span, it takes a little while for the instrument to compute a valid average.
- b. Set Manual Marker (a) at the frequency with the highest noise level as follows:
 - Push the Markers front-panel button.
 - Push the Manual Markers side-bezel button to turn on the markers.
 - Turn Multipurpose knob a to move the marker to the frequency at the noise threshold (highest point of noise), ignoring any spurs. See the following figure.



- c. Record the highest noise value (in dBm/Hz) in the test record and compare it to the instrument specification.
- 3. Check from 50 kHz to 5 MHz (all models):
 - a. Set the start and stop frequency as follows:
 - Push the front-panel Freq/Span button.
 - = Push the side-bezel Stop button.
 - Set the stop frequency to 5 MHz.
 - Push the side-bezel Start button.
 - Set the start frequency to 50 kHz.
 - b. Set Manual Marker (a) at the frequency with the highest noise level as follows:
 - = Push the Markers front-panel button.
 - Push the Manual Markers side-bezel button to turn on the markers.
 - Turn Multipurpose knob a to move the marker to the frequency at the noise threshold (highest point of noise), ignoring any spurs. See the following figure.



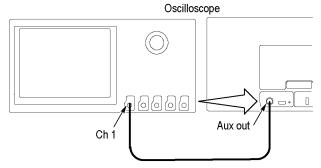
- c. Record the noise threshold value (in dBm/Hz) in the test record and compare it to the instrument specification.
- 4. Check from 5 MHz to BW (MDO3SA not installed)
 - a. Set the stop frequency to the maximum BW.
 - b. Set the start frequency to 5 MHz.
 - c. Set Manual Marker (a) at the frequency of the highest noise, ignoring any spurs.
 - d. Set the center frequency as follows: Push the R To Center side-bezel button.
 - e. Set the Span to 10 MHz.
 - Push the side-bezel Span button.
 - = Set the Span to 10 MHz.
 - f. Record the highest noise value (in dBm/Hz) in the test record and compare it to the instrument specification.
- 5. Check from 5 MHz to 2 GHz (MDO3SA installed)
 - a. Set the stop frequency to 2 GHz.
 - b. Set the start frequency to 5 MHz.
 - c. Set Manual Marker (a) at the frequency of the highest noise, ignoring any spurs.
 - d. Set the center frequency as follows: Push the R To Center side-bezel button.
 - e. Set the Span to 10 MHz.
 - Push the side-bezel Span button.
 - = Set the Span to 10 MHz.
 - f. Record the highest noise value (in dBm/Hz) in the test record and compare it to the instrument specification.
- 6. Check from 2 GHz to 3 GHz (MDO3SA installed):
 - a. Set the stop frequency to 3 GHz.
 - b. Set the start frequency to 2 GHz.

- c. Set Manual Marker (a) at the frequency of the highest noise, ignoring any spurs.
- d. Set the center frequency as follows: Push the R To Center side-bezel button.
- e. Set the Span to 10 MHz as follows.
 - = Push the side-bezel **Span** button.
 - = Set the Span to 10 MHz.
- f. Record the highest noise value (in dBm/Hz) in the test record and compare it to the instrument specification.

Check Auxiliary Output

This test checks the Auxiliary Output.

1. Connect the Aux Out signal from the rear of the instrument to the channel 1 input using a 50 Ω cable.

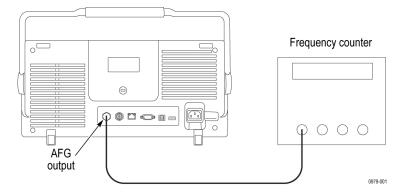


- 2. Push the Default Setup button on the front panel to set the instrument to the factory default settings.
- 3. Push the channel 1 button.
- 4. Set the oscilloscope termination to 1 M Ω . The default Termination setting is 1M Ω .
- 5. Set the horizontal to 4 uS/div and the vertical to 1 V/div.
- 6. On the front panel, push the Measure button on the Wave Inspector.
- 7. Push Add Measurement on the lower menu.
- 8. Use Multipurpose Knob "b" to select Low in the Measurements menu, and then push OK Add Measurement on the side menu.
- 9. Use Multipurpose Knob "b" to select High in the Measurements menu, and then push OK Add Measurement on the side menu.
- 10. Push Menu Off on the front panel.
- **11.** Record the high and low measurements in the test record (for example, low = 200 mV and high = 3.52 V). (See page 69, *Auxiliary (Trigger) Output Tests.*)
- 12. Repeat the procedure, using 50 Ω instead of 1 M Ω in step 4.

Check AFG Sine and Ramp Frequency

This test checks the AFG Sine and Ramp Frequency.

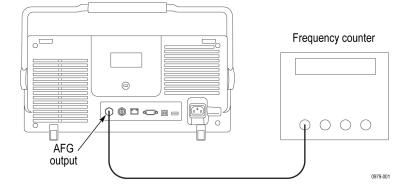
1. Connect AFG output to the frequency counter.



- 2. Push the Default Setup button on the oscilloscope front panel.
- 3. Push the AFG button on the front panel.
- 4. Under Waveform Settings, set amplitude and frequency to those shown in the test record.
- 5. Set Waveform to Sine wave (or Ramp).
- 6. Push Output Settings on the bottom menu. Push Load Impedance on the side menu to select 50 Ω .
- 7. Measure frequency in the frequency counter. Compare results to the limits in the test record.
- 8. Repeat steps 3 7 above for all rows in the test record.

Check AFG Square and Pulse Frequency Accuracy

This test checks the AFG Square and Pulse Frequency Accuracy.

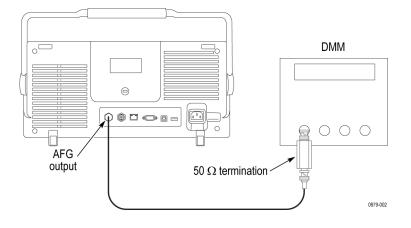


- 1. Connect the AFG output to the frequency counter.
- 2. Push the Default Setup button on the oscilloscope front panel.
- 3. Push the AFG button on the front panel.
- 4. Under Waveform Settings, set Amplitude and frequency to that shown in the test record.
- 5. Set output to Square wave (or Pulse).
- 6. Push Output Settings on the bottom menu. Push Load Impedance on the side menu to select 50 Ω .
- 7. Measure frequency in the frequency counter. Compare results to the limits in the test record.
- 8. Repeat steps 3 7 for all rows in the test record.

Check AFG Signal Amplitude Accuracy

This test checks the AFG Signal Amplitude Accuracy.

1. Connect the AFG output to the DMM through a 50 Ω termination.

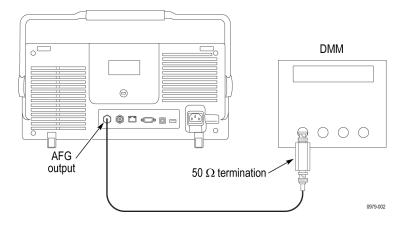


- 2. Push the Default Setup button on the oscilloscope front panel.
- 3. Push the AFG button on the front panel.
- 4. Under Waveform Settings, set amplitude and frequency to the value shown in the test record.
- 5. Under Waveform set the signal to Square.
- 6. Push Output Settings on the bottom menu. Push Load Impedance on the side menu to select 50 Ω .
- 7. Set the DMM to measure ACRMS Voltage.
- 8. Measure voltage on the DMM. Compare the result to the limits in the test record.
- 9. Repeat steps 3 8 above for all rows in the test record.

Check AFG DC Offset Accuracy

This test checks the AFG DC Offset Accuracy.

1. Connect the AFG output to the DMM through a 50 Ω termination.

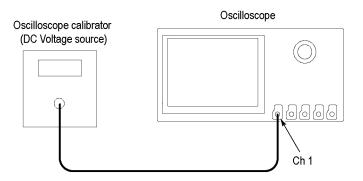


- 2. Push the Default Setup button on the oscilloscope front panel.
- 3. Push the AFG button on the front panel.
- 4. Under Waveform set the signal to DC.
- 5. Under Waveform Settings, set Amplitude to the value shown in the test record.
- 6. Push Output Settings on the bottom menu. Push Load Impedance on the side menu to select 50 Ω.
- 7. Measure voltage on the DMM. Compare the value to the limits in the test record.
- 8. Repeat steps 3 7 above for each line in the test record.

Check DVM Voltage Accuracy (DC)

This test checks the DVM voltage accuracy (DC).

1. Connect the oscilloscope to a DC voltage source to run this test. If using the Fluke 9500 calibrator as the DC voltage source, connect the calibrator head to the oscilloscope channel to test.



- 2. Push the Default Setup button on the front panel to set the instrument to the factory default settings.
- 3. Push channel button 1, 2, 3, or 4 to select the channel you want to check.
- 4. Confirm that the oscilloscope termination and calibrator impedance are both set to 1 M Ω . Push **Termination** on the lower menu to select 1 M Ω .
- 5. Set the calibrator to the input voltage shown in the test record (for example, -5 V for a 1 V/div setting). Set the calibrator impedance to match the termination setting for the oscilloscope.
- 6. On the oscilloscope, push More on the lower menu repeatedly, to select Offset.
- 7. Set the oscilloscope to the vertical offset value shown in the test record (for example, -5 V for -5 V input and 1 V/div setting).
- 8. Turn the vertical Scale knob to match the value in the test record (for example, 1 V/division).
- 9. Turn the Horizontal Scale knob to 1 ms/div.
- 10. Push Bandwidth on the lower menu.
- 11. Push 20 MHz on the side menu.
- **12.** Check that the vertical position is set to 0 divs. If not, turn the appropriate **Vertical Position** knob to set the position to 0 divs.

Or, push More on the lower menu repeatedly to select Position, and then push Set to 0 divs on the side menu.

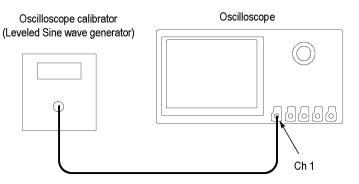
- 13. Push Acquire on the front panel.
- 14. Push Mode on the lower menu, and then push Average on the side menu. Use the default number of averages (16).
- **15.** Push the Trigger **Menu** button on the front panel.
- 16. Push Source on the lower menu.
- 17. Turn Multipurpose knob "a" to select AC Line as the trigger source.
- **18.** On the front panel, push the **Measure** button.
- 19. Push the DVM lower-bezel button to turn on the DVM function.
- 20. Turn the Multipurpose a knob to select DC mode

- 21. Turn the Multipurpose b knob to select the input channel to be tested.
- 22. Push Menu Off on the front panel. The measured value should appear in a measurement pane at the top of the display.
- 23. Enter the measured value in the test record. (See page 71, DVM Voltage Accuracy Tests (DC).)
- 24. Repeat the procedure (steps 6, 7, 8 and 22) for each volts/division setting shown in the test record.
- 25. Repeat all steps, starting with step 1, for each oscilloscope channel you want to check.

Check DVM Voltage Accuracy (AC)

This test checks the DVM voltage accuracy (AC).

1. Connect the output of the leveled sine wave generator (for example, Fluke 9500) to the oscilloscope channel 1 input as shown below.

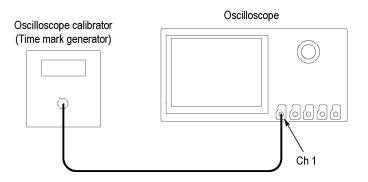


- 2. Push Default Setup on the front panel to set the instrument to the factory default settings.
- 3. Push channel button 1, 2, 3, or 4 for the channel that you want to check.
- 4. Set the generator to 50 Ω output impedance (50 Ω source impedance).
- 5. Set the oscilloscope termination to 50 Ω . Push Termination on the lower menu to select 50 Ω .
- 6. Set the generator to produce a square wave of the amplitude and frequency listed in the test record (for example, 20 mV_{pp} and 1 kHz).
- 7. Turn the vertical scale knob so that the signal covers between 4 and 8 vertical divisions on screen.
- 8. Push the Measure button, then the DVM lower-bezel button to turn on the DVM function.
- 9. Use the multipurpose knob a to select AC RMS mode
- 10. Use the multipurpose knob b to select the input channel being tested.
- 11. Enter the measured value in the test record.
- 12. Repeat procedure for each voltage and frequency combination shown in the record.
- **13.** Repeat all steps for each oscilloscope channel.

Check DVM Frequency Accuracy and Maximum Input Frequency

This test checks DVM Frequency Accuracy.

- 1. Push Default Setup on the oscilloscope front panel to set the instrument to the factory default settings.
- 2. Connect the output of the time mark generator to the oscilloscope channel 1 input using a 50 Ω cable. Use the time mark generator with a 50 Ω source with the oscilloscope set for internal 50 Ω termination.



- 3. Set the time mark generator to the value shown in the test record. For example, use 9 Hz. Use a time mark waveform with a fast rising edge (square wave), except at 150 MHz use a sine wave.
- 4. Set the mark amplitude to 1 V_{pp} .
- 5. Set the oscilloscope vertical Scale to 200 mV/div.
- 6. Set the Horizontal Scale to 20 ms/div.
- 7. Adjust the Trigger Level for a triggered display.
- 8. Adjust the vertical Position knob to center the time mark on center screen.
- 9. Push the Measure button on the front panel, and then the DVM lower-bezel button to turn on the DVM feature.
- 10. Turn multipurpose knob a to select Frequency mode.
- 11. Turn multipurpose knob b to select the input channel being tested.
- 12. Enter the measured value in the test record.
- **13.** Repeat this procedure for each frequency setting shown in the record. (Keep the same vertical and horizontal scales as set in steps 5 and 6.)
- 14. Repeat all these steps for each oscilloscope channel.

This completes the procedure.

This completes the Performance Verification procedures